

INTERNATIONAL STANDARD



**Fixed capacitors for use in electronic equipment –
Part 21: Sectional specification – Fixed surface mount multilayer capacitors of
ceramic dielectric, Class 1**



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IEC Secretariat
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

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Part 21: Sectional specification – Fixed surface mount multilayer capacitors of
ceramic dielectric, Class 1**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

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CONTENTS

FOREWORD	6
1 Scope	9
2 Normative references	9
3 Terms and definitions	10
4 Preferred ratings and characteristics	11
4.1 Preferred characteristics	11
4.2 Preferred values of ratings	11
4.2.1 Rated temperature (T_R)	11
4.2.2 Rated voltage (U_R)	11
4.2.3 Category voltage (U_C)	11
4.2.4 Preferred values of nominal capacitance and associated tolerance values	11
4.2.5 Temperature coefficient (α)	12
4.2.6 Dimensions	14
5 Test and measurement procedures	14
5.1 General	14
5.2 Preliminary drying	15
5.3 Measuring conditions	15
5.4 Mounting	15
5.5 Visual examination and check of dimensions	15
5.5.1 General	15
5.5.2 Visual examination	15
5.5.3 Requirements	15
5.6 Electrical tests	17
5.6.1 Capacitance	17
5.6.2 Tangent of loss angle ($\tan \delta$)	17
5.6.3 Insulation resistance	18
5.6.4 Voltage proof	19
5.7 Temperature coefficient (α) and temperature cyclic drift	19
5.7.1 General	19
5.7.2 Preliminary drying	19
5.7.3 Measuring conditions	19
5.7.4 Requirements	20
5.8 Shear test	20
5.9 Substrate bending test	20
5.9.1 General	20
5.9.2 Initial measurement	20
5.9.3 Final inspection	20
5.10 Resistance to soldering heat	21
5.10.1 General	21
5.10.2 Initial measurement	21
5.10.3 Test conditions	21
5.10.4 Recovery	22
5.10.5 Final inspection, measurements and requirements	22
5.11 Solderability	23
5.11.1 General	23

5.11.2	Test conditions	23
5.11.3	Recovery.....	24
5.11.4	Final inspection, measurements and requirements.....	24
5.12	Rapid change of temperature	24
5.12.1	General.....	24
5.12.2	Initial measurement	24
5.12.3	Number of cycles.....	24
5.12.4	Recovery.....	24
5.12.5	Final inspection, measurements and requirements.....	24
5.13	Climatic sequence	25
5.13.1	General.....	25
5.13.2	Initial measurement	25
5.13.3	Dry heat.....	25
5.13.4	Damp heat, cyclic, Test Db, first cycle.....	25
5.13.5	Cold	25
5.13.6	Damp heat, cyclic, Test Db, remaining cycles.....	25
5.13.7	Final inspection, measurements and requirements.....	25
5.14	Damp heat, steady state	26
5.14.1	General.....	26
5.14.2	Initial measurement	26
5.14.3	Test conditions	26
5.14.4	Recovery.....	27
5.14.5	Final inspection, measurements and requirements.....	27
5.15	Endurance.....	27
5.15.1	General.....	27
5.15.2	Initial measurement	27
5.15.3	Test conditions.....	27
5.15.4	Recovery.....	28
5.15.5	Final inspection, measurements and requirements.....	28
5.16	Robustness of terminations (only for capacitors with strip termination)	28
5.16.1	General.....	28
5.16.2	Test conditions.....	28
5.16.3	Final inspection and requirements.....	29
5.17	Component solvent resistance (if required).....	29
5.18	Solvent resistance of the marking (if required).....	29
5.19	Accelerated damp heat, steady state (if required)	29
5.19.1	General.....	29
5.19.2	Initial measurement	29
5.19.3	Conditioning	29
5.19.4	Recovery.....	30
5.19.5	Final measurements	30
6	Marking	30
6.1	General	30
6.2	Information for marking.....	30
6.3	Marking on the body	30
6.4	Requirements for marking	30
6.5	Marking of the packaging	31
6.6	Additional marking	31
7	Information to be given in a detail specification	31

7.1	General	31
7.2	Outline drawing and dimensions	31
7.3	Mounting	31
7.4	Rating and characteristics	31
7.4.1	General	31
7.4.2	Nominal capacitance range	31
7.4.3	Particular characteristics	32
7.4.4	Soldering	32
7.5	Marking	32
8	Quality assessment procedures	32
8.1	Primary stage of manufacture	32
8.2	Structurally similar components	32
8.3	Certified records of released lots	32
8.4	Qualification approval	32
8.4.1	General	32
8.4.2	Qualification approval on the basis of the fixed sample size procedures	32
8.4.3	Tests	33
Annex A (normative) Guidance for the specification and coding of dimensions of fixed surface mount multilayer capacitors of ceramic dielectric, Class 1		42
Annex B (informative) Combination of temperature coefficients and tolerances for the reference temperature of 25 °C		43
Annex C (normative) Quality conformance inspection		44
C.1	Formation of inspection lots	44
C.1.1	Groups A and B inspection	44
C.1.2	Group C inspection	44
C.2	Test schedule	44
C.3	Delayed delivery	44
C.4	Assessment levels	44
C.5	Test schedule for quality conformance inspection	45
Annex X (informative) Cross-reference for reference to IEC 60384-21:2011/2019		50
Bibliography		52
List of comments		53
Figure 1 – Fault: crack or fissure		15
Figure 2 – Fault: crack or fissure		16
Figure 3 – Separation or delamination		16
Figure 4 – Exposed electrodes		16
Figure 5 – Principal faces		17
Figure 6 – Reflow temperature profile		22
Figure A.1 – Dimensions		42
Table 1 – Preferred tolerances on nominal capacitance		12
Table 2 – Nominal temperature coefficient and tolerance (for reference temperature 20 °C)		12
Table 3 – Combination of temperature coefficient and tolerance		13
Table 4 – Tangent of loss angle limits		18
Table 5 – Test voltages		19

Table 6 – Temperature cyclic drift limits	20
Table 7 – Reflow temperature profiles for Sn-Ag-Cu alloy	22
Table 8 – Maximum capacitance change	23
Table 9 – Maximum capacitance change	24
Table 10 – Number of damp heat cycles	25
Table 11 – Final inspection, measurements and requirements	26
Table 12 – Test conditions for damp heat, steady state	26
Table 13 – Final inspection, measurements and requirements	27
Table 14 – Endurance test conditions ($U_C = U_R$)	27
Table 15 – Endurance test conditions ($U_C \neq U_R$)	28
Table 16 – Final inspection, measurements and requirements	28
Table 17 – Initial requirements	29
Table 18 – Conditioning	30
Table 19 – Fixed sample size test plan for qualification approval Assessment level EZ	34
Table 20 – Tests schedule for qualification approval	35
Table A.1 – Dimensions	42
Table B.1 – Combination of temperature coefficients and tolerances for the reference temperature of 25 °C	43
Table C.1 – Lot by lot inspection	45
Table C.2 – Periodic ~~tests~~ inspection	45
Table C.3 – Test schedule for quality conformance inspection (lot by lot)	46
Table C.4 – Test schedule for quality conformance inspection (Periodic test)	47
Table X.1 – Reference to IEC 60384-21 for clause/ ~~subclause~~ annex	50
Table X.2 – Reference to IEC 60384-21 for figure/table	51

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FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT –**Part 21: Sectional specification –
Fixed surface mount multilayer capacitors of ceramic dielectric, Class 1****FOREWORD**

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This commented version (CMV) of the official standard IEC 60384-21:2024 edition 4.0 allows the user to identify the changes made to the previous IEC 60384-21:2019 edition 3.0. Furthermore, comments from IEC TC 40 experts are provided to explain the reasons of the most relevant changes, or to clarify any part of the content.

A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text. Experts' comments are identified by a blue-background number. Mouse over a number to display a pop-up note with the comment.

This publication contains the CMV and the official standard. The full list of comments is available at the end of the CMV.

IEC 60384-21 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment. It is an International Standard.

This fourth edition cancels and replaces the third edition published in 2019. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) the document has been completely restructured to comply with the ISO/IEC Directives, Part 2 and to make it more useable; tables, figures and references have been revised accordingly; Annex X contains all cross-references of changes in clause/subclause numbers;
- b) the terms have been replaced by the letter symbols in Table 3;
- c) code of temperature coefficient and tolerance of C0G, U2J have been added in Table 4, Table 6, Table 8, Table 9, Table 11, Table 13, Table 16 and Annex B;
- d) the requirement in 5.5.2(visual examination) has been repeated in 5.9.3, 5.10.5, 5.11.4, 5.11.4, 5.13.7, 5.14.5 and 5.15.5;
- e) the deflection D in the very robust designs has been added in 5.9.1;
- f) Annex B has been changed informative into normative;
- g) Clause C.5 (Test schedule for quality conformance inspection) has been newly added to withdraw the blank detail specification: IEC 60384-21-1.

The text of this International Standard is based on the following documents:

Draft	Report on voting
40/3119/FDIS	40/3138/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all parts in the IEC 60384 series, published under the general title *Fixed capacitors for use in electronic equipment*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

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FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT –

Part 21: Sectional specification – Fixed surface mount multilayer capacitors of ceramic dielectric, Class 1

1 Scope

This part of IEC 60384 is applicable to fixed unencapsulated surface mount multilayer capacitors of ceramic dielectric with a defined temperature coefficient (dielectric Class 1), intended for use in electronic equipment. These capacitors have metallized connecting pads or soldering strips and are intended to be mounted on printed boards, or directly onto substrates for hybrid circuits.

Capacitors for electromagnetic interference suppression are not included, but are covered by IEC 60384-14.

The object of this document is to ~~prescribe~~ specify preferred ratings and characteristics and to select from IEC 60384-1:2021 the appropriate quality assessment procedures, tests and measuring methods and to give general performance requirements for this type of capacitor. ~~Test severities and requirements prescribed in detail specifications referring to this sectional specification are of equal or higher performance levels; lower performance levels are not permitted.~~ Test severities and requirements specified in detail specifications referring to this document provide specific test severities and requirements of an equal or higher performance level. Further information on the conception of generic, sectional and detail specifications can be found in the Introduction of IEC 60384-1:2021. **1**

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

~~IEC 60063, Preferred number series for resistors and capacitors~~

~~IEC 60068-1:2013, Environmental testing – Part 1: General and guidance~~

IEC 60068-2-58:2015, *Environmental testing – Part 2-58: Tests – Test Td – Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)*

~~IEC 60068-2-58:2015/AMD1:2017~~

IEC 60384-1:2016/2021, *Fixed capacitors for use in electronic equipment – Part 1: Generic specification*

IEC 61193-2:2007, *Quality assessment systems – Part 2: Selection and use of sampling plans for inspection of electronic components and packages*

~~ISO 3:1973, Preferred numbers – Series of preferred numbers~~

3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60384-1:2021 and the following apply.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- IEC Electropedia: available at <https://www.electropedia.org/>
- ISO Online browsing platform: available at <https://www.iso.org/obp>

3.1

surface mount multilayer capacitor

multilayer capacitor whose small dimensions and nature or shape of terminations make it suitable for surface mounting in hybrid circuits and on printed boards

3.2

capacitor of ceramic dielectric, Class 1

capacitor specially designed and suited for resonant circuit application where low losses and high stability of capacitance are essential or where a precisely defined temperature coefficient is required, for example for compensating temperature effects in the circuit

Note 1 to entry: The ceramic dielectric is defined by its nominal temperature coefficient (α).

3.3

subclass

<Class 1> tolerance on the temperature coefficient for a given nominal temperature coefficient; ~~the subclass is defined by the tolerance on the temperature coefficient~~

Note 1 to entry: See Table 2.

Note 2 to entry: The nominal temperature coefficient value and its tolerance refer to the temperature interval ~~of~~ from the reference temperature +20 °C or +25 °C to +85 °C, but because in practice TC curves are not strictly linear, it is necessary to define limiting capacitance deviation ($\Delta C/C$) for other temperatures (see Table 3 and Annex B).

3.4

~~category~~ **temperature range**

ambient temperature range for which the capacitor has been designed to operate continuously

Note 1 to entry: This is given by the lower and upper category temperature. (see Table 3 and Annex B).

3.5

rated temperature

T_R

maximum ambient temperature at which the rated voltage ~~may~~ can be continuously applied

3.6

rated voltage

U_R

maximum DC voltage that ~~may~~ can be applied continuously to a capacitor at any temperature between the lower category temperature and the rated temperature

Note 1 to entry: The maximum DC voltage is the sum of the DC voltage and peak AC voltage or peak pulse voltage applied to the capacitor.

3.7

category voltage

U_C

maximum voltage that can be applied continuously to a capacitor at its upper category temperature

4 Preferred ratings and characteristics

4.1 Preferred characteristics

Preferred climatic categories only shall be given in the preferred characteristics.

The capacitors covered by this document are classified into climatic categories in accordance with the general rules given in IEC 60068-1:2013, Annex A.

For reference temperature 20 °C or 25 °C **2**, the lower and upper category temperatures and the duration of the damp heat, steady state test shall be chosen from the following:

- lower category temperature: –55 °C, –40 °C, –25 °C, –10 °C and +10 °C;
- upper category temperature: +70 °C, +85 °C, +100 °C, +125 °C ~~and +150 °C~~;
- duration of the damp heat, steady state test (40 °C, 93 % RH): 4, 10, 21 and 56 days.

The severities of the cold and dry heat tests are the lower and upper category temperatures respectively.

NOTE The resistance to humidity resulting from the above climatic category is for the capacitors in their unmounted state. The climatic performance of the capacitors after mounting is greatly influenced by the mounting substrate, the mounting method (see 5.4) and the final coating.

4.2 Preferred values of ratings

4.2.1 Rated temperature (T_R)

For capacitors covered by this document, the rated temperature is equal to the upper category temperature, unless the upper category temperature exceeds 125 °C.

4.2.2 Rated voltage (U_R)

The preferred values of the rated voltage are the values of the R5 series of ISO 3. If other values are needed, they shall be chosen from the R10 series.

The sum of the DC voltage and the peak AC voltage or the peak-to-peak AC voltage, whichever is the greater, applied to the capacitor shall not exceed the rated voltage.

4.2.3 Category voltage (U_C)

When the rated temperature is defined as the upper category temperature, the category voltage is equal to the rated voltage as defined in IEC 60384-1:2016/2021, 3.5. If the upper category temperature exceeds 125 °C, or the rated voltages exceed 500 V, the category voltage shall be given in the detail specification.

4.2.4 Preferred values of nominal capacitance and associated tolerance values

4.2.4.1 Preferred values of nominal capacitance

Nominal capacitance values ~~shall~~ should be taken from ~~the number series of IEC 60063~~; the E6, E12 and E24 series ~~are preferred~~ given in IEC 60063.

4.2.4.2 Preferred tolerances on nominal capacitance

See Table 1.

Table 1 – Preferred tolerances on nominal capacitance

Preferred series	Tolerance			
	$C_N \geq 10 \text{ pF}$	Letter code	$C_N < 10 \text{ pF}$	Letter code
E6	$\pm 20 \%$	M	$\pm 2 \text{ pF}$	G
E12	$\pm 10 \%$	K	$\pm 1 \text{ pF}$	F
E24	$\pm 5 \%$	J	$\pm 0,5 \text{ pF}$	D
	$\pm 2 \%$	G	$\pm 0,25 \text{ pF}$	C
	$\pm 1 \%$	F	$\pm 0,1 \text{ pF}$	B

4.2.5 Temperature coefficient (α)

4.2.5.1 Nominal temperature coefficient and tolerance (for reference temperature 20 °C)

Table 2 shows the ~~preferred~~ nominal temperature coefficients for the reference temperature 20 °C, the associated tolerances, expressed in parts per million per Kelvin ($10^{-6}/\text{K}$), and the corresponding subclasses and letter codes. The temperature coefficients, tolerances and letter codes for the reference temperature 25 °C are given in Annex B. **3**

The detail specification shall specify for each temperature coefficient the minimum value of capacitance for which the given tolerance of temperature coefficient can be verified, considering the accuracy of the methods of capacitance measurement specified.

For values of capacitance lower than this minimum value:

- the detail specification shall specify a multiplying factor for the tolerance on α , as well as the permissible changes of capacitance at the lower and upper category temperature;
- special methods of measurement ~~may~~ can be necessary and, if required, shall be stated in the detail specification.

Table 2 – Nominal temperature coefficient and tolerance (for reference temperature 20 °C)

Nominal temperature coefficient ($10^{-6}/\text{K}$)	Tolerance on temperature coefficient ($10^{-6}/\text{K}$)	Subclass	Letter code for	
			α	Tolerance
+100	± 30	1B	A	G
0	± 30	1B	C	G
–33	± 30	1B	H	G
–75	± 30	1B	L	G
–150	± 30	1B	P	G
–220	± 30	1B	R	G
–330	± 60	1B	S	H
–470	± 60	1B	T	H
–750	± 120	1B	U	J
–1 000	± 250	1F	Q	K
–1 500	± 250	1F	V	K
$+140 \geq \alpha \geq -1\,000$	^a	1C	SL	-

~~NOTE 1 Preferred temperature coefficients values (α) are underlined.~~

~~NOTE 2~~ The nominal temperature coefficients and their tolerances are defined using the capacitance change between the temperatures 20 °C and 85 °C.

~~NOTE 3~~ A capacitor with a temperature coefficient $0 \times 10^{-6}/K$ and a tolerance on temperature coefficient of $\pm 30 \times 10^{-6}/K$ is designated as a CG capacitor (subclass 1B).

^a This temperature coefficient value is not subject to inspection since no limits for relative capacitance variation are specified in Table 3.

~~NOTE See Annex B for the reference temperature of 25 °C as an informative guidance.~~

4.2.5.2 Permissible relative variation of capacitance

Table 3 shows for each combination of temperature coefficient and tolerance the permissible relative variation of capacitance expressed in parts per thousand at both the upper and lower category temperatures. Temperature coefficients and tolerances are expressed in parts per million per Kelvin ($10^{-6}/K$). In case of reference temperature 25 °C, see Table B.1 for an explanation of the permissible relative variation of capacitance.

Table 3 – Combination of temperature coefficient and tolerance

		Permissible relative variation in capacitance in parts per 1 000 between 20 °C and a given temperature							
		Lower category temperature				Upper category temperature			
α 10 ⁻⁶ /K	Tolerance 10 ⁻⁶ /K	-55 °C	-40 °C	-25 °C	-10 °C	+70 °C	+85 °C	+100 °C	+125 °C
+100	±30 (G)	-9,75/ -3,71	-7,80/ -2,96	-5,85/ -2,22	-3,90/ -1,48	3,50/ 6,50	4,55/ 8,45	5,60/ 10,4	7,35/ 13,7
0	±30 (G)	-2,25/ 5,45	-1,80/ 4,36	-1,35/ 3,27	-0,90/ 2,18	-1,50/ 1,50	-1,95/ 1,95	-2,40/ 2,40	-3,15/ 3,15
-33	±30 (G)	0,225/ 8,47	0,180/ 6,77	0,135/ 5,08	0,090/ 3,39	-3,15/ -0,15	-4,10/ -0,195	-5,04/ -0,240	-6,62/ -0,32
-75	±30 (G)	3,38/ 12,3	2,70/ 9,85	2,03/ 7,39	1,35/ 4,92	-5,25/ -2,25	-6,83/ -2,93	-8,40/ -3,60	-11,0/ -4,73
-150	±30 (G)	9,00/ 19,2	7,20/ 15,3	5,40/ 11,5	3,60/ 7,67	-9,00/ -6,0	-11,7/ -7,80	-14,4/ -9,60	-18,9/ -12,6
-220	±30 (G)	14,3/ 25,6	11,4/ 20,46	8,55/ 15,3	5,70/ 10,2	-12,5/ -9,50	-16,2/ -12,4	-20,0/ -15,2	-26,3/ -20,0
-330	±60 (H)	20,3/ 38,4	16,2/ 30,7	12,2/ 23,0	8,10/ 15,4	-19,5/ -13,5	-25,4/ -17,6	-31,2/ -21,6	-41,0/ -28,4
-470	±60 (H)	30,8/ 51,2	24,6/ 41,0	18,5/ 30,7	12,3/ 20,5	-26,5/ -20,5	-34,5/ -26,7	-42,4/ -32,8	-55,7/ -43,1
-750	±120 (J)	47,3/ 82,3	37,8/ 65,8	28,4/ 49,4	18,9/ 32,9	-43,5/ -31,5	-56,6/ -41,0	-69,6/ -50,4	-91,4/ -66,2
-1 000	±250 (K)	56,3/ 117	45,0/ 93,7	33,8/ 70,2	22,5/ 46,8	-62,5/ -37,5	-81,3/ -48,8	-100/ -60,0	-131/ -78,8
-1 500	±250 (K)	93,8/ 163	75,0/ 130	56,3/ 97,7	37,5/ 65,1	-87,5/ -62,5	-114/ -81,3	-140/ -100	-184/ -131

When the upper category temperature is above 125 °C, the limits shall be given in the detail specification.

~~NOTE 1 Preferred temperature coefficient values (α) are underlined.~~

~~NOTE 2 The temperature coefficient limits at the temperature range from 20 °C to the upper category temperature are calculated by the nominal temperature coefficients and their tolerances (see formula a) of NOTE 3).~~

~~The temperature coefficient limits at the temperature range from 20 °C to 55 °C are calculated by using the formulas b) and c) of NOTE 3.~~

~~NOTE 3 The capacitance deviations at the lower category temperature are obtained by using following formulas:~~

~~a) upper and lower permissible relative variation in capacitance under upper category temperature:~~

~~$$\Delta C/C (10^{-3}) = (\text{nominal temperature coefficient} \pm \text{tolerance on temperature coefficient}) \times (\text{upper category temperature} - 20)/1\,000$$~~

~~b) lower permissible relative variation in capacitance under lower category temperature:~~

~~$$\Delta C/C (10^{-3}) = (\text{nominal temperature coefficient} + \text{tolerance on temperature coefficient}) \times (\text{lower category temperature} - 20)/1\,000$$~~

~~c) upper permissible relative variation in capacitance under lower category temperature:~~

~~$$\Delta C/C (10^{-3}) = [(-36) - (1,22 \times \text{tolerance on temperature coefficient}) + (0,22 \times \text{nominal temperature coefficient}) + \text{nominal temperature coefficient}] \times (\text{lower category temperature} - 20)/1\,000$$~~

~~where tolerance on temperature coefficient* is an absolute value.~~

Formulas for calculation of the permissible relative variation in capacitance:

Permissible relative variation in the temperature range from 20 °C to the upper category temperature:

$$\Delta C/C (10^{-3}) = (\alpha \pm |\delta|) \times (UCT - 20)/1\,000 \quad (1)$$

Permissible relative variation in the temperature range from 20 °C to the lower category temperature:

a) lower permissible relative variation in capacitance from 20 °C to lower category temperature:

$$\Delta C/C (10^{-3}) = (\alpha \pm |\delta|) \times (LCT - 20)/1\,000 \quad (2)$$

b) upper permissible relative variation in capacitance from 20 °C to lower category temperature:

$$\Delta C/C (10^{-3}) = [(-36) - (1,22 \times |\delta|) + (0,22 \times \alpha) + \alpha] \times (LCT - 20)/1\,000 \quad (3)$$

α Temperature coefficient

δ Tolerance of α

LCT Lower category temperature

UCT Upper category temperature

4.2.6 Dimensions

Suggested rules for the specification and coding of dimensions are given in Annex A.

Specific dimensions shall be given in the detail specification.

5 Test and measurement procedures

5.1 General

This Clause 5 supplements the information given in IEC 60384-1:2016/2021, Clause 5 to Clause 10.

5.2 Preliminary drying

See IEC 60384-1:20162021, 5.3.

5.3 Measuring conditions

See IEC 60384-1:20162021, 5.2.1.

5.4 Mounting

See IEC 60384-1:20162021, 5.5.

5.5 Visual examination and check of dimensions

5.5.1 General

See IEC 60384-1:20162021, 7.1, with the details of 5.5.2 and 5.5.3.

5.5.2 Visual examination

A visual examination shall be carried out with suitable equipment with approximately 10× magnification and lighting appropriate to the specimen under test and the quality level required. In case the specimen are very small components, the visual examination may be carried out with higher magnification.

The operator should have available facilities for incident or transmitted illumination as well as an appropriate measuring facility.

5.5.3 Requirements

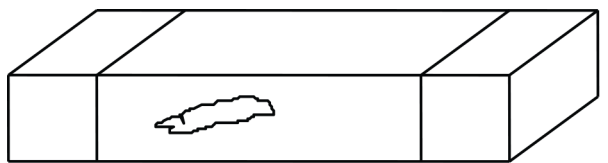
5.5.3.1 General

Quantitative values for the requirements below may be given in the detail or in the manufacturer's specification.

5.5.3.2 Requirements for the ceramic

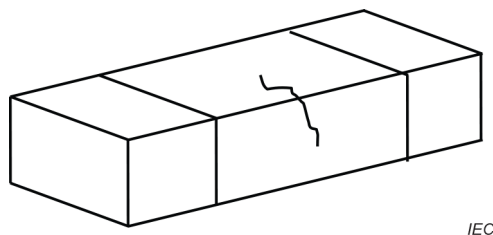
Requirements for the ceramic are as follows:

- a) Be free of cracks or fissures, except small damages on the surface, that do not deteriorate the performance of the capacitor (examples: see Figure 1 and Figure 2).



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Figure 1 – Fault: crack or fissure



NOTE Crack or fissure on one side or extending from one face to another over a corner.

Figure 2 – Fault: crack or fissure

- b) Not exhibit visible separation or delamination between the layers of the capacitor (see Figure 3).

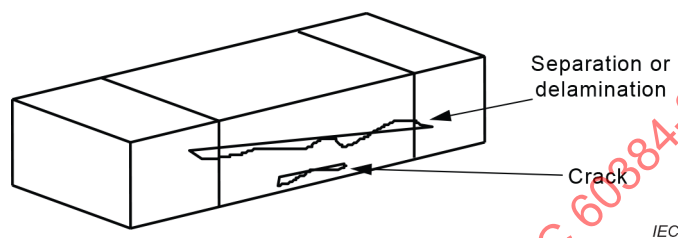


Figure 3 – Separation or delamination

- c) Not exhibit exposed electrodes between the two terminations (see Figure 4).

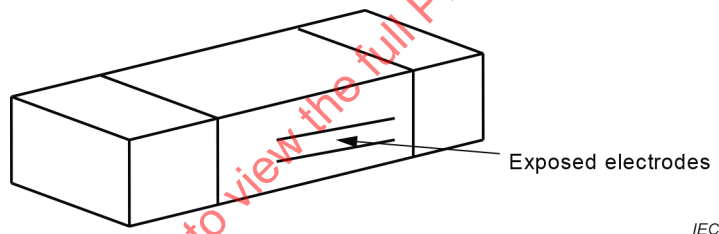


Figure 4 – Exposed electrodes

- d) The ceramic body shall be free of any conducting smears (metallization, tinning, etc.) on a central zone between two adjacent terminations which is equal to the minimum distance between those (Annex A, dimension L_4).

5.5.3.3 Requirements for the metallization

Requirements for the metallization are as follows:

- Not exhibit any visible detachment of the metallized terminations and not exhibit any exposed electrodes (see Figure 4).
- The principal faces (see Figure 5) are those noted A, B and C.

In the case of capacitors of square section, the faces D and E are also considered principal.

The maximum area of gaps in metallization on each principal face shall not be greater than 15 % of the area of that face; these gaps shall not be concentrated in the same area. The gaps in metallization shall not affect the two principal edges of each extremity of the block (or four edges for square section capacitors). Dissolution of the end face plating (leaching) shall not exceed 25 % of the length of the edge concerned.

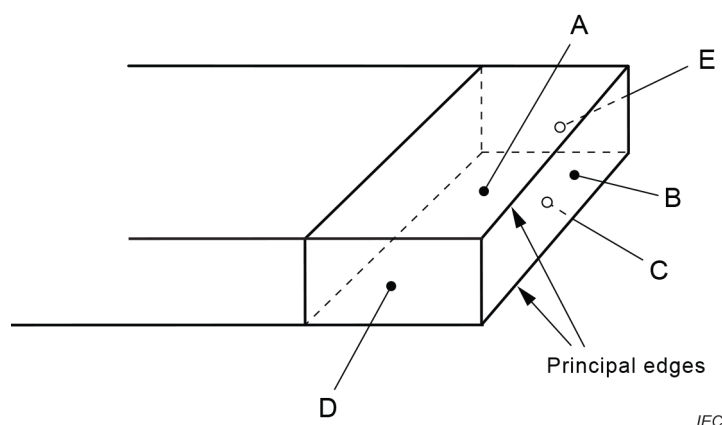


Figure 5 – Principal faces

5.6 Electrical tests

5.6.1 Capacitance

5.6.1.1 General

See IEC 60384-1:2016/2021, 6.3, with the details of 5.6.1.2 and 5.6.1.3.

5.6.1.2 Measuring conditions

Unless otherwise specified in the detail specification,

- measuring voltage: $\leq 5 \text{ V RMS}$,
- frequency: $C_N \leq 1\,000 \text{ pF}$ 1 MHz or 100 kHz (reference frequency 1 MHz);
 $C_N > 1\,000 \text{ pF}$ 1 kHz or 100 kHz (reference frequency 1 kHz).

5.6.1.3 Requirements

The capacitance value as measured in the unmounted state, shall correspond to the rated value taking into account the specified tolerance.

The capacitance as measured in the mounted state in accordance with Group 3 is for reference purposes only in further tests.

5.6.2 Tangent of loss angle ($\tan \delta$)

5.6.2.1 General

See IEC 60384-1:2016/2021, 6.4, with the details of 5.6.2.2 and 5.6.2.3.

5.6.2.2 Measuring conditions

The measuring conditions are the same as those of 5.6.1. The inaccuracy of the measuring equipment shall not exceed 3×10^{-4} .

5.6.2.3 Requirements

The tangent of loss angle as measured in the unmounted state shall not exceed the limit given in Table 4.

Table 4 – Tangent of loss angle limits

Nominal capacitance pF	Tangent of loss angle ($\tan \delta$) $\times 10^{-4}$		
	$+100 \geq \alpha > -750$ and SL (1C) C0G	$-750 \geq \alpha > -1\ 500$ U2J	$\alpha = -1\ 500$
$C_N \geq 50$	15	20	30
$5 \leq C_N < 50$	$1,5 \left(\frac{150}{C_N} + 7 \right)$	$2 \left(\frac{150}{C_N} + 7 \right)$	$3 \left(\frac{150}{C_N} + 7 \right)$
$C_N < 5$	When the measurement is required the detail specification shall specify the limit.		

The tangent of loss angle as measured in the mounted state in accordance with Group 3 is for reference purpose only in further tests.

5.6.3 Insulation resistance

5.6.3.1 General

See IEC 60384-1:2016/2021, 6.1, with the details of 5.6.3.2 to 5.6.3.4.

5.6.3.2 Preparation for test

Prior to the test, capacitors shall be carefully cleaned to remove any contamination.

Care shall be taken to maintain cleanliness in the test chambers and during post-test measurements. Before the measurement, the capacitors shall be fully discharged. The insulation resistance shall be measured between the terminations.

5.6.3.3 Measuring conditions

See IEC 60384-1:2016/2021, 6.1.2, with the following details.

The measuring voltage may be of any value not greater than U_R , the referee voltage being U_R , for a capacitor with a rated voltage below or equal to 1 kV. For $U_R > 1$ kV the referee voltage shall be 1 kV.

The insulation resistance (R_i) shall be measured after the voltage has been applied for (60 ± 5) s.

For lot-by-lot testing (Group A) the test may be terminated in a shorter time, if the required value of insulation resistance is reached.

The product of the internal resistance of the voltage source and the nominal capacitance of the capacitor shall not exceed 1 s, unless otherwise ~~prescribed~~ specified in the detail specification.

The charge current shall not exceed 0,05 A. For capacitors with rated voltages of 1 kV and above, a lower limit (value) may be given in the detail specification.

5.6.3.4 Requirements

The insulation resistance shall meet the following requirements.

$C_N \leq 10$ nF	$R_i \geq 10\ 000$ M Ω
$C_N > 10$ nF	$R_i \times C_N \geq 100$ s

5.6.4 Voltage proof

5.6.4.1 General

See IEC 60384-1:2016:2021, 6.2, with the details of 5.6.4.2 to 5.6.4.4.

5.6.4.2 Test conditions

The product of R_1 and the nominal capacitance C_X shall be smaller than or equal to 1 s.

NOTE R_1 is a charging resistor that includes the internal resistance of the voltage source. More information can be found in IEC 60384-1:2016:2021, 6.2.2.

The charge current shall not exceed 0,05 A.

For capacitors with rated voltages of 1 kV and above, a lower charge current limit value may be given in the detail specification. To protect the capacitors against flashover, the test may be performed in a suitable insulating medium.

5.6.4.3 Test voltages

The test voltages in accordance with Table 5 shall be applied between the measuring points of 5.6.3 and Table 3 in IEC 60384-1:2016:2021, for a period of 1 min for qualification approval testing and for a period of 1 s for the lot-by-lot quality conformance testing.

Table 5 – Test voltages

Rated voltage V	Test voltage V
$U_R \leq 100$	$2,5 U_R$
$100 < U_R \leq 200$	$1,5 U_R + 100$
$200 < U_R \leq 500$	$1,3 U_R + 100$
$500 < U_R < 1\,000$	$1,3 U_R$
$U_R \geq 1\,000$	$1,2 U_R$

5.6.4.4 Requirement

There shall be no breakdown or flashover during the test.

5.7 Temperature coefficient (α) and temperature ~~cycle~~ cyclic drift

5.7.1 General

See IEC 60384-1:2016:2021, 6.8.3.3, with the details of 5.7.2 to 5.7.4.

5.7.2 Preliminary drying

The capacitors shall be dried in accordance with 5.2 for 16 h to 24 h.

5.7.3 Measuring conditions

See IEC 60384-1:2016:2021, 6.8.1.2 and 6.8.1.3, with the following details.

The capacitors shall be measured in the unmounted state.

5.7.4 Requirements

The capacitance deviation at upper and lower category temperature (and at such other temperatures as may be specified in the detail specification) shall not exceed the limits given in Table 3.

The temperature cyclic drift shall not exceed the limits given in Table 6.

Table 6 – Temperature cyclic drift limits

α rated in $10^{-6}/K$	Requirements ^a
$+100 \geq \alpha > -150$ C0G	0,3 % or 0,05 pF
$-150 \geq \alpha > -1\ 500$ and SL (1C) U2J	1 % or 0,05 pF
$\alpha = -1\ 500$	2 % or 0,05 pF
^a Whichever is the greater.	

5.8 Shear test

See IEC 60384-1:2016/2021, 7.7.

A force shall be selected from 1 N, 2 N, 5 N or 10 N and specified in the detail specification.

5.9 Substrate bending test

5.9.1 General

See IEC 60384-1:2016/2021, 7.8.

Unless otherwise specified in the detail specification,

- the deflection D shall be selected from 1 mm, 2 mm or 3 mm, higher deflection values may be given in the detail specification in case of very robust designs.
- the number of bends shall be 1 time,
- the radius of the bending tool shall be 5 mm,
When the deflection D is 2 mm or less, the radius may be 230 mm.
- the duration in the bent state shall be 5 s.

For 1005 M or smaller size, the thickness of substrate should be 0,8 mm.

5.9.2 Initial measurement

The capacitance shall be measured as specified in 5.6.1 and in the detail specification.

5.9.3 Final inspection

The capacitors shall be visually examined and there shall be no visible damage.

See 5.5.2.

The change of capacitance with board in bent position shall not exceed 5 %.

5.10 Resistance to soldering heat

5.10.1 General

See IEC 60068-2-58 with the details of 5.10.2 to 5.10.5.

5.10.2 Initial measurement

The capacitance shall be measured in accordance with 5.6.1.

5.10.3 Test conditions

5.10.3.1 Solder bath method (applicable to 1608 M, 2012 M and 3216 M)

~~NOTE~~ See Table A.1 for explanation of the size code.

See IEC 60068-2-58, Test Td₂, Method 1, with the following details, if not otherwise specified in the detail specification:

The specimen shall be preheated to a temperature of 110 °C to 140 °C and maintained for 30 s to 60 s.

Solder alloy:	Sn-Pb or Sn-Ag-Cu
Temperature:	260 °C ± 5 °C
Duration of immersion:	10 s ± 1 s
Depth of immersion:	10 mm
Number of immersions:	1

5.10.3.2 Infrared and forced gas convection soldering system

See IEC 60068-2-58, Test Td₂, Method 2, with the following details:

- a) the solder paste shall be applied to the test substrate;
- b) the thickness of solder deposit shall be specified in the detail specification;
- c) the terminations of the specimen shall be placed on the solder paste;
- d) solder alloy: Sn-Pb;

unless otherwise specified in the detail specification, the specimen and test substrate shall be preheated to a temperature of (150 ± 10) °C and maintained for 60 s to 120 s in infrared and forced gas convection soldering system;

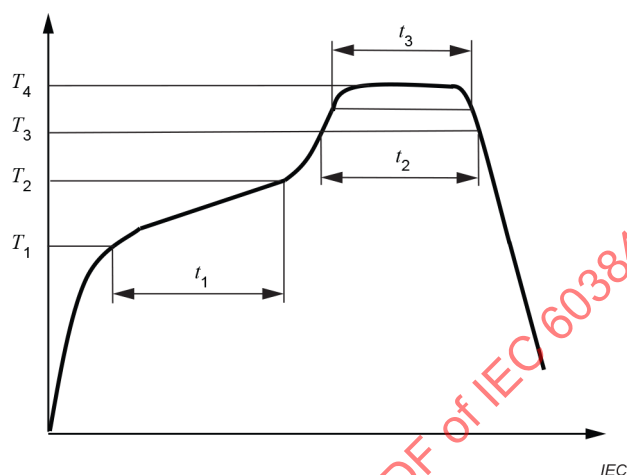
the temperature of the reflow system shall be quickly raised until the specimen has reached (235 ± 5) °C and maintained at this temperature for (10 ± 1) s;

- e) solder alloy: Sn-Ag-Cu;

unless otherwise specified in the detail specification, the reflow temperature profile shall be selected from Table 7 and Figure 6;

Table 7 – Reflow temperature profiles for Sn-Ag-Cu alloy

Alloy composition		T_1 °C	T_2 °C	t_1 s	T_3 °C	t_2 s	T_4 °C	t_3 s
Lead-free solder (Sn-Ag-Cu)	Test 1	150 ± 5	180 ± 5	120 ± 5	220	60 to 90	250	20 to 40 at $T_4 - 5 \text{ °C}$
	Test 2	~~150 ± 5~~	~~180 ± 5~~	~~120 ± 5~~	220	~~≤ 60~~	~~255~~	~~≤ 20 at $T_4 - 10 \text{ °C}$~~

**Figure 6 – Reflow temperature profile**

- f) number of each test: 1, unless otherwise specified in the detail specification;
g) the temperature profile of d) or e) shall be specified in the detail specification.

5.10.4 Recovery

The capacitors shall recover for 6 h to 24 h.

The flux residues shall be removed with a suitable solvent.

5.10.5 Final inspection, measurements and requirements

After recovery, the capacitors shall be visually examined and measured and shall meet the following requirements.

Under normal lighting and approximately 10× magnification, there shall be no signs of damage such as cracks. See 5.5.2.

Dissolution of the end face plating (leaching) shall not exceed 25 % of the length of the edge concerned. The detail specification may ~~prescribe~~ specify further details.

The capacitance shall be measured in accordance with 5.6.1 and the change shall not exceed the values in Table 8.

Table 8 – Maximum capacitance change

α rated in $10^{-6}/\text{K}$	Requirements ^a
$+100 \geq \alpha \geq -750$ C0G and U2J	0,5 % or 0,5 pF
$-750 > \alpha \geq -1\,500$ and SL (1C)	1 % or 1 pF
^a Whichever is the greater.	

5.11 Solderability

5.11.1 General

See IEC 60068-2-58 with the details of 5.11.2 to 5.11.4.

5.11.2 Test conditions

5.11.2.1 Solder bath method (applicable to 1608 M, 2012 M and 3216 M)

~~NOTE~~ See Table A.1 for explanation of the size code.

See IEC 60068-2-58, Test Td₁, Method 1, with the following details, if not otherwise specified in the detail specification:

The specimen shall be preheated to a temperature of 80 °C to 140 °C and maintained for 30 s to 60 s.

Solder alloy:	Sn-Pb	Sn-Ag-Cu
Temperature:	(235 ± 5) °C	(245 ± 5) °C
Duration of immersion:	(2 ± 0,2) s	(3 ± 0,3) s
Depth of immersion:	10 mm	10 mm
Number of immersions:	1	1

5.11.2.2 Infrared and forced gas convection soldering system

See IEC 60068-2-58, Test Td₁, Method 2, with the following details:

- the solder paste shall be applied to the test substrate;
- the thickness of solder deposit shall be specified in the detail specification;
- the terminations of the specimen shall be placed on the solder paste;
- solder alloy: Sn-Pb;

unless otherwise specified in the detail specification, the specimen and test substrate shall be preheated to a temperature of (150 ± 10) °C and maintained for 60 s to 120 s in the infrared and forced gas convection soldering system;

the temperature of the reflow system shall be quickly raised until the specimen has reached (215 ± 3) °C and maintained at this temperature for (10 ± 1) s;
- solder alloy: Sn-Ag-Cu;

unless otherwise specified in the detail specification, the specimen and test substrate shall be preheated to a temperature of (150 ± 5) °C to (180 ± 5) °C for 60 s to 120 s in the infrared and forced gas convection soldering system;

the temperature of the reflow system shall be quickly raised until the specimen has reached (235 ± 3) °C. The time above 225 °C shall be (20 ± 5) s;
- the temperature profile of d) or e) shall be specified in the detail specification.

5.11.3 Recovery

The flux residues shall be removed with a suitable solvent.

5.11.4 Final inspection, measurements and requirements

The capacitors shall be visually examined under normal lighting and approximately 10× magnification. There shall be no signs of damage. See 5.5.2.

Both end face and the contact areas shall be covered with a smooth and bright solder coating with no more than a small number of scattered imperfections such as pinholes or unwetted or de-wetted areas. These imperfections shall not be concentrated in one area.

The detail specification may ~~prescribe~~ specify further requirements.

5.12 Rapid change of temperature

5.12.1 General

This test shall be applied only to capacitors for which the category temperature is greater 110 °C.

See IEC 60384-1:2016/2021, 8.1, with the details of 5.12.2 to 5.12.5.

The capacitors shall be mounted in accordance with 5.4.

5.12.2 Initial measurement

The capacitance shall be measured in accordance with 5.6.1.

5.12.3 Number of cycles

The number of cycles: 5.

Duration of exposure at the temperature limits: 30 min.

5.12.4 Recovery

The capacitors shall recover for 6 h to 24 h.

5.12.5 Final inspection, measurements and requirements

The capacitors shall be visually examined. There shall be no visible damage. See 5.5.2.

The capacitance shall be measured in accordance with 5.6.1 and the change shall not exceed the value in Table 9.

Table 9 – Maximum capacitance change

α rated in $10^{-6}/K$	Requirements ^a
$+100 \geq \alpha \geq -750$ C0G and U2J	1 % or 1 pF
$-750 > \alpha \geq -1\,500$ and SL (1C)	2 % or 1 pF
^a Whichever is the greater.	

5.13 Climatic sequence

5.13.1 General

See IEC 60384-1:20162021, 8.2, with the details of 5.13.2 to 5.13.7.

5.13.2 Initial measurement

The capacitance shall be measured in accordance with 5.6.1.

5.13.3 Dry heat

See IEC 60384-1:20162021, 8.2.3.

5.13.4 Damp heat, cyclic, Test Db, first cycle

See IEC 60384-1:20162021, 8.2.4.

5.13.5 Cold

See IEC 60384-1:20162021, 8.2.5, with the following details.

The capacitors shall be visually examined. There shall be no visible damage.

5.13.6 Damp heat, cyclic, Test Db, remaining cycles

5.13.6.1 General

See IEC 60384-1:20162021, 8.2.7, with the details of 5.13.6.2 and 5.13.6.3.

5.13.6.2 Test conditions

No voltage applied.

The remaining cycles shall be tested in accordance with Table 10.

Table 10 – Number of damp heat cycles

Category	No. of cycles of 24 h
- / - / 56	5
- / - / 21	1
- / - / 10	1
- / - / 04	0

5.13.6.3 Recovery

The capacitors shall recover for 6 h to 24 h.

5.13.7 Final inspection, measurements and requirements

The capacitors shall be visually examined. There shall be no visible damage. See 5.5.2.

The capacitors shall be measured and shall meet the requirements in Table 11.

Table 11 – Final inspection, measurements and requirements

Measurement	Measurement and conditions	α rated and (Subclass)	Requirements
Capacitance	5.6.1	+100 $\geq \alpha \geq$ -750 (1B) C0G and U2J	Capacitance change $\leq 2\%$ or 1 pF ^a
		-750 $> \alpha \geq$ -1 500 (1F) SL (1C)	Capacitance change $\leq 3\%$ or 1 pF ^a
Tangent of loss angle	5.6.2	All α s and subclasses	$\leq 2\times$ value in the table of 5.6.2
Insulation resistance	5.6.3	All α s and subclasses	$R_i \geq 2\,500\text{ M}\Omega$ or $R_i \times C_N \geq 25\text{ s}$ ^b
NOTE See 4.2.5 for an explanation of the subclass codes. ^a Whichever is the greater. ^b Whichever is the lower.			

5.14 Damp heat, steady state

5.14.1 General

See IEC 60384-1:2016/2021, 8.3, with the details of 5.14.2 to 5.14.5.

The capacitors shall be mounted in accordance with 5.4.

5.14.2 Initial measurement

The capacitance shall be measured in accordance with 5.6.1.

5.14.3 Test conditions

No voltage shall be applied, unless otherwise specified in the detail specification.

The severity of the test should be selected from the test conditions as shown in Table 12 and be specified in the detail specification.

The duration time should be selected in accordance with 4.1 and shall be specified in the detail specification.

Table 12 – Test conditions for damp heat, steady state

Severity	Temperature °C	Relative humidity %
1	+85 $\pm$ 2	85 $\pm$ 3
2	+60 $\pm$ 2	93 $\pm$ 3
3	+40 $\pm$ 2	93 $\pm$ 3

When the application of voltage is ~~prescribed~~ specified, U_R shall be applied to one half of the lot and no voltage shall be applied to the other half of the lot.

Within 15 min after removal from the damp heat test, the voltage proof test in accordance with 5.6.4 shall be carried out, but with the rated voltage applied.

For safety reasons, different conditions for the application of voltage to capacitors with rated voltages of 1 kV or above may be given in the detail specification.

5.14.4 Recovery

The capacitors shall recover for 6 h to 24 h.

5.14.5 Final inspection, measurements and requirements

The capacitors shall be visually examined. There shall be no visible damage. See 5.5.2.

The capacitors shall be measured and shall meet the requirements in Table 13.

Table 13 – Final inspection, measurements and requirements

Measurement	Measurement and conditions	α rated and (Subclass)	Requirements
Capacitance	5.6.1	+100 $\geq \alpha \geq$ -750 (1B) C0G and U2J	Capacitance change $\leq 2\%$ or 1 pF ^a
		-750 $> \alpha \geq$ -1 500 (1F) SL (1C)	Capacitance change $\leq 3\%$ or 1 pF ^a
Tangent of loss angle	5.6.2	All α s and subclasses	$\leq 2\times$ value in the table of 5.6.2
Insulation resistance	5.6.3	All α s and subclasses	$R_i \geq 2\,500\text{ M}\Omega$ or $R_i \times C_N \geq 25\text{ s}^b$
NOTE See 4.2.5 for an explanation of the subclass codes. ^a Whichever is the greater. ^b Whichever is the lower.			

5.15 Endurance

5.15.1 General

See IEC 60384-1:2016/2021, 8.5, with the details of 5.15.2 to 5.15.5.

The capacitors shall be mounted in accordance with 5.4.

5.15.2 Initial measurement

The capacitance shall be measured in accordance with 5.6.1.

5.15.3 Test conditions

If the category voltage is equal to the rated voltage, the capacitors shall be tested as in Table 14.

Table 14 – Endurance test conditions ($U_C = U_R$)

U_R	$U_R \leq 200$	$200 < U_R \leq 500$	$U_R > 500$
Temperature	Upper category temperature		
Voltage (DC)	1,5 U_R	1,3 U_R	1,2 U_R
Duration	1 000 h	1 500 h	2 000 h

If the category voltage is not equal to the rated voltage, the capacitors shall be tested as in Table 15.

Table 15 – Endurance test conditions ($U_C \neq U_R$)

U_R	$U_R \leq 200$		$200 < U_R \leq 500$		$U_R > 500$	
Temperature	T_R	T_B	T_R	T_B	T_R	T_B
Voltage (DC)	1,5 U_R	1,5 U_C	1,3 U_R	1,3 U_C	1,2 U_R	1,2 U_C
Duration	1 000 h		1 500 h		2 000 h	
Sample	Divided into two parts		Divided into two parts		Divided into two parts	
T_R = Rated temperature.						
T_B = Upper category temperatures > 85 °C, such as 100 °C, 125 °C and 150 °C.						

5.15.4 Recovery

The capacitors shall recover for 6 h to 24 h.

5.15.5 Final inspection, measurements and requirements

The capacitors shall be visually examined. There shall be no visible damage. See 5.5.2.

The capacitors shall be measured and shall meet the requirements in Table 16.

Table 16 – Final inspection, measurements and requirements

Measurement	Measurement and conditions	α rated and (Subclass)	Requirements
Capacitance	5.6.1	$+100 \geq \alpha \geq -750$ (1B) C0G and U2J	Capacitance change $\leq 2 \%$ or 1 pF^a
		$-750 > \alpha \geq -1\,500$ (1F) SL (1C)	Capacitance change $\leq 3 \%$ or 1 pF^a
Tangent of loss angle	5.6.2	All α s and subclasses	$\leq 2 \times$ value in the table of 5.6.2.
Insulation resistance	5.6.3	All α s and subclasses	$R_i \geq 4\,000 \text{ M}\Omega$ or $R_i \times C_N \geq 40 \text{ s}^b$
NOTE See 4.2.5 for an explanation of the subclass codes.			
^a Whichever is the greater.			
^b Whichever is the lower.			

5.16 Robustness of terminations (only for capacitors with strip termination)

5.16.1 General

See IEC 60384-1:2016/2021, 7.3, with the details of 5.16.2 and 5.16.3.

5.16.2 Test conditions

Unless otherwise specified in the detail specification, the conditions of the tests are as follows:

- Test U_{a1} : force: 2,5 N;
- Test U_b , Method 1: force: 2,5 N;

- number of bends: 1.

5.16.3 Final inspection and requirements

The capacitors shall be visually examined. There shall be no visible damage.

5.17 Component solvent resistance (if required)

See IEC 60384-1:2016/2021, 9.4.

5.18 Solvent resistance of the marking (if required)

See IEC 60384-1:2016/2021, 9.5.

5.19 Accelerated damp heat, steady state (if required)

5.19.1 General

See IEC 60384-1:2016/2021, 8.9, with the details of 5.19.2 to 5.19.5.

The capacitors shall be mounted in accordance with 5.4 and IEC 60384-1:2016/2021, 8.9.1.

Half the capacitors shall be connected in series with resistors of 100 k Ω , with a relative tolerance of ± 10 %, and half in series with resistors of 6,8 k Ω , with a relative tolerance of ± 10 %.

5.19.2 Initial measurement

The capacitors shall be measured for insulation resistance with a voltage of 1,5 V $\pm$ 0,1 V applied across the capacitor and resistor in series.

The insulation resistance, including the series resistor, shall meet the requirements given in Table 17.

Table 17 – Initial requirements

Measurement	Measuring conditions	Requirements	
Insulation resistance	(1,5 $\pm$ 0,1) V	Connected to 100 k Ω resistors	$C_N \leq 10$ nF: $R_i \geq 10\,000$ M Ω $C_N > 10$ nF: $(R_i - 100\text{ k}\Omega) \times C_N \geq 100$ s
		Connected to 6,8 k Ω resistors	$C_N \leq 10$ nF: $R_i \geq 10\,000$ M Ω $C_N > 10$ nF: $(R_i - 6,8\text{ k}\Omega) \times C_N \geq 100$ s

5.19.3 Conditioning

The capacitors with associated resistors shall be subjected to conditioning at (85 $\pm$ 2) °C, (85 $\pm$ 3) % relative humidity for the test duration given in Table 18. The voltage given in Table 18 shall be applied to the capacitors connected to 100 k Ω resistors and those connected to 6,8 k Ω resistors. In both cases, the voltage shall be applied across the capacitor/resistor combination.

Care shall be taken to avoid condensation of water on the capacitors or substrates. This ~~may~~ can happen if the door is opened during the test before the humidity is lowered.

Table 18 – Conditioning

Connected resistors kΩ	Applied voltage	Duration
100	(1,5 ± 0,1) V or the voltage specified in the detail specification	168 h, 500 h or 1 000 h; as specified in the detail specification
6,8	(50 ± 0,1) V or U_R , whichever is the lower, or the voltage specified in the detail specification	

5.19.4 Recovery

The applied voltage shall be disconnected, and the capacitors and resistors shall be removed from the test chamber and allowed to recover for 6 h to 24 h in standard atmospheric conditions for testing.

5.19.5 Final measurements

The capacitors shall be measured for insulation resistance, as in 5.19.2.

The insulation resistance, including the series resistor, shall be greater than 0,1 times the values given in 5.19.2.

6 Marking

6.1 General

See IEC 60384-1:2016/2021, 4.3, with the details of 6.2 to 6.6.

6.2 Information for marking

The information given in the marking is normally selected from the following list: the relative importance of each item is indicated by its position in the list:

- nominal capacitance;
- rated voltage (DC voltage may be indicated by the symbol: $\overline{\text{---}}$ [IEC 60417-5031(2002-10)] or ---);
- tolerance on nominal capacitance;
- temperature coefficient and its tolerance as applicable (in accordance with 4.2.5) or Annex B;
- year and month (or week) of manufacture;
- manufacturer's name or trade mark;
- climatic category;
- manufacturer's type designation;
- reference to the detail specification.

6.3 Marking on the body

These capacitors are generally not marked on the body. If some marking can be applied, they shall be clearly marked with as many as possible of the items stated in 6.2 as is considered useful. Any duplication of information in the marking on the capacitor should be avoided.

6.4 Requirements for marking

Any marking shall be legible and not easily smeared or removed by rubbing with fingers.

6.5 Marking of the packaging

The packaging containing the capacitor(s) shall be clearly marked with all the information listed in 6.2.

6.6 Additional marking

Any additional marking shall be so applied that no confusion can arise.

7 Information to be given in a detail specification

7.1 General

The detail specification shall be derived from the relevant blank detail specification.

Detail specifications shall not specify requirements inferior to those of the generic, sectional or blank detail specification. When more severe requirements are included, they shall be ~~listed in 1.9 of the detail specification and~~ indicated in the test schedules, for example by an asterisk.

The information given in 7.2 may be presented in tabular form if more convenient.

The information in 7.2 to 7.5 shall be given in each detail specification and the values quoted should be selected from those given in the appropriate clause of this document.

7.2 Outline drawing and dimensions

There shall be an illustration of the capacitors as an aid to easy recognition and for comparison of the capacitors with others.

Dimensions and their associated tolerances, which affect interchangeability and mounting, shall be given in the detail specification. All dimensions shall be stated in millimetres; however, when the original dimensions are given in inches, the converted metric dimensions in millimetres shall be added.

Normally the numerical values shall be given for the length, width and height of the body. When necessary, for example when a number of items (sizes and capacitance/voltage ranges) are covered by a detail specification, the dimensions and their associated tolerances shall be placed in a table below the drawing.

When the configuration is other than described above, the detail specification shall state such dimensional information as will adequately describe the capacitors.

7.3 Mounting

The detail specification shall give guidance on methods of mounting for normal use. Mounting for test and measurement purposes (when required) shall be in accordance with 5.4 of this document.

7.4 Rating and characteristics

7.4.1 General

The ratings and characteristics shall be in accordance with the relevant clauses of this document, together with 7.4.2, 7.4.3 and 7.4.4.

7.4.2 Nominal capacitance range

The nominal capacitance range shall be specified as described in 4.2.4.1.

When products approved to the detail specification have different ranges, the following statement should be added: "The range of capacitance values available in each voltage range is given in the register of approvals, available for example on the IECQ on-line certificate system website: www.iecq.org".

7.4.3 Particular characteristics

Additional characteristics may be listed when they are considered necessary to specify adequately the component for design and application purposes.

7.4.4 Soldering

The detail specification shall ~~prescribe~~ specify the test methods, severities and requirements applicable for the solderability and the resistance to soldering heat tests.

7.5 Marking

The detail specification shall specify the content of the marking on the capacitor and on the packaging. Deviations from Clause 6 shall be specifically stated in the detail specification.

8 Quality assessment procedures

8.1 Primary stage of manufacture

The primary stage of manufacture is the first common firing of the dielectric-electrode assembly.

8.2 Structurally similar components

Capacitors considered as being structurally similar are capacitors produced with similar processes and materials, though they ~~may~~ can be of different case sizes and values.

8.3 Certified records of released lots

The information required in IEC 60384-1:20162021, Q.1.5, shall be made available when ~~prescribed~~ specified in the detail specification and when requested by a purchaser. After the endurance test, the parameters for which variables information is required are the capacitance change, $\tan \delta$ and the insulation resistance.

8.4 Qualification approval

8.4.1 General

The procedures for qualification approval testing are given in IEC 60384-1:20162021, Clause Q.2.

The schedule to be used for qualification approval testing on the basis of lot-by-lot and periodic tests is given in Annex C. The procedure using a fixed sample size schedule is given in 8.4.2 and 8.4.3.

8.4.2 Qualification approval on the basis of the fixed sample size procedures

The fixed sample size procedure is described in IEC 60384-1:20162021, Q.2.4. The sample shall be representative of the range of capacitors for which approval is sought. This range may ~~or may not~~ be different from the complete range covered by the detail specification.

For each temperature coefficient, the sample shall consist of specimens of capacitors of maximum and minimum size and for each of these sizes, the maximum capacitance value for the highest rated voltage and minimum rated voltage of the voltage ranges for which approval is sought. When there are more than four rated voltages, an intermediate voltage shall also be tested. Thus, for the approval of a range, testing is required of either four or six values (capacitance/voltage combinations) for each temperature coefficient. Where the total range consists of fewer than four values, the number of specimens to be tested shall be that required for four values. When approval is sought for more than one temperature coefficient, see 8.4.3.

In case assessment level EZ is used, spare specimens are permitted as follows:

Two (for six values) or three (for four values) per value may be used as replacements for specimens that are non-conforming because of incidents not attributable to the manufacturer.

The numbers given in Group 0 assume that all groups are applicable. If this is not so, the numbers may be reduced accordingly.

When additional groups are introduced into the qualification approval test schedule, the number of specimens required for Group 0 shall be increased by the same number as that required for the additional groups.

Table 4 gives the number of samples to be tested in each group or subgroup together with the number of permissible non-conformances for the qualification approval test.

8.4.3 Tests

The complete series of tests specified in Table 19 and Table 20 are required for the approval of capacitors covered by one detail specification. The tests of each group shall be carried out in the order given.

The whole sample shall be subjected to the tests of Group 0 and then divided for the other groups.

Non-conforming specimens found during the tests of Group 0 shall not be used for the other groups.

"One non-conforming item" is counted when a capacitor has not satisfied the whole or a part of the tests of a group.

When approval is sought for more than one temperature coefficient at the same time, the test schedule and sample size required for the smallest temperature coefficient are those of Groups 1, 2 and 3. For each additional temperature coefficient, the testing is limited to the tests and sample sizes as specified for Subgroup 3.3 and Group 4.

The approval is decided on an individual temperature coefficient basis in accordance with the permissible number of non-conforming items indicated in Table 4. In order to calculate the total actual non-conforming items for temperature coefficients other than the smallest, the non-conforming items in Groups 1, 2 and 3 for the smallest temperature coefficient are added to the non-conforming items in Subgroup 3.3 and Group 4 for that particular temperature coefficient.

The approval is granted when the number of non-conforming items is zero.

Table 19 and Table 20 together form the fixed sample size test schedule. Table 4 includes the details for the sampling and permissible non-conforming items for the different tests or groups of tests. Table 5 together with the details of the test contained in Clause 8 gives a complete summary of test conditions and performance requirements and indicates where, for example for the test method or conditions of test, a choice shall be made in the detail specification.

The conditions of test and performance requirements for the fixed sample size test schedule shall be identical to those ~~prescribed~~ specified in the detail specification for quality conformance inspection.

Table 19 – Fixed sample size test plan for qualification approval
Assessment level EZ

Group No.	Test	Subclause of this publication	Number of specimens n^e	Permissible number of nonconforming items c
0	Visual examination Dimensions Capacitance Tangent of loss angle Insulation resistance Voltage proof Spare specimens	5.5 5.5 5.6.1 5.6.2 5.6.3 5.6.4 12	132 + 24 ^f 12	0 0
1A	Robustness of termination ^g Resistance to soldering heat Component solvent resistance ^b	5.16 5.10 5.17	12 12	0 0
1B	Solderability Solvent resistance of marking ^b	5.11 5.18	12 12	0 0
2	Substrate bending test ^d	5.9	12	0
3 ^a	Mounting Visual examination Capacitance Tangent of loss angle Insulation resistance Voltage proof	5.4 5.5 5.6.1 5.6.2 5.6.3 5.6.4	84 + 24 ^f 24	0 ^c 0
3.1	Shear test ^h Rapid change of temperature Climatic sequence	5.8 5.12 5.13	24 24	0 0
3.2	Damp heat, steady state	5.14	24	0
3.3	Endurance	5.15	36	0
3.4	Accelerated damp heat, steady state ^b	5.19	24 ^f	0
4	Temperature coefficient and temperature ~~cycle~~ cyclic drift	5.7	12	0

- a The values of these measurements serve as initial measurements for the tests of Group 3.
- b If required in the detail specification.
- c The capacitors found non-conforming items after mounting shall not be taken into account when calculating the permissible non-conforming for the following tests. They shall be replaced by spare capacitors.
- d Not applicable to capacitors, which, in accordance with their detail specification, shall only be mounted on alumina substrates.
- e Capacitance/voltage combinations, see 8.4.2.
- f Additional capacitors, if Group 3.4 is tested.
- g Applicable to capacitors with strip terminations.
- h Not applicable to capacitors with strip terminations.

Table 20 – Tests schedule for qualification approval

Subclause number and test (see NOTE 1)	D or ND	Conditions of test (see NOTE 1)	Number of specimens (#) and number of non-conforming items (c)	Performance requirements (see NOTE 1)
GROUP 0 ~~8.5 Visual examination~~ ~~8.5 Dimension (detail)~~ ~~8.6.1 Capacitance~~ ~~8.6.2 Tangent of loss angle (tan δ)~~ ~~8.6.3 Insulation resistance~~ ~~8.6.4 Voltage proof~~	ND	~~Frequency: ... Hz~~ ~~Measuring voltage: ... V RMS~~ ~~Frequency and Measuring voltage same as in 8.6.1~~ ~~See detail specification for the method~~ ~~See detail specification for the method~~	See Table 4	~~As in 8.5.3~~ ~~Legible marking and as specified in the detail specification~~ ~~See the detail specification~~ ~~Within specified tolerance~~ ~~As in 8.6.2.3~~ ~~As in 8.6.3.4~~ ~~No breakdown or flashover~~
GROUP 1A ~~8.16 Robustness of termination (if applicable)~~ ~~8.10.2 Initial measurement~~ ~~8.10 Resistance to soldering heat~~ ~~8.10.5 Final measurement~~ ~~8.17 Component solvent resistance (if required)~~	D	~~Test Ua₁, Force: 2,5 N~~ ~~Test Ub, Method 1, Force: 2,5 N~~ ~~Number of bends: 4~~ ~~Visual examination~~ ~~Capacitance~~ ~~See detail specification for the method~~ ~~Recovery: 6 h to 24 h~~ ~~Visual examination~~ ~~Capacitance~~ ~~Solvent: ...~~ ~~Solvent temperature: ...~~ ~~Method 2~~ ~~Recovery: ...~~	See Table 4	~~No visible damage~~ ~~As in 8.10.5~~ ~~As in 8.10.5~~ ~~See detail specification~~

Subclause number and test (see NOTE 1)	D or ND	Conditions of test (see NOTE 1)	Number of specimens (#) and number of non-conforming items (c)	Performance requirements (see NOTE 1)
8.13.4 — Damp heat, cyclic, test Db, first cycle 8.13.5 — Cold 8.13.6 — Damp heat, cyclic, test Db, remaining cycles		Temperature: lower category temperature Duration: 2 h Visual examination Recovery: 6 h to 24 h		No visible damage
8.13.7 — Final measurements		Visual examination Capacitance Tangent of loss angle Insulation resistance		No visible damage Legible marking As in 8.13.7 As in 8.13.7 As in 8.13.7
GROUP 3.2 8.14 — Damp heat, steady state 8.14.2 Initial measurement 8.14.5 Final measurements	D	Capacitance Recovery: 6 h to 24 h Visual examination Capacitance Tangent of loss angle Insulation resistance	See Table 4	No visible damage Legible marking As in 8.14.5 As in 8.14.5 As in 8.14.5
GROUP 3.3 8.15 — Endurance 8.15.2 Initial measurement 8.15.5 Final measurements	D	Duration: ... h Temperature: ... °C Voltage: ... V Capacitance Recovery: 6 h to 24 h Visual examination Capacitance Tangent of loss angle Insulation resistance	See Table 4	No visible damage Legible marking As in 8.15.5 As in 8.15.5 As in 8.15.5
Group 3.4 8.19 — Accelerated damp heat, steady state (if required) 8.19.2 Initial measurement 8.19.5 Final measurement	D	Duration: ... h Temperature: $(85 \pm 2)^\circ\text{C}$ Humidity: $(85 \pm 3)\% \text{ RH}$ Insulation resistance Recovery: 6 h to 24 h Insulation resistance	See Table 4	As in 8.19.2 As in 8.19.5
Group 4	ND		See Table 4	

Subclause number and test (see NOTE 1)	D or ND	Conditions of test (see NOTE 1)	Number of specimens (n) and number of non-conforming items (c)	Performance requirements (see NOTE 1)
8.7 Temperature coefficient and cyclic drift		Preliminary drying: 16 h to 24 h		As in 8.7.4
NOTE 1 Subclause numbers of test and performance requirements refer to Clause 8.				
NOTE 2 In this table: D – destructive, ND – non-destructive.				
^a This test may be carried out on capacitors mounted on a substrate. ^b When different substrate materials are used for the individual subgroup, the detail specification shall indicate which substrate material is used in each subgroup.				

Test (see NOTE 1)	Conditions of test (see NOTE 1)	D or ND (see NOTE 2)	n (see Table 19)	c (see Table 19)	Performance requirements (see NOTE 1)
GROUP 0		ND	See Table 19		
5.5 Visual examination					As in 5.5.3
5.5 Dimension (detail)					Legible marking and as specified in the detail specification See the detail specification
5.6.1 Capacitance	Frequency: ... Hz Measuring voltage: V RMS				Within specified tolerance
5.6.2 Tangent of loss angle (tan δ)	Frequency and Measuring voltage same as in 5.6.1				As in 5.6.2.3
5.6.3 Insulation resistance	See detail specification for the method				As in 5.6.3.4
5.6.4 Voltage proof	See detail specification for the method				No breakdown or flashover
GROUP 1A		D	See Table 19		
5.16 Robustness of termination (if applicable)	Test Ua ₁ , Force: 2,5 N Test Ub, Method 1, Force: 2,5 N Number of bends: 1				No visible damage
5.10.2 Initial measurement	Visual examination Capacitance				
5.10 Resistance to soldering heat	See detail specification for the method Recovery: 6 h to 24 h				
5.10.5 Final inspection, measurements and requirements	Visual examination Capacitance				As in 5.10.5 As in 5.10.5
5.17 Component solvent resistance (if required)	Solvent: ... Solvent temperature: Method 2 Recovery: ...				See detail specification
GROUP 1B		D	See Table 19		

Test (see NOTE 1)		Conditions of test (see NOTE 1)	D or ND (see NOTE 2)	n c (see Table 19)	Performance requirements (see NOTE 1)
5.11	Solderability	See detail specification for the method			
5.11.4	Final inspection, measurements and requirements	Visual examination			As in 5.11.4
5.18	Solvent resistance of the marking ^a (if required)	Solvent: ... Solvent temperature: ... Method 1 Rubbing material: cotton wool Recovery: ...			Legible marking
GROUP 2			D	See Table 19	
5.9	Substrate bending test	Deflection: ... Number of bends: ...			See detail specification
5.9.2	Initial measurement	Capacitance			
5.9.3	Final inspection	Capacitance (with printed board in bent position) Visual examination			$ \Delta C/C \leq 5 \%$ No visible damage
GROUP 3			D	See Table 19	
5.4	Mounting	Substrate material: ... ^b Visual examination Capacitance Tangent of loss angle Insulation resistance Voltage proof			As in 5.5.3 Within specified tolerance As in 5.6.2.3 As in 5.6.3.4 No breakdown or flashover
GROUP 3.1			D	See Table 19	
5.8	Shear test	Visual examination			No visible damage
5.12.2	Initial measurement	Capacitance			
5.12	Rapid change of temperature	T_A = Lower category temperature T_B = Upper category temperature Five cycles Duration t_1 = 30 min Recovery: 6 h to 24 h			
5.12.5	Final inspection, measurements and requirements	Visual examination Capacitance			No visible damage $\Delta C/C$: as in 5.12.5
5.13	Climatic sequence				
5.13.2	Initial Measurement	Capacitance			
5.13.3	Dry heat	Temperature: upper category temperature Duration: 16 h			
5.13.4	Damp heat, cyclic, test Db, first cycle				
5.13.5	Cold	Temperature: lower category temperature Duration: 2 h			

Test (see NOTE 1)	Conditions of test (see NOTE 1)	D or ND (see NOTE 2)	n	c	Performance requirements (see NOTE 1)
5.13.6 Damp heat, cyclic, test Db, remaining cycles 5.13.7 Final inspection, measurements and requirements	Visual examination Recovery: 6 h to 24 h Visual examination Capacitance Tangent of loss angle Insulation resistance				No visible damage No visible damage Legible marking $\Delta C/C$: as in 5.13.7 As in 5.13.7 As in 5.13.7
GROUP 3.2 5.14 Damp heat, steady state 5.14.2 Initial measurement 5.14.5 Final inspection, measurements and requirements	Capacitance Recovery: 6 h to 24 h Visual examination Capacitance Tangent of loss angle Insulation resistance	D	See Table 19		No visible damage Legible marking $\Delta C/C$: as in 5.14.5 As in 5.14.5 As in 5.14.5
GROUP 3.3 5.15 Endurance 5.15.2 Initial measurement 5.15.5 Final inspection, measurements and requirements	Duration: ... h Temperature: ... °C Voltage: ... V Capacitance Recovery: 6 h to 24 h Visual examination Capacitance Tangent of loss angle Insulation resistance	D	See Table 19		No visible damage Legible marking $\Delta C/C$: as in 5.15.5 As in 5.15.5 As in 5.15.5
GROUP 3.4 5.19 Accelerated damp heat, steady state (if required) 5.19.2 Initial measurement 5.19.5 Final measurement	Duration: ... h Temperature: (85 ± 2) °C Humidity: (85 ± 3) % RH Insulation resistance Recovery: 6 h to 24 h Insulation resistance	D	See Table 19		As in 5.19.2 As in 5.19.5
GROUP 4 5.7 Temperature coefficient (a) and temperature cyclic drift	Primary drying: 16 h to 24 h	ND	See Table 19		$\Delta C/C$: as in 5.7.4

Test (see NOTE 1)	Conditions of test (see NOTE 1)	D or ND (see NOTE 2)	n (see Table 19)	c	Performance requirements (see NOTE 1)
NOTE 1 Subclause numbers of test and performance requirements refer to Clause 5.					
NOTE 2 In this table: D = destructive, ND= non-destructive.					
^a This test may be carried out on capacitors mounted on a substrate.					
^b When different substrate materials are used for the individual subgroup, the detail specification shall indicate which substrate material is used in each subgroup.					

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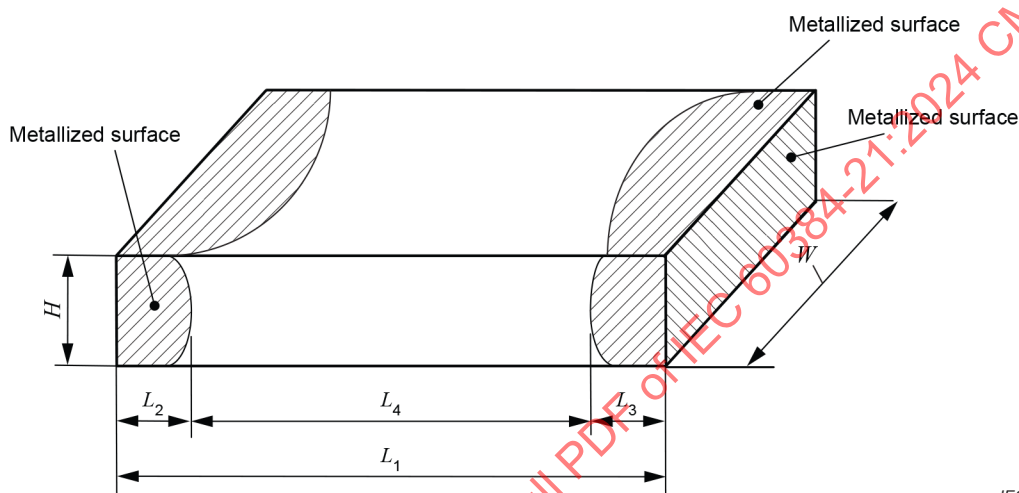
Annex A

(normative)

Guidance for the specification and coding of dimensions of fixed surface mount multilayer capacitors of ceramic dielectric, Class 1

The principles given in Figure A.1 ~~should~~ shall be considered in the dimensioning of the capacitors.

Dimensions are specified in Table A.1.



Dimension W should not exceed dimension L_1 .

Dimension H should not exceed dimension W .

If necessary, the thickness of tinning should be specified.

Figure A.1 – Dimensions

Table A.1 – Dimensions

Code	Length L_1	Width W	$L_2; L_3$ Minimum	L_4 Minimum
0201M	$0,25 \pm 0,013$	$0,125 \pm 0,013$	0,04	0,06
0402M	$0,4 \pm 0,02$	$0,2 \pm 0,02$	0,05	0,1
0603M	$0,6 \pm 0,03$	$0,3 \pm 0,03$	0,1	0,2
1005M	$1,0 \pm 0,05$	$0,5 \pm 0,05$	0,1	0,3
1608M	$1,6 \pm 0,1$	$0,8 \pm 0,1$	0,2	0,5
2012M	$2,0 \pm 0,1$	$1,25 \pm 0,1$	0,2	0,7
3216M	$3,2 \pm 0,2$	$1,6 \pm 0,15$	0,3	1,4
3225M	$3,2 \pm 0,2$	$2,5 \pm 0,2$	0,3	1,4
4532M	$4,5 \pm 0,3$	$3,2 \pm 0,2$	0,3	2,0
5750M	$5,7 \pm 0,4$	$5,0 \pm 0,4$	0,3	2,5

NOTE Dimension in millimetres.

Other case sizes and dimensions may be specified in the detail specification.

Annex B

(~~informative~~ normative) 4

Combination of temperature coefficients and tolerances for the reference temperature of 25 °C

~~The temperature coefficient of capacitance for the reference temperature of 25 °C has often been used due to marketing needs and because of their actual performance.~~

Temperature coefficients of capacitance, tolerances and related codes are shown in Table B.1.

Table B.1 – Combination of temperature coefficients and tolerances for the reference temperature of 25 °C

Code of temperature coefficient and tolerance	Temperature coefficient and the tolerance		Permissible relative variation in capacitance in parts per 1 000 between 25 °C and given temperature							
			Lower category temperature				Upper category temperature			
	α 10 ⁻⁶ /K	Tolerance 10 ⁻⁶ /K	-55 °C	-40 °C	-25 °C	-10 °C	+70 °C	+85 °C	+100 °C	+125 °C
C0G	0	± 30	-2,40/ 5,81	-1,95/ 4,72	-1,50/ 3,63	-1,05/ 2,54	-1,35/ 1,35	-1,80/ 1,80	-2,25/ 2,25	-3,00/ 3,00
U2J	-750	±120	50,4/ 87,8	41,0/ 71,3	31,5 /54,9	22,1/ 38,4	-39,2/ -28,4	-52,2/ -37,8	-65,3/ -47,3	-87,0/ -63,0

α = nominal temperature coefficient

NOTE C0G and U2J (Code of temperature coefficient and tolerance), see EIA-198-1-F.

Annex C (normative)

Quality conformance inspection

C.1 Formation of inspection lots

C.1.1 Groups A and B inspection

These tests shall be carried out on a lot-by-lot basis.

A manufacturer may aggregate the current production into inspection lots subject to the following safeguards.

- a) The inspection lot shall consist of structurally similar capacitors (see 8.2).
- b) The sample tested shall be representative of the values and the dimensions contained in the inspection lot:
 - in relation to their number;
 - with a minimum of five of any one value.
- c) If there are fewer than five of any one value in the sample, the basis for the drawing of samples shall be agreed between the manufacturer and the certification body (CB).

C.1.2 Group C inspection

These tests shall be carried out on a periodic basis.

Samples shall be representative of the current production of the specified periods and shall be divided into small, medium and large sizes. In order to cover the range of approvals in any period, one voltage shall be tested from each group of sizes. In subsequent periods, other sizes and/or voltage ratings in production shall be tested with the aim of covering the whole range.

C.2 Test schedule

The schedule for the lot-by-lot and periodic tests for quality conformance inspection is given in ~~Clause 2 of the blank detail specification~~ Table C.3 and Table C.4.

C.3 Delayed delivery

When, in accordance with the procedures of IEC 60384-1:2016/2021, Q.1.7, re-inspection shall be made, solderability and capacitance shall be checked as specified in Groups A and B inspection.

C.4 Assessment levels

The assessment level(s) given in ~~the blank detail specification~~ Table C.3 and Table C.4 should be selected from Table C.1 and Table C.2.

Table C.1 – Lot by lot inspection

Inspection subgroup ^d	EZ		
	IL ^a	<i>n</i> ^a	<i>c</i> ^a
A0	100 % ^b		
A1	S-4	<i>c</i>	0
A2	S-3	<i>c</i>	0
B1	S-3	<i>c</i>	0
B2	S-2	<i>c</i>	0
^a IL = inspection level <i>n</i> = sample size <i>c</i> = permissible number of non-conforming items ^b The inspection shall be performed after removal of nonconforming items by 100 % testing during the manufacturing process. Whether the lot was accepted or not, all samples for sampling inspection shall be inspected in order to monitor outgoing quality level by nonconforming items per million ($\times 10^{-6}$). The sampling level shall be established by the manufacturer, ~~preferably~~ and should be in accordance with IEC 61193-2:2007, Annex A. In the case where one or more nonconforming items occur in a sample, this lot shall be rejected, but all non-conforming items shall be counted for the calculation of quality level values. Outgoing quality level by non-conforming items per million ($\times 10^{-6}$) values shall be calculated by accumulating inspection data in accordance with the method given in IEC 61193-2:2007, 6.2. ^c Number to be tested: Sample size shall be determined in accordance with IEC 61193-2:2007, 4.3.2. ^d The content of the inspection subgroup is described in ~~Clause 2 of the relevant blank detail specification~~ Table C.3.			

Table C.2 – Periodic ~~tests~~ inspection

Inspection subgroup ^b	EZ		
	<i>p</i> ^a	<i>n</i> ^a	<i>c</i> ^a
C1	3	12	0
C2	3	12	0
C3.1	6	27	0
C3.2	6	15	0
C3.3	3	15	0
C3.4 ^c	6	15	0
C4	6	9	0
^a <i>p</i> = periodicity in months <i>n</i> = sample size <i>c</i> = permissible number of non-conforming items ^b The content of the inspection subgroup is described in ~~Clause 2 of the relevant blank details specification~~ Table C.4. ^c If required.			

C.5 Test schedule for quality conformance inspection 5

For quality conformance inspection, the test schedules given in Table C.3 and Table C.4 include sampling, periodicity, severities and requirements. The formation of inspection lots is given in Clause C.1.

Table C.3 – Test schedule for quality conformance inspection (lot by lot)

Test ^a		Lot-by-lot tests Conditions of test ^b		D ^c or ND	IL ^c	c ^c	Performance requirements
Group A0 [100 % tests]				ND			
5.6.1	Capacitance	Frequency: ... Hz Measuring voltage: ... V r.m.s			100 % ^d		Within specified tolerance
5.6.2	Tangent of loss angle (tan δ)	Frequency and measuring voltage same as in 5.6.1					As in 5.6.2
5.6.3	Insulation resistance	See detail specification for the method					As in 5.6.3.4
5.6.4	Voltage proof	See detail specification for the method					No breakdown or flashover
Group A1 [Sampling tests]				ND			
5.5.2	Visual examination				S-4 ^e	0	As in 5.5.2 Legible marking and as specified in the detail specification
Group A2 [Sampling tests]				ND			
4.2.6	Dimension ^f				S-3 ^e	0	See the detail specification
Group B1 [Special tests]				D			
5.11	Solderability	See detail specification for the method			S-3 ^e		
5.11.4	Final inspection, measurements and requirements	Visual examination					As in 5.11.4
5.18	Solvent resistance of the marking (if required) ^g	Solvent: ... Solvent temperature: ... Method 1 Rubbing material: cotton wool Recovery: ...					Legible marking
Group B2 [Special tests]				ND			
5.7	Temperature coefficient (α) and cyclic drift ^h				S-2 ^e	0	$\Delta C/C$: As in 5.7.3

^a Applicable tests, test conditions, requirements and clause numbers as selected from this document.

^b The information given in Table C.3 shall provide a suitable overview of the most relevant parameters of each test, however shall not take precedence over any more detailed specification given in a respective clause of this specification or in a cited normative reference.

^c Refer to Table C.1 for lists of symbols and of abbreviated terms.

^d After 100 % measurement and removal of nonconforming items, a re-inspection shall be performed in order to monitor the outgoing quality level, in accordance with the detail specification. A lot shall be rejected if one or more non-conforming items occur in a sample during re-inspection.

^e Inspection levels are selected from IEC 611932-2:2007.

^f This test may be replaced by in-production testing if the manufacturer installs statistical process control (SPC) on dimensional measurements or other mechanisms to avoid parts exceeding the limits.

^g This test may be carried out on capacitors mounted on a substrate.

^h This subgroup may be omitted if a corresponding test is carried out on each manufacturing batch of dielectric material.

Table C.4 – Test schedule for quality conformance inspection (Periodic test)

Periodic tests							
Test ^a		Conditions of test ^b	D ^c or ND	p ^c	n ^c	c ^c	Performance requirements
Group C1 ^h			D	3	12	0 ^d	No visible damage
5.16	Robustness of Termination (only for capacitors with strip terminations)	Test Ua, Force: 2,5 N Test Ub, Method 1, Force: 2,5 N Number of bends: 1 Visual examination					
5.10.2	Initial measurement	Capacitance					
5.10	Resistance to soldering heat	See detail specification for the method Recovery: 6 h to 24 h					
5.10.5	Final inspection, measurements and requirements	Visual examination Capacitance					
5.17	Component solvent resistance (if required)	Solvent: ... Solvent temperature: ... Method 2 Recovery: ...					As in 5.10.5 As in 5.10.5 See detail specification
Group C2 ^h			D	3	12	0 ^d	See detail specification $\Delta C/C \leq 5\%$ No visible damage
5.9	Substrate bending test ^e	Deflection: ... Number of bends: ...					
5.9.2	Initial measurement	Capacitance					
5.9.3	Final inspection	Capacitance (with printed board in bent position) Visual examination					
Group C3 ^h			D				As in 5.5.3 Within specified tolerance As in 5.6.2.3 As in 5.6.3.4 No breakdown or flashover
5.4	Mounting ^f	Substrate material: ...					
		Visual examination					
		Capacitance					
		Tangent of loss angle					
		Insulation resistance					
		Voltage proof					

Periodic tests							
Test ^a		Conditions of test ^b	D ^c or ND	p ^c	n ^c	c ^c	Performance requirements
Group C3.1 ^h			D	6	27	0 ^d	
5.8	Shear test ^g	Visual inspection					No visible damage
5.12.2	Initial measurement	Capacitance					
5.12	Rapid change of temperature	T_A = Lower category temperature T_B = Upper category temperature: five cycles Duration t_1 = 30 min Recovery: 6 h to 24 h					
5.12.5	Final inspections, measurements and requirements	Visual examination					
		Capacitance					$\Delta C/C$: As in 5.12.5
5.13.2	Initial measurement	Capacitance					
5.13.3	Dry heat	Temperature: upper category temperature Duration: 16 h					
5.13.4	Damp heat, cyclic, test Db, first cycle						
5.13.5	Cold	Temperature: lower category temperature Duration: 2 h Visual inspection					
5.13.6	Damp heat, cyclic, test Db, remaining cycles	Recovery: 6 h to 24 h					No visible damage, Legible marking $\Delta C/C$: As in 5.13.7 As in 5.13.7 As in 5.13.7
5.13.7	Final inspections, measurements and requirements	Visual examination					
		Capacitance					
		Tangent of loss angle					
		Insulation resistance					
Group C3.2 ^h			D	6	15	0 ^d	
5.14	Damp heat, steady state						
5.14.2	Initial measurement	Capacitance Recovery: 6 h to 24 h					No visible damage, Legible marking $\Delta C/C$: As in 5.14.5 As in 5.14.5 As in 5.14.5
5.14.5	Final inspections, measurements and requirements	Visual examination					
		Capacitance Tangent of loss angle Insulation resistance					

Periodic tests							
Test ^a		Conditions of test ^b	D ^c or ND	p ^c	n ^c	c ^c	Performance requirements
Group C3.3 ^h			D				No visible damage. Legible marking $\Delta C/C$: As in 5.15.5 As in 5.15.5 As in 5.15.5
5.15	Endurance	Duration: ...h Temperature: ...°C Voltage: ...V		3	15	0 ^d	
5.15.2	Initial measurement	Capacitance Recovery: 6 h to 24 h					
5.15.5	Final inspections, measurements and requirements	Visual examination Capacitance Tangent of loss angle Insulation resistance					
Group C3.4 ^h			D				As in 5.19.2 As in 5.19.5
5.19	Accelerated damp heat, steady state (if required)	Duration: ... h Temperature: (85 ± 2) °C Humidity: (85 ± 3) %		6	15	0 ^d	
5.19.2	Initial measurement	Insulation resistance Recovery: 6 h to 24 h					
5.19.5	Final measurements	Insulation resistance					As in 5.19.5
Group C4 ^h			ND				$\Delta C/C$: As in 5.7.3
5.7	Temperature coefficient (α) and cyclic drift	Preliminary drying: 16 h to 24 h		6	9	0 ^d	

^a Applicable tests, test conditions, requirements and clause numbers as selected from this document.

^b The information given in Table C.4 shall provide a suitable overview of the most relevant parameters of each test, however shall not take precedence over any more detailed specification given in a respective clause of this specification or in a cited normative reference.

^c Refer to Table C.2 for lists of symbols and of abbreviated terms.

^d If one non-conforming item is obtained, all the tests of the subgroup shall be repeated on a new sample and then no further non-conforming items are permitted. Release of product may continue during repeat testing.

^e Not applicable to capacitors, which, in accordance with the detail specification, shall only be mounted on alumina substrates.

^f The capacitors found non-conformances after mounting shall not be taken into account when calculating the non-conformances for the following tests. They shall be replaced by spare capacitors.

^g Not applicable to capacitors with strip terminations

^h All tests of the sub-group shall be repeated if one or more nonconforming item is obtained. No non-conforming items are permitted in the repeat testing. Release of products may continue during repeat testing.

Annex X (informative)

Cross-reference for reference to IEC 60384-21:~~2011~~2019

The drafting of this document has resulted in a new structure. Table X.1 indicates the new clause and subclause numbers with respect to IEC 60384-21:~~2011~~2019.

Table X.1 – Reference to IEC 60384-21 for clause/~~subclause~~annex

~~IEC 60384-21:2011~~ 2 nd -edition Clause/Subclause	~~IEC 60384-21:20xx~~ 3 rd -edition Clause/Subclause	Notes
~~4~~ ~~4.1~~ ~~4.2~~	4	Scope and Object are merged into one in accordance with the ISO/IEC Directives Part 2
~~4.3~~	2	In accordance with ISO/IEC Directives Part 2
~~4.4~~	4	In accordance with the change of clause numbers
~~4.5~~	3	In accordance with ISO/IEC Directives Part 2
~~4.6~~	5	In accordance with the change of clause numbers
~~2~~	6	In accordance with the change of clause numbers
~~3~~	7	In accordance with the change of clause numbers
~~4~~	8	In accordance with the change of clause numbers

IEC 60384-21:2019 3 rd edition Clause/Annex	IEC 60384-21:2024 4 th edition Clause/Annex	Notes
1	1	No change
2	2	No change
3	3	No change
4	7	In accordance with the change of clause numbers
5	6	In accordance with the change of clause numbers
6	4	In accordance with the change of clause numbers
7.1 to 7.4	8.1 to 8.4	In accordance with the change of clause numbers
7.5.1 to 7.5.4	C.1 to C.4	In accordance with the change of clause numbers
8	5	In accordance with the change of clause numbers
Annex A	Annex A	No change
Annex B	Annex B	Changed from informative to normative
—	C.5	Newly added. Modified from IEC 60384-21-1:2004, Clause 2
Annex X	Annex X	No change

Table X.2 indicates the new figure and table numbers with respect to IEC 60384-21:~~2011~~2019.

Table X.2 – Reference to IEC 60384-21 for figure/table

~~IEC 60384-21:2014 2nd edition~~ ~~Figure/Table~~	~~IEC 60384-21:20xx 3rd edition~~ ~~Figure/Table~~	~~Notes~~
~~Table 6a~~	~~Table 6~~	~~In accordance with the ISO/IEC directives, Part 2 and the change of table numbers~~
~~Table 6b~~	~~Table 7~~	
~~Table 7 to Table 21~~	~~Table 8 to Table 22~~	~~In accordance with the change of table numbers~~
~~For the figure numbers, there was no change.~~		

IEC 60384-21:2019 3rd edition Figure/Table	IEC 60384-21:20xx 4th edition Figure/Table	Notes
Table 1 to Table 3	Table 1 to Table 3	No change
Table 4 and table 5	Table 19 and Table 20	In accordance with the change of table numbers
Table 6 and Table 7	Table C.1 and Table C.2	In accordance with the change of table numbers
-	Table C.3 and Table C.4	Newly added. Modified from IEC 60384-21-1:2004, Table 4
Table 8 to Table 22	Table 4 to Table 18	In accordance with the change of table numbers
Table A.1	Table A.1	No change
Table B.1	Table B.1	Updated
Table X.1 and Table X.2	Table X.1 and Table X.2	No change
For the figure numbers, there was no change.		

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Bibliography

IEC 60063, *Preferred number series for resistors and capacitors*

IEC 60068-1:2013, *Environmental testing – Part 1: General and guidance*

IEC 60384-14, *Fixed capacitors for use in electronic equipment – Part 14: Sectional specification: Fixed capacitors for electromagnetic interference suppression and connection to the supply mains*

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IEC 60417, *Graphical symbols for use on equipment* (available at <http://www.graphical-symbols.info>)

IECQ on-line certificate system: available at www.iecq.org

ISO 3:1973, *Preferred numbers – Series of preferred numbers*

EIA-198-1-F, *Ceramic Dielectric Capacitors Classes I, II, III and IV – Part I: Characteristics and Requirements*

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List of comments

- 1 This modification in scope clarifies, that deviations to the requirements set forth in this standard are allowed, but only if they are more severe. For example, capacitors which are specified to withstand a substrate bending test with 5 mm bending depth comply to this standard, which requires 1 mm to 3 mm bending depth as test severity.
- 2 This is the most important change in this new edition. The addition of the reference temperature 25 °C became necessary to include the temperature coefficients COG and U2J, which are specified in EIA-198-1 and are very common in the market. With this extension, the requirements to those capacitors are now precisely given in this standard and included in Clause 5. See Annex B for details.
- 3 With this change temperature coefficients specified in EIA-198-1 are included.
- 4 With this change of Annex B from “informative” into “normative” capacitors specified in accordance to EIA-198-1 are formally included in this standard.
- 5 Clause C.5 has been added to Annex C to include the test schedule for quality conformance inspection. This previously has been the content of the blank detail specification IEC 60384-21-1, which is intended to be withdrawn. Now this standard contains the complete information for the qualification of the capacitors.

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INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Fixed capacitors for use in electronic equipment –
Part 21: Sectional specification – Fixed surface mount multilayer capacitors of
ceramic dielectric, Class 1**

**Condensateurs fixes utilisés dans les équipements électroniques –
Partie 21: Spécification intermédiaire – Condensateurs multicouches fixes à
diélectriques en céramique pour montage en surface, de Classe 1**

CONTENTS

FOREWORD	6
1 Scope	8
2 Normative references	8
3 Terms and definitions	8
4 Preferred ratings and characteristics	9
4.1 Preferred characteristics	9
4.2 Preferred values of ratings	10
4.2.1 Rated temperature (T_R)	10
4.2.2 Rated voltage (U_R)	10
4.2.3 Category voltage (U_C)	10
4.2.4 Preferred values of nominal capacitance and associated tolerance values	10
4.2.5 Temperature coefficient (α)	11
4.2.6 Dimensions	13
5 Test and measurement procedures	13
5.1 General	13
5.2 Preliminary drying	13
5.3 Measuring conditions	13
5.4 Mounting	13
5.5 Visual examination and check of dimensions	13
5.5.1 General	13
5.5.2 Visual examination	13
5.5.3 Requirements	13
5.6 Electrical tests	15
5.6.1 Capacitance	15
5.6.2 Tangent of loss angle ($\tan \delta$)	15
5.6.3 Insulation resistance	16
5.6.4 Voltage proof	17
5.7 Temperature coefficient (α) and temperature cyclic drift	17
5.7.1 General	17
5.7.2 Preliminary drying	18
5.7.3 Measuring conditions	18
5.7.4 Requirements	18
5.8 Shear test	18
5.9 Substrate bending test	18
5.9.1 General	18
5.9.2 Initial measurement	18
5.9.3 Final inspection	19
5.10 Resistance to soldering heat	19
5.10.1 General	19
5.10.2 Initial measurement	19
5.10.3 Test conditions	19
5.10.4 Recovery	20
5.10.5 Final inspection, measurements and requirements	20
5.11 Solderability	21
5.11.1 General	21

5.11.2	Test conditions	21
5.11.3	Recovery	21
5.11.4	Final inspection, measurements and requirements.....	21
5.12	Rapid change of temperature	22
5.12.1	General	22
5.12.2	Initial measurement	22
5.12.3	Number of cycles	22
5.12.4	Recovery	22
5.12.5	Final inspection, measurements and requirements.....	22
5.13	Climatic sequence.....	22
5.13.1	General	22
5.13.2	Initial measurement	22
5.13.3	Dry heat	23
5.13.4	Damp heat, cyclic, Test Db, first cycle	23
5.13.5	Cold.....	23
5.13.6	Damp heat, cyclic, Test Db, remaining cycles	23
5.13.7	Final inspection, measurements and requirements.....	23
5.14	Damp heat, steady state	24
5.14.1	General	24
5.14.2	Initial measurement	24
5.14.3	Test conditions	24
5.14.4	Recovery	24
5.14.5	Final inspection, measurements and requirements.....	24
5.15	Endurance	25
5.15.1	General	25
5.15.2	Initial measurement	25
5.15.3	Test conditions	25
5.15.4	Recovery	26
5.15.5	Final inspection, measurements and requirements.....	26
5.16	Robustness of terminations (only for capacitors with strip termination).....	26
5.16.1	General	26
5.16.2	Test conditions	26
5.16.3	Final inspection and requirements	27
5.17	Component solvent resistance (if required)	27
5.18	Solvent resistance of the marking (if required)	27
5.19	Accelerated damp heat, steady state (if required)	27
5.19.1	General	27
5.19.2	Initial measurement	27
5.19.3	Conditioning	27
5.19.4	Recovery	28
5.19.5	Final measurements	28
6	Marking	28
6.1	General.....	28
6.2	Information for marking	28
6.3	Marking on the body	28
6.4	Requirements for marking	28
6.5	Marking of the packaging	29
6.6	Additional marking	29
7	Information to be given in a detail specification.....	29

7.1	General.....	29
7.2	Outline drawing and dimensions	29
7.3	Mounting.....	29
7.4	Rating and characteristics.....	29
7.4.1	General	29
7.4.2	Nominal capacitance range.....	29
7.4.3	Particular characteristics	30
7.4.4	Soldering	30
7.5	Marking.....	30
8	Quality assessment procedures	30
8.1	Primary stage of manufacture	30
8.2	Structurally similar components	30
8.3	Certified records of released lots	30
8.4	Qualification approval	30
8.4.1	General	30
8.4.2	Qualification approval on the basis of the fixed sample size procedures	30
8.4.3	Tests	31
Annex A (normative) Guidance for the specification and coding of dimensions of fixed surface mount multilayer capacitors of ceramic dielectric, Class 1		36
Annex B (normative) Combination of temperature coefficients and tolerances for the reference temperature of 25 °C.....		37
Annex C (normative) Quality conformance inspection.....		38
C.1	Formation of inspection lots	38
C.1.1	Groups A and B inspection	38
C.1.2	Group C inspection	38
C.2	Test schedule	38
C.3	Delayed delivery	38
C.4	Assessment levels	38
C.5	Test schedule for quality conformance inspection	39
Annex X (informative) Cross-reference for reference to IEC 60384-21:2019.....		44
Bibliography.....		45
Figure 1 – Fault: crack or fissure.....		14
Figure 2 – Fault: crack or fissure.....		14
Figure 3 – Separation or delamination		14
Figure 4 – Exposed electrodes.....		14
Figure 5 – Principal faces		15
Figure 6 – Reflow temperature profile		20
Figure A.1 – Dimensions		36
Table 1 – Preferred tolerances on nominal capacitance		10
Table 2 – Nominal temperature coefficient and tolerance (for reference temperature 20 °C)		11
Table 3 – Combination of temperature coefficient and tolerance		12
Table 4 – Tangent of loss angle limits		16
Table 5 – Test voltages.....		17

Table 6 – Temperature cyclic drift limits	18
Table 7 – Reflow temperature profiles for Sn-Ag-Cu alloy	20
Table 8 – Maximum capacitance change	20
Table 9 – Maximum capacitance change	22
Table 10 – Number of damp heat cycles	23
Table 11 – Final inspection, measurements and requirements	23
Table 12 – Test conditions for damp heat, steady state	24
Table 13 – Final inspection, measurements and requirements	25
Table 14 – Endurance test conditions ($U_C = U_R$)	25
Table 15 – Endurance test conditions ($U_C \neq U_R$)	26
Table 16 – Final inspection, measurements and requirements	26
Table 17 – Initial requirements	27
Table 18 – Conditioning	28
Table 19 – Fixed sample size test plan for qualification approval Assessment level EZ	32
Table 20 – Tests schedule for qualification approval	33
Table A.1 – Dimensions	36
Table B.1 – Combination of temperature coefficients and tolerances for the reference temperature of 25 °C	37
Table C.1 – Lot by lot inspection	39
Table C.2 – Periodic inspection	39
Table C.3 – Test schedule for quality conformance inspection (lot by lot)	40
Table C.4 – Test schedule for quality conformance inspection (Periodic test)	41
Table X.1 – Reference to IEC 60384-21 for clause/annex	44
Table X.2 – Reference to IEC 60384-21 for figure/table	44

INTERNATIONAL ELECTROTECHNICAL COMMISSION

FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT –**Part 21: Sectional specification –
Fixed surface mount multilayer capacitors of ceramic dielectric, Class 1****FOREWORD**

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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IEC 60384-21 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment. It is an International Standard.

This fourth edition cancels and replaces the third edition published in 2019. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) the document has been completely restructured to comply with the ISO/IEC Directives, Part 2 and to make it more useable; tables, figures and references have been revised accordingly; Annex X contains all cross-references of changes in clause/subclause numbers;
- b) the terms have been replaced by the letter symbols in Table 3;

- c) code of temperature coefficient and tolerance of C0G, U2J have been added in Table 4, Table 6, Table 8, Table 9, Table 11, Table 13, Table 16 and Annex B;
- d) the requirement in 5.5.2(visual examination) has been repeated in 5.9.3, 5.10.5, 5.11.4, 5.11.4, 5.13.7, 5.14.5 and 5.15.5;
- e) the deflection D in the very robust designs has been added in 5.9.1;
- f) Annex B has been changed informative into normative;
- g) Clause C.5 (Test schedule for quality conformance inspection) has been newly added to withdraw the blank detail specification: IEC 60384-21-1.

The text of this International Standard is based on the following documents:

Draft	Report on voting
40/3119/FDIS	40/3138/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all parts in the IEC 60384 series, published under the general title *Fixed capacitors for use in electronic equipment*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn, or
- revised.

FIXED CAPACITORS FOR USE IN ELECTRONIC EQUIPMENT –

Part 21: Sectional specification – Fixed surface mount multilayer capacitors of ceramic dielectric, Class 1

1 Scope

This part of IEC 60384 is applicable to fixed unencapsulated surface mount multilayer capacitors of ceramic dielectric with a defined temperature coefficient (dielectric Class 1), intended for use in electronic equipment. These capacitors have metallized connecting pads or soldering strips and are intended to be mounted on printed boards, or directly onto substrates for hybrid circuits.

Capacitors for electromagnetic interference suppression are not included but are covered by IEC 60384-14.

The object of this document is to specify preferred ratings and characteristics and to select from IEC 60384-1:2021 the appropriate quality assessment procedures, tests and measuring methods and to give general performance requirements for this type of capacitor. Test severities and requirements specified in detail specifications referring to this document provide specific test severities and requirements of an equal or higher performance level. Further information on the conception of generic, sectional and detail specifications can be found in the Introduction of IEC 60384-1:2021.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-2-58, *Environmental testing – Part 2-58: Tests – Test Td – Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)*

IEC 60384-1:2021, *Fixed capacitors for use in electronic equipment – Part 1: Generic specification*

IEC 61193-2:2007, *Quality assessment systems – Part 2: Selection and use of sampling plans for inspection of electronic components and packages*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC 60384-1:2021 and the following apply.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- IEC Electropedia: available at <https://www.electropedia.org/>
- ISO Online browsing platform: available at <https://www.iso.org/obp>

3.1

surface mount multilayer capacitor

multilayer capacitor whose small dimensions and nature or shape of terminations make it suitable for surface mounting in hybrid circuits and on printed boards

3.2

capacitor of ceramic dielectric, Class 1

capacitor specially designed and suited for resonant circuit application where low losses and high stability of capacitance are essential or where a precisely defined temperature coefficient is required, for example for compensating temperature effects in the circuit

Note 1 to entry: The ceramic dielectric is defined by its nominal temperature coefficient (α).

3.3

subclass

<Class 1> tolerance on the temperature coefficient for a given nominal temperature coefficient

Note 1 to entry: See Table 2.

Note 2 to entry: The nominal temperature coefficient value and its tolerance refer to the temperature interval from the reference temperature +20 °C or +25 °C to +85 °C, but because in practice TC curves are not strictly linear, it is necessary to define limiting capacitance deviation ($\Delta C/C$) for other temperatures (see Table 3 and Annex B).

3.4

temperature range

ambient temperature range for which the capacitor has been designed to operate continuously

Note 1 to entry: This is given by the lower and upper category temperature. (see Table 3 and Annex B).

3.5

rated temperature

T_R

maximum ambient temperature at which the rated voltage can be continuously applied

3.6

rated voltage

U_R

maximum DC voltage that can be applied continuously to a capacitor at any temperature between the lower category temperature and the rated temperature

Note 1 to entry: The maximum DC voltage is the sum of the DC voltage and peak AC voltage or peak pulse voltage applied to the capacitor.

3.7

category voltage

U_C

maximum voltage that can be applied continuously to a capacitor at its upper category temperature

4 Preferred ratings and characteristics

4.1 Preferred characteristics

Preferred climatic categories only shall be given in the preferred characteristics.

The capacitors covered by this document are classified into climatic categories in accordance with the general rules given in IEC 60068-1:2013, Annex A.

For reference temperature 20 °C or 25 °C, the lower and upper category temperatures and the duration of the damp heat, steady state test shall be chosen from the following:

- lower category temperature: $-55\text{ }^{\circ}\text{C}$, $-40\text{ }^{\circ}\text{C}$, $-25\text{ }^{\circ}\text{C}$, $-10\text{ }^{\circ}\text{C}$ and $+10\text{ }^{\circ}\text{C}$;
- upper category temperature: $+70\text{ }^{\circ}\text{C}$, $+85\text{ }^{\circ}\text{C}$, $+100\text{ }^{\circ}\text{C}$, $+125\text{ }^{\circ}\text{C}$;
- duration of the damp heat, steady state test ($40\text{ }^{\circ}\text{C}$, 93 % RH): 4, 10, 21 and 56 days.

The severities of the cold and dry heat tests are the lower and upper category temperatures respectively.

NOTE The resistance to humidity resulting from the above climatic category is for the capacitors in their unmounted state. The climatic performance of the capacitors after mounting is greatly influenced by the mounting substrate, the mounting method (see 5.4) and the final coating.

4.2 Preferred values of ratings

4.2.1 Rated temperature (T_R)

For capacitors covered by this document, the rated temperature is equal to the upper category temperature, unless the upper category temperature exceeds $125\text{ }^{\circ}\text{C}$.

4.2.2 Rated voltage (U_R)

The preferred values of the rated voltage are the values of the R5 series of ISO 3. If other values are needed, they shall be chosen from the R10 series.

The sum of the DC voltage and the peak AC voltage or the peak-to-peak AC voltage, whichever is the greater, applied to the capacitor shall not exceed the rated voltage.

4.2.3 Category voltage (U_C)

When the rated temperature is defined as the upper category temperature, the category voltage is equal to the rated voltage as defined in IEC 60384-1:2021, 3.5. If the upper category temperature exceeds $125\text{ }^{\circ}\text{C}$, or the rated voltages exceed 500 V, the category voltage shall be given in the detail specification.

4.2.4 Preferred values of nominal capacitance and associated tolerance values

4.2.4.1 Preferred values of nominal capacitance

Nominal capacitance values should be taken from the E6, E12 and E24 series given in IEC 60063.

4.2.4.2 Preferred tolerances on nominal capacitance

See Table 1.

Table 1 – Preferred tolerances on nominal capacitance

Preferred series	Tolerance			
	$C_N \geq 10\text{ pF}$	Letter code	$C_N < 10\text{ pF}$	Letter code
E6	$\pm 20\%$	M	$\pm 2\text{ pF}$	G
E12	$\pm 10\%$	K	$\pm 1\text{ pF}$	F
E24	$\pm 5\%$	J	$\pm 0,5\text{ pF}$	D
	$\pm 2\%$	G	$\pm 0,25\text{ pF}$	C
	$\pm 1\%$	F	$\pm 0,1\text{ pF}$	B

4.2.5 Temperature coefficient (α)

4.2.5.1 Nominal temperature coefficient and tolerance (for reference temperature 20 °C)

Table 2 shows the nominal temperature coefficients for the reference temperature 20 °C, the associated tolerances, expressed in parts per million per Kelvin ($10^{-6}/K$), and the corresponding subclasses and letter codes. The temperature coefficients, tolerances and letter codes for the reference temperature 25 °C are given in Annex B.

The detail specification shall specify for each temperature coefficient the minimum value of capacitance for which the given tolerance of temperature coefficient can be verified, considering the accuracy of the methods of capacitance measurement specified.

For values of capacitance lower than this minimum value:

- the detail specification shall specify a multiplying factor for the tolerance on α , as well as the permissible changes of capacitance at the lower and upper category temperature;
- special methods of measurement can be necessary and, if required, shall be stated in the detail specification.

**Table 2 – Nominal temperature coefficient and tolerance
(for reference temperature 20 °C)**

Nominal temperature coefficient ($10^{-6}/K$)	Tolerance on temperature coefficient ($10^{-6}/K$)	Subclass	Letter code for	
			α	Tolerance
+100	± 30	1B	A	G
0	± 30	1B	C	G
-33	± 30	1B	H	G
-75	± 30	1B	L	G
-150	± 30	1B	P	G
-220	± 30	1B	R	G
-330	± 60	1B	S	H
-470	± 60	1B	T	H
-750	± 120	1B	U	J
-1 000	± 250	1F	Q	K
-1 500	± 250	1F	V	K
$+140 \geq \alpha \geq -1\,000$	^a	1C	SL	-
The nominal temperature coefficients and their tolerances are defined using the capacitance change between the temperatures 20 °C and 85 °C. A capacitor with a temperature coefficient $0 \times 10^{-6}/K$ and a tolerance on temperature coefficient of $\pm 30 \times 10^{-6}/K$ is designated as a CG capacitor (subclass 1B). ^a This temperature coefficient value is not subject to inspection since no limits for relative capacitance variation are specified in Table 3.				

4.2.5.2 Permissible relative variation of capacitance

Table 3 shows for each combination of temperature coefficient and tolerance the permissible relative variation of capacitance expressed in parts per thousand at both the upper and lower category temperatures. Temperature coefficients and tolerances are expressed in parts per million per Kelvin ($10^{-6}/K$). In case of reference temperature 25 °C, see Table B.1 for an explanation of the permissible relative variation of capacitance.

Table 3 – Combination of temperature coefficient and tolerance

		Permissible relative variation in capacitance in parts per 1 000 between 20 °C and a given temperature							
		Lower category temperature				Upper category temperature			
α 10 ⁻⁶ /K	Tolerance 10 ⁻⁶ /K	-55 °C	-40 °C	-25 °C	-10 °C	+70 °C	+85 °C	+100 °C	+125 °C
+100	±30 (G)	-9,75/ -3,71	-7,80/ -2,96	-5,85/ -2,22	-3,90/ -1,48	3,50/ 6,50	4,55/ 8,45	5,60/ 10,4	7,35/ 13,7
0	±30 (G)	-2,25/ 5,45	-1,80/ 4,36	-1,35/ 3,27	-0,90/ 2,18	-1,50/ 1,50	-1,95/ 1,95	-2,40/ 2,40	-3,15/ 3,15
-33	±30 (G)	0,225/ 8,47	0,180/ 6,77	0,135/ 5,08	0,090/ 3,39	-3,15/ -0,15	-4,10/ -0,195	-5,04/ -0,240	-6,62/ -0,32
-75	±30 (G)	3,38/ 12,3	2,70/ 9,85	2,03/ 7,39	1,35/ 4,92	-5,25/ -2,25	-6,83/ -2,93	-8,40/ -3,60	-11,0/ -4,73
-150	±30 (G)	9,00/ 19,2	7,20/ 15,3	5,40/ 11,5	3,60/ 7,67	-9,00/ -6,0	-11,7/ -7,80	-14,4/ -9,60	-18,9/ -12,6
-220	±30 (G)	14,3/ 25,6	11,4/ 20,46	8,55/ 15,3	5,70/ 10,2	-12,5/ -9,50	-16,2/ -12,4	-20,0/ -15,2	-26,3/ -20,0
-330	±60 (H)	20,3/ 38,4	16,2/ 30,7	12,2/ 23,0	8,10/ 15,4	-19,5/ -13,5	-25,4/ -17,6	-31,2/ -21,6	-41,0/ -28,4
-470	±60 (H)	30,8/ 51,2	24,6/ 41,0	18,5/ 30,7	12,3/ 20,5	-26,5/ -20,5	-34,5/ -26,7	-42,4/ -32,8	-55,7/ -43,1
-750	±120 (J)	47,3/ 82,3	37,8/ 65,8	28,4/ 49,4	18,9/ 32,9	-43,5/ -31,5	-56,6/ -41,0	-69,6/ -50,4	-91,4/ -66,2
-1 000	±250 (K)	56,3/ 117	45,0/ 93,7	33,8/ 70,2	22,5/ 46,8	-62,5/ -37,5	-81,3/ -48,8	-100/ -60,0	-131/ -78,8
-1 500	±250 (K)	93,8/ 163	75,0/ 130	56,3/ 97,7	37,5/ 65,1	-87,5/ -62,5	-114/ -81,3	-140/ -100	-184/ -131

When the upper category temperature is above 125 °C, the limits shall be given in the detail specification.

Formulas for calculation of the permissible relative variation in capacitance:

Permissible relative variation in the temperature range from 20 °C to the upper category temperature:

$$\Delta C/C \left(10^{-3}\right) = (\alpha \pm |\delta|) \times (UCT - 20) / 1000 \quad (1)$$

Permissible relative variation in the temperature range from 20 °C to the lower category temperature:

a) lower permissible relative variation in capacitance from 20 °C to lower category temperature:

$$\Delta C/C \left(10^{-3}\right) = (\alpha \pm |\delta|) \times (LCT - 20) / 1000 \quad (2)$$

b) upper permissible relative variation in capacitance from 20 °C to lower category temperature:

$$\Delta C/C \left(10^{-3}\right) = [(-36) - (1,22 \times |\delta|) + (0,22 \times \alpha) + \alpha] \times (LCT - 20) / 1000 \quad (3)$$

α Temperature coefficient

δ Tolerance of α

LCT Lower category temperature

UCT Upper category temperature

4.2.6 Dimensions

Suggested rules for the specification and coding of dimensions are given in Annex A.

Specific dimensions shall be given in the detail specification.

5 Test and measurement procedures

5.1 General

This Clause 5 supplements the information given in IEC 60384-1:2021, Clause 5 to Clause 10.

5.2 Preliminary drying

See IEC 60384-1:2021, 5.3.

5.3 Measuring conditions

See IEC 60384-1:2021, 5.2.1.

5.4 Mounting

See IEC 60384-1:2021, 5.5.

5.5 Visual examination and check of dimensions

5.5.1 General

See IEC 60384-1:2021, 7.1, with the details of 5.5.2 and 5.5.3.

5.5.2 Visual examination

A visual examination shall be carried out with suitable equipment with approximately 10× magnification and lighting appropriate to the specimen under test and the quality level required. In case the specimen are very small components, the visual examination may be carried out with higher magnification.

The operator should have available facilities for incident or transmitted illumination as well as an appropriate measuring facility.

5.5.3 Requirements

5.5.3.1 General

Quantitative values for the requirements below may be given in the detail or in the manufacturer's specification.

5.5.3.2 Requirements for the ceramic

Requirements for the ceramic are as follows:

- a) Be free of cracks or fissures, except small damages on the surface, that do not deteriorate the performance of the capacitor (examples: see Figure 1 and Figure 2).

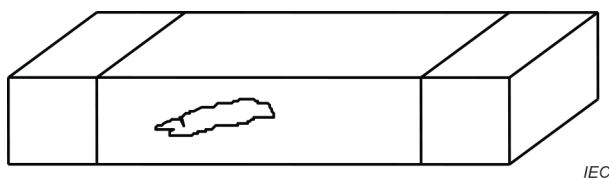
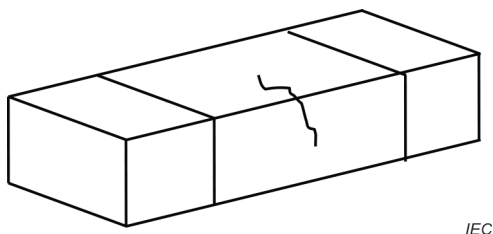


Figure 1 – Fault: crack or fissure



NOTE Crack or fissure on one side or extending from one face to another over a corner.

Figure 2 – Fault: crack or fissure

- b) Not exhibit visible separation or delamination between the layers of the capacitor (see Figure 3).

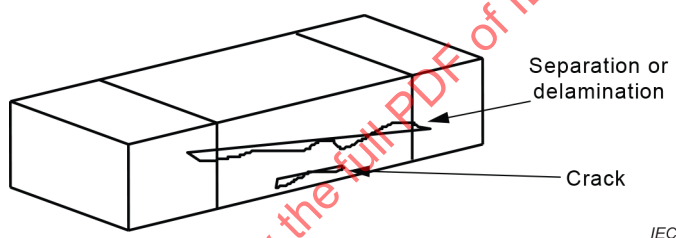


Figure 3 – Separation or delamination

- c) Not exhibit exposed electrodes between the two terminations (see Figure 4).

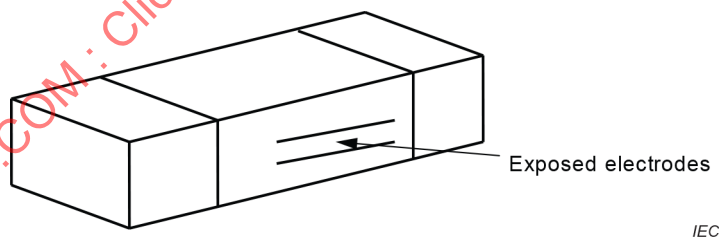


Figure 4 – Exposed electrodes

- d) The ceramic body shall be free of any conducting smears (metallization, tinning, etc.) on a central zone between two adjacent terminations which is equal to the minimum distance between those (Annex A, dimension L_4).

5.5.3.3 Requirements for the metallization

Requirements for the metallization are as follows:

- a) Not exhibit any visible detachment of the metallized terminations and not exhibit any exposed electrodes (see Figure 4).
- b) The principal faces (see Figure 5) are those noted A, B and C.
- In the case of capacitors of square section, the faces D and E are also considered principal.

The maximum area of gaps in metallization on each principal face shall not be greater than 15 % of the area of that face; these gaps shall not be concentrated in the same area. The gaps in metallization shall not affect the two principal edges of each extremity of the block (or four edges for square section capacitors). Dissolution of the end face plating (leaching) shall not exceed 25 % of the length of the edge concerned.

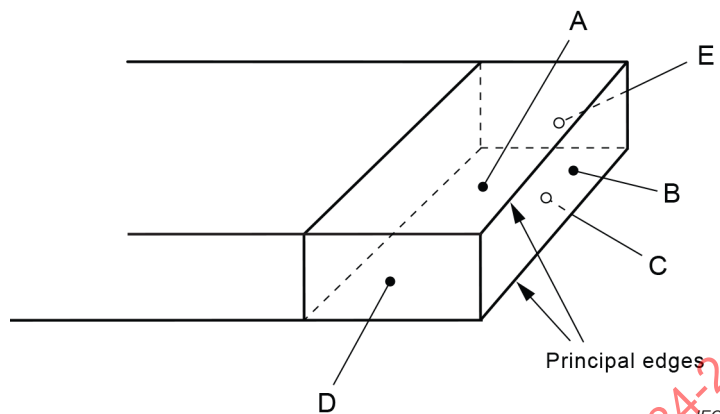


Figure 5 – Principal faces

5.6 Electrical tests

5.6.1 Capacitance

5.6.1.1 General

See IEC 60384-1:2021, 6.3, with the details of 5.6.1.2 and 5.6.1.3.

5.6.1.2 Measuring conditions

Unless otherwise specified in the detail specification,

- measuring voltage: $\leq 5 \text{ V}_{\text{RMS}}$,
- frequency: $C_N \leq 1\,000 \text{ pF}$ 1 MHz or 100 kHz (reference frequency 1 MHz);
 $C_N > 1\,000 \text{ pF}$ 1 kHz or 100 kHz (reference frequency 1 kHz).

5.6.1.3 Requirements

The capacitance value as measured in the unmounted state, shall correspond to the rated value taking into account the specified tolerance.

The capacitance as measured in the mounted state in accordance with Group 3 is for reference purposes only in further tests.

5.6.2 Tangent of loss angle ($\tan \delta$)

5.6.2.1 General

See IEC 60384-1:2021, 6.4, with the details of 5.6.2.2 and 5.6.2.3.

5.6.2.2 Measuring conditions

The measuring conditions are the same as those of 5.6.1. The inaccuracy of the measuring equipment shall not exceed 3×10^{-4} .

5.6.2.3 Requirements

The tangent of loss angle as measured in the unmounted state shall not exceed the limit given in Table 4.

Table 4 – Tangent of loss angle limits

Nominal capacitance pF	Tangent of loss angle ($\tan \delta$) $\times 10^{-4}$		
	$+100 \geq \alpha > -750$ and SL (1C) C0G	$-750 \geq \alpha > -1\ 500$ U2J	$\alpha = -1\ 500$
$C_N \geq 50$	15	20	30
$5 \leq C_N < 50$	$1,5 \left(\frac{150}{C_N} + 7 \right)$	$2 \left(\frac{150}{C_N} + 7 \right)$	$3 \left(\frac{150}{C_N} + 7 \right)$
$C_N < 5$	When the measurement is required the detail specification shall specify the limit.		

The tangent of loss angle as measured in the mounted state in accordance with Group 3 is for reference purpose only in further tests.

5.6.3 Insulation resistance

5.6.3.1 General

See IEC 60384-1:2021, 6.1, with the details of 5.6.3.2 to 5.6.3.4.

5.6.3.2 Preparation for test

Prior to the test, capacitors shall be carefully cleaned to remove any contamination.

Care shall be taken to maintain cleanliness in the test chambers and during post-test measurements. Before the measurement, the capacitors shall be fully discharged. The insulation resistance shall be measured between the terminations.

5.6.3.3 Measuring conditions

See IEC 60384-1:2021, 6.1.2, with the following details.

The measuring voltage may be of any value not greater than U_R , the referee voltage being U_R , for a capacitor with a rated voltage below or equal to 1 kV. For $U_R > 1$ kV the referee voltage shall be 1 kV.

The insulation resistance (R_i) shall be measured after the voltage has been applied for (60 ± 5) s.

For lot-by-lot testing (Group A) the test may be terminated in a shorter time, if the required value of insulation resistance is reached.

The product of the internal resistance of the voltage source and the nominal capacitance of the capacitor shall not exceed 1 s, unless otherwise specified in the detail specification.

The charge current shall not exceed 0,05 A. For capacitors with rated voltages of 1 kV and above, a lower limit (value) may be given in the detail specification.

5.6.3.4 Requirements

The insulation resistance shall meet the following requirements.

$C_N \leq 10 \text{ nF}$	$R_i \geq 10\,000 \text{ M}\Omega$
$C_N > 10 \text{ nF}$	$R_i \times C_N \geq 100 \text{ s}$

5.6.4 Voltage proof

5.6.4.1 General

See IEC 60384-1:2021, 6.2, with the details of 5.6.4.2 to 5.6.4.4.

5.6.4.2 Test conditions

The product of R_1 and the nominal capacitance C_X shall be smaller than or equal to 1 s.

NOTE R_1 is a charging resistor that includes the internal resistance of the voltage source. More information can be found in IEC 60384-1:2021, 6.2.2.

The charge current shall not exceed 0,05 A.

For capacitors with rated voltages of 1 kV and above, a lower charge current limit value may be given in the detail specification. To protect the capacitors against flashover, the test may be performed in a suitable insulating medium.

5.6.4.3 Test voltages

The test voltages in accordance with Table 5 shall be applied between the measuring points of 5.6.3 and Table 3 in IEC 60384-1:2021 for a period of 1 min for qualification approval testing and for a period of 1 s for the lot-by-lot quality conformance testing.

Table 5 – Test voltages

Rated voltage V	Test voltage V
$U_R \leq 100$	$2,5 U_R$
$100 < U_R \leq 200$	$1,5 U_R + 100$
$200 < U_R \leq 500$	$1,3 U_R + 100$
$500 < U_R < 1\,000$	$1,3 U_R$
$U_R \geq 1\,000$	$1,2 U_R$

5.6.4.4 Requirement

There shall be no breakdown or flashover during the test.

5.7 Temperature coefficient (α) and temperature cyclic drift

5.7.1 General

See IEC 60384-1:2021, 6.8.3.3, with the details of 5.7.2 to 5.7.4.

5.7.2 Preliminary drying

The capacitors shall be dried in accordance with 5.2 for 16 h to 24 h.

5.7.3 Measuring conditions

See IEC 60384-1:2021, 6.8.1.2 and 6.8.1.3, with the following details.

The capacitors shall be measured in the unmounted state.

5.7.4 Requirements

The capacitance deviation at upper and lower category temperature (and at such other temperatures as may be specified in the detail specification) shall not exceed the limits given in Table 3.

The temperature cyclic drift shall not exceed the limits given in Table 6.

Table 6 – Temperature cyclic drift limits

α rated in $10^{-6}/K$	Requirements ^a
$+100 \geq \alpha > -150$ C0G	0,3 % or 0,05 pF
$-150 \geq \alpha > -1\ 500$ and SL (1C) U2J	1 % or 0,05 pF
$\alpha = -1\ 500$	2 % or 0,05 pF
^a Whichever is the greater.	

5.8 Shear test

See IEC 60384-1:2021, 7.7.

A force shall be selected from 1 N, 2 N, 5 N or 10 N and specified in the detail specification.

5.9 Substrate bending test

5.9.1 General

See IEC 60384-1:2021, 7.8.

Unless otherwise specified in the detail specification,

- the deflection D shall be selected from 1 mm, 2 mm or 3 mm, higher deflection values may be given in the detail specification in case of very robust designs.
- the number of bends shall be 1 time,
- the radius of the bending tool shall be 5 mm,
When the deflection D is 2 mm or less, the radius may be 230 mm.
- the duration in the bent state shall be 5 s.

For 1005 M or smaller size, the thickness of substrate should be 0,8 mm.

5.9.2 Initial measurement

The capacitance shall be measured as specified in 5.6.1 and in the detail specification.

5.9.3 Final inspection

The capacitors shall be visually examined and there shall be no visible damage.

See 5.5.2.

The change of capacitance with board in bent position shall not exceed 5 %.

5.10 Resistance to soldering heat

5.10.1 General

See IEC 60068-2-58 with the details of 5.10.2 to 5.10.5.

5.10.2 Initial measurement

The capacitance shall be measured in accordance with 5.6.1.

5.10.3 Test conditions

5.10.3.1 Solder bath method (applicable to 1608 M, 2012 M and 3216 M)

See Table A.1 for explanation of the size code.

See IEC 60068-2-58, Test Td₂, Method 1, with the following details, if not otherwise specified in the detail specification:

The specimen shall be preheated to a temperature of 110 °C to 140 °C and maintained for 30 s to 60 s.

Solder alloy: Sn-Pb or Sn-Ag-Cu

Temperature: 260 °C ± 5 °C

Duration of immersion: 10 s ± 1 s

Depth of immersion: 10 mm

Number of immersions: 1

5.10.3.2 Infrared and forced gas convection soldering system

See IEC 60068-2-58, Test Td₂, Method 2, with the following details:

- a) the solder paste shall be applied to the test substrate;
- b) the thickness of solder deposit shall be specified in the detail specification;
- c) the terminations of the specimen shall be placed on the solder paste;
- d) solder alloy: Sn-Pb;

unless otherwise specified in the detail specification, the specimen and test substrate shall be preheated to a temperature of (150 ± 10) °C and maintained for 60 s to 120 s in infrared and forced gas convection soldering system;

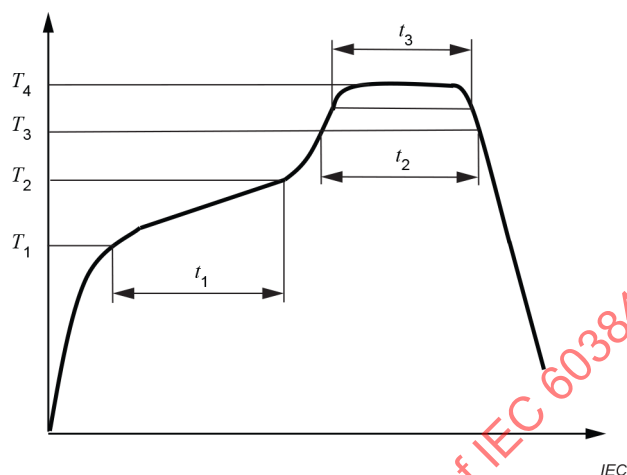
the temperature of the reflow system shall be quickly raised until the specimen has reached (235 ± 5) °C and maintained at this temperature for (10 ± 1) s;

- e) solder alloy: Sn-Ag-Cu;

unless otherwise specified in the detail specification, the reflow temperature profile shall be selected from Table 7 and Figure 6;

Table 7 – Reflow temperature profiles for Sn-Ag-Cu alloy

Alloy composition		T_1 °C	T_2 °C	t_1 s	T_3 °C	t_2 s	T_4 °C	t_3 s
Lead-free solder (Sn-Ag-Cu)	Test 1	150 ± 5	180 ± 5	120 ± 5	220	60 to 90	250	20 to 40 at $T_4 - 5$ °C

**Figure 6 – Reflow temperature profile**

- f) number of each test: 1, unless otherwise specified in the detail specification;
g) the temperature profile of d) or e) shall be specified in the detail specification.

5.10.4 Recovery

The capacitors shall recover for 6 h to 24 h.

The flux residues shall be removed with a suitable solvent.

5.10.5 Final inspection, measurements and requirements

After recovery, the capacitors shall be visually examined and measured and shall meet the following requirements.

Under normal lighting and approximately 10× magnification, there shall be no signs of damage such as cracks. See 5.5.2.

Dissolution of the end face plating (leaching) shall not exceed 25 % of the length of the edge concerned. The detail specification may specify further details.

The capacitance shall be measured in accordance with 5.6.1 and the change shall not exceed the values in Table 8.

Table 8 – Maximum capacitance change

α rated in $10^{-6}/K$	Requirements ^a
$+100 \geq \alpha \geq -750$ C0G and U2J	0,5 % or 0,5 pF
$-750 > \alpha \geq -1\,500$ and SL (1C)	1 % or 1 pF
^a Whichever is the greater.	

5.11 Solderability

5.11.1 General

See IEC 60068-2-58 with the details of 5.11.2 to 5.11.4.

5.11.2 Test conditions

5.11.2.1 Solder bath method (applicable to 1608 M, 2012 M and 3216 M)

See Table A.1 for explanation of the size code.

See IEC 60068-2-58, Test Td₁, Method 1, with the following details, if not otherwise specified in the detail specification:

The specimen shall be preheated to a temperature of 80 °C to 140 °C and maintained for 30 s to 60 s.

Solder alloy:	Sn-Pb	Sn-Ag-Cu
Temperature:	(235 ± 5) °C	(245 ± 5) °C
Duration of immersion:	(2 ± 0,2) s	(3 ± 0,3) s
Depth of immersion:	10 mm	10 mm
Number of immersions:	1	1

5.11.2.2 Infrared and forced gas convection soldering system

See IEC 60068-2-58, Test Td₁, Method 2, with the following details:

- a) the solder paste shall be applied to the test substrate;
- b) the thickness of solder deposit shall be specified in the detail specification;
- c) the terminations of the specimen shall be placed on the solder paste;
- d) solder alloy: Sn-Pb;

unless otherwise specified in the detail specification, the specimen and test substrate shall be preheated to a temperature of (150 ± 10) °C and maintained for 60 s to 120 s in the infrared and forced gas convection soldering system;

the temperature of the reflow system shall be quickly raised until the specimen has reached (215 ± 3) °C and maintained at this temperature for (10 ± 1) s;
- e) solder alloy: Sn-Ag-Cu;

unless otherwise specified in the detail specification, the specimen and test substrate shall be preheated to a temperature of (150 ± 5) °C to (180 ± 5) °C for 60 s to 120 s in the infrared and forced gas convection soldering system;

the temperature of the reflow system shall be quickly raised until the specimen has reached (235 ± 3) °C. The time above 225 °C shall be (20 ± 5) s;
- f) the temperature profile of d) or e) shall be specified in the detail specification.

5.11.3 Recovery

The flux residues shall be removed with a suitable solvent.

5.11.4 Final inspection, measurements and requirements

The capacitors shall be visually examined under normal lighting and approximately 10× magnification. There shall be no signs of damage. See 5.5.2.

Both end face and the contact areas shall be covered with a smooth and bright solder coating with no more than a small number of scattered imperfections such as pinholes or unwetted or de-wetted areas. These imperfections shall not be concentrated in one area.

The detail specification may specify further requirements.

5.12 Rapid change of temperature

5.12.1 General

This test shall be applied only to capacitors for which the category temperature is greater 110 °C.

See IEC 60384-1:2021, 8.1, with the details of 5.12.2 to 5.12.5.

The capacitors shall be mounted in accordance with 5.4.

5.12.2 Initial measurement

The capacitance shall be measured in accordance with 5.6.1.

5.12.3 Number of cycles

The number of cycles: 5.

Duration of exposure at the temperature limits: 30 min.

5.12.4 Recovery

The capacitors shall recover for 6 h to 24 h.

5.12.5 Final inspection, measurements and requirements

The capacitors shall be visually examined. There shall be no visible damage. See 5.5.2.

The capacitance shall be measured in accordance with 5.6.1 and the change shall not exceed the value in Table 9.

Table 9 – Maximum capacitance change

α rated in $10^{-6}/K$	Requirements ^a
$+100 \geq \alpha \geq -750$ C0G and U2J	1 % or 1 pF
$-750 > \alpha \geq -1\ 500$ and SL (1C)	2 % or 1 pF
^a Whichever is the greater.	

5.13 Climatic sequence

5.13.1 General

See IEC 60384-1:2021, 8.2, with the details of 5.13.2 to 5.13.7.

5.13.2 Initial measurement

The capacitance shall be measured in accordance with 5.6.1.

5.13.3 Dry heat

See IEC 60384-1:2021, 8.2.3.

5.13.4 Damp heat, cyclic, Test Db, first cycle

See IEC 60384-1:2021, 8.2.4.

5.13.5 Cold

See IEC 60384-1:2021, 8.2.5, with the following details.

The capacitors shall be visually examined. There shall be no visible damage.

5.13.6 Damp heat, cyclic, Test Db, remaining cycles**5.13.6.1 General**

See IEC 60384-1:2021, 8.2.7, with the details of 5.13.6.2 and 5.13.6.3.

5.13.6.2 Test conditions

No voltage applied.

The remaining cycles shall be tested in accordance with Table 10.

Table 10 – Number of damp heat cycles

Category	No. of cycles of 24 h
- / - / 56	5
- / - / 21	1
- / - / 10	1
- / - / 04	0

5.13.6.3 Recovery

The capacitors shall recover for 6 h to 24 h.

5.13.7 Final inspection, measurements and requirements

The capacitors shall be visually examined. There shall be no visible damage. See 5.5.2.

The capacitors shall be measured and shall meet the requirements in Table 11.

Table 11 – Final inspection, measurements and requirements

Measurement	Measurement and conditions	α rated and (Subclass)	Requirements
Capacitance	5.6.1	+100 $\geq \alpha \geq$ -750 (1B) C0G and U2J	Capacitance change $\leq 2\%$ or 1 pF ^a
		-750 $> \alpha \geq$ -1 500 (1F) SL (1C)	Capacitance change $\leq 3\%$ or 1 pF ^a
Tangent of loss angle	5.6.2	All α s and subclasses	$\leq 2 \times$ value in the table of 5.6.2
Insulation resistance	5.6.3	All α s and subclasses	$R_i \geq 2\,500\text{ M}\Omega$ or $R_i \times C_N \geq 25\text{ s}^b$

NOTE See 4.2.5 for an explanation of the subclass codes.

^a Whichever is the greater.

^b Whichever is the lower.

5.14 Damp heat, steady state

5.14.1 General

See IEC 60384-1:2021, 8.3, with the details of 5.14.2 to 5.14.5.

The capacitors shall be mounted in accordance with 5.4.

5.14.2 Initial measurement

The capacitance shall be measured in accordance with 5.6.1.

5.14.3 Test conditions

No voltage shall be applied, unless otherwise specified in the detail specification.

The severity of the test should be selected from the test conditions as shown in Table 12 and be specified in the detail specification.

The duration time should be selected in accordance with 4.1 and shall be specified in the detail specification.

Table 12 – Test conditions for damp heat, steady state

Severity	Temperature °C	Relative humidity %
1	+85 ± 2	85 ± 3
2	+60 ± 2	93 ± 3
3	+40 ± 2	93 ± 3

When the application of voltage is specified, U_R shall be applied to one half of the lot and no voltage shall be applied to the other half of the lot.

Within 15 min after removal from the damp heat test, the voltage proof test in accordance with 5.6.4 shall be carried out, but with the rated voltage applied.

For safety reasons, different conditions for the application of voltage to capacitors with rated voltages of 1 kV or above may be given in the detail specification.

5.14.4 Recovery

The capacitors shall recover for 6 h to 24 h.

5.14.5 Final inspection, measurements and requirements

The capacitors shall be visually examined. There shall be no visible damage. See 5.5.2.

The capacitors shall be measured and shall meet the requirements in Table 13.

Table 13 – Final inspection, measurements and requirements

Measurement	Measurement and conditions	α rated and (Subclass)	Requirements
Capacitance	5.6.1	+100 $\geq \alpha \geq$ -750 (1B) C0G and U2J	Capacitance change $\leq 2\%$ or 1 pF ^a
		-750 $> \alpha \geq$ -1 500 (1F) SL (1C)	Capacitance change $\leq 3\%$ or 1 pF ^a
Tangent of loss angle	5.6.2	All α s and subclasses	$\leq 2 \times$ value in the table of 5.6.2
Insulation resistance	5.6.3	All α s and subclasses	$R_i \geq 2\,500\text{ M}\Omega$ or $R_i \times C_N \geq 25\text{ s}$ ^b
NOTE See 4.2.5 for an explanation of the subclass codes. ^a Whichever is the greater. ^b Whichever is the lower.			

5.15 Endurance**5.15.1 General**

See IEC 60384-1:2021, 8.5, with the details of 5.15.2 to 5.15.5.

The capacitors shall be mounted in accordance with 5.4.

5.15.2 Initial measurement

The capacitance shall be measured in accordance with 5.6.1.

5.15.3 Test conditions

If the category voltage is equal to the rated voltage, the capacitors shall be tested as in Table 14.

Table 14 – Endurance test conditions ($U_C = U_R$)

U_R	$U_R \leq 200$	$200 < U_R \leq 500$	$U_R > 500$
Temperature	Upper category temperature		
Voltage (DC)	1,5 U_R	1,3 U_R	1,2 U_R
Duration	1 000 h	1 500 h	2 000 h

If the category voltage is not equal to the rated voltage, the capacitors shall be tested as in Table 15.

Table 15 – Endurance test conditions ($U_C \neq U_R$)

U_R	$U_R \leq 200$		$200 < U_R \leq 500$		$U_R > 500$	
Temperature	T_R	T_B	T_R	T_B	T_R	T_B
Voltage (DC)	1,5 U_R	1,5 U_C	1,3 U_R	1,3 U_C	1,2 U_R	1,2 U_C
Duration	1 000 h		1 500 h		2 000 h	
Sample	Divided into two parts		Divided into two parts		Divided into two parts	
T_R = Rated temperature.						
T_B = Upper category temperatures > 85 °C, such as 100 °C, 125 °C and 150 °C.						

5.15.4 Recovery

The capacitors shall recover for 6 h to 24 h.

5.15.5 Final inspection, measurements and requirements

The capacitors shall be visually examined. There shall be no visible damage. See 5.5.2.

The capacitors shall be measured and shall meet the requirements in Table 16.

Table 16 – Final inspection, measurements and requirements

Measurement	Measurement and conditions	α rated and (Subclass)	Requirements
Capacitance	5.6.1	$+100 \geq \alpha \geq -750$ (1B) C0G and U2J	Capacitance change $\leq 2 \%$ or 1 pF^a
		$-750 > \alpha \geq -1\,500$ (1F) SL (1C)	Capacitance change $\leq 3 \%$ or 1 pF^a
Tangent of loss angle	5.6.2	All α s and subclasses	$\leq 2 \times$ value in the table of 5.6.2.
Insulation resistance	5.6.3	All α s and subclasses	$R_i \geq 4\,000 \text{ M}\Omega$ or $R_i \times C_N \geq 40 \text{ s}^b$
NOTE See 4.2.5 for an explanation of the subclass codes.			
^a Whichever is the greater.			
^b Whichever is the lower.			

5.16 Robustness of terminations (only for capacitors with strip termination)**5.16.1 General**

See IEC 60384-1:2021, 7.3, with the details of 5.16.2 and 5.16.3.

5.16.2 Test conditions

Unless otherwise specified in the detail specification, the conditions of the tests are as follows:

- Test U_{a1} : force: 2,5 N;
- Test U_b , Method 1: force: 2,5 N;
- number of bends: 1.

5.16.3 Final inspection and requirements

The capacitors shall be visually examined. There shall be no visible damage.

5.17 Component solvent resistance (if required)

See IEC 60384-1:2021, 9.4.

5.18 Solvent resistance of the marking (if required)

See IEC 60384-1:2021, 9.5.

5.19 Accelerated damp heat, steady state (if required)

5.19.1 General

See IEC 60384-1:2021, 8.9, with the details of 5.19.2 to 5.19.5.

The capacitors shall be mounted in accordance with 5.4 and IEC 60384-1:2021, 8.9.1.

Half the capacitors shall be connected in series with resistors of 100 k Ω , with a relative tolerance of ± 10 %, and half in series with resistors of 6,8 k Ω , with a relative tolerance of ± 10 %.

5.19.2 Initial measurement

The capacitors shall be measured for insulation resistance with a voltage of $1,5 \text{ V} \pm 0,1 \text{ V}$ applied across the capacitor and resistor in series.

The insulation resistance, including the series resistor, shall meet the requirements given in Table 17.

Table 17 – Initial requirements

Measurement	Measuring conditions	Requirements	
Insulation resistance	$(1,5 \pm 0,1) \text{ V}$	Connected to 100 k Ω resistors	$C_N \leq 10 \text{ nF}$: $R_i \geq 10\,000 \text{ M}\Omega$ $C_N > 10 \text{ nF}$: $(R_i - 100 \text{ k}\Omega) \times C_N \geq 100 \text{ s}$
		Connected to 6,8 k Ω resistors	$C_N \leq 10 \text{ nF}$: $R_i \geq 10\,000 \text{ M}\Omega$ $C_N > 10 \text{ nF}$: $(R_i - 6,8 \text{ k}\Omega) \times C_N \geq 100 \text{ s}$

5.19.3 Conditioning

The capacitors with associated resistors shall be subjected to conditioning at $(85 \pm 2) ^\circ\text{C}$, $(85 \pm 3) \%$ relative humidity for the test duration given in Table 18. The voltage given in Table 18 shall be applied to the capacitors connected to 100 k Ω resistors and those connected to 6,8 k Ω resistors. In both cases, the voltage shall be applied across the capacitor/resistor combination.

Care shall be taken to avoid condensation of water on the capacitors or substrates. This can happen if the door is opened during the test before the humidity is lowered.

Table 18 – Conditioning

Connected resistors kΩ	Applied voltage	Duration
100	$(1,5 \pm 0,1)$ V or the voltage specified in the detail specification	168 h, 500 h or 1 000 h; as specified in the detail specification
6,8	$(50 \pm 0,1)$ V or U_R , whichever is the lower, or the voltage specified in the detail specification	

5.19.4 Recovery

The applied voltage shall be disconnected, and the capacitors and resistors shall be removed from the test chamber and allowed to recover for 6 h to 24 h in standard atmospheric conditions for testing.

5.19.5 Final measurements

The capacitors shall be measured for insulation resistance, as in 5.19.2.

The insulation resistance, including the series resistor, shall be greater than 0,1 times the values given in 5.19.2.

6 Marking**6.1 General**

See IEC 60384-1:2021, 4.3, with the details of 6.2 to 6.6.

6.2 Information for marking

The information given in the marking is normally selected from the following list: the relative importance of each item is indicated by its position in the list:

- nominal capacitance;
- rated voltage (DC voltage may be indicated by the symbol: $\overline{\text{---}}$ [IEC 60417-5031(2002-10)] or ---);
- tolerance on nominal capacitance;
- temperature coefficient and its tolerance as applicable (in accordance with 4.2.5) or Annex B;
- year and month (or week) of manufacture;
- manufacturer's name or trade mark;
- climatic category;
- manufacturer's type designation;
- reference to the detail specification.

6.3 Marking on the body

These capacitors are generally not marked on the body. If some marking can be applied, they shall be clearly marked with as many as possible of the items stated in 6.2 as is considered useful. Any duplication of information in the marking on the capacitor should be avoided.

6.4 Requirements for marking

Any marking shall be legible and not easily smeared or removed by rubbing with fingers.

6.5 Marking of the packaging

The packaging containing the capacitor(s) shall be clearly marked with all the information listed in 6.2.

6.6 Additional marking

Any additional marking shall be so applied that no confusion can arise.

7 Information to be given in a detail specification

7.1 General

The detail specification shall be derived from the relevant blank detail specification.

Detail specifications shall not specify requirements inferior to those of the generic, sectional or blank detail specification. When more severe requirements are included, they shall be indicated in the test schedules, for example by an asterisk.

The information given in 7.2 may be presented in tabular form if more convenient.

The information in 7.2 to 7.5 shall be given in each detail specification and the values quoted should be selected from those given in the appropriate clause of this document.

7.2 Outline drawing and dimensions

There shall be an illustration of the capacitors as an aid to easy recognition and for comparison of the capacitors with others.

Dimensions and their associated tolerances, which affect interchangeability and mounting, shall be given in the detail specification. All dimensions shall be stated in millimetres; however, when the original dimensions are given in inches, the converted metric dimensions in millimetres shall be added.

Normally the numerical values shall be given for the length, width and height of the body. When necessary, for example when a number of items (sizes and capacitance/voltage ranges) are covered by a detail specification, the dimensions and their associated tolerances shall be placed in a table below the drawing.

When the configuration is other than described above, the detail specification shall state such dimensional information as will adequately describe the capacitors.

7.3 Mounting

The detail specification shall give guidance on methods of mounting for normal use. Mounting for test and measurement purposes (when required) shall be in accordance with 5.4 of this document.

7.4 Rating and characteristics

7.4.1 General

The ratings and characteristics shall be in accordance with the relevant clauses of this document, together with 7.4.2, 7.4.3 and 7.4.4.

7.4.2 Nominal capacitance range

The nominal capacitance range shall be specified as described in 4.2.4.1.

When products approved to the detail specification have different ranges, the following statement should be added: "The range of capacitance values available in each voltage range is given in the register of approvals, available for example on the IECQ on-line certificate system website: www.iecq.org".

7.4.3 Particular characteristics

Additional characteristics may be listed when they are considered necessary to specify adequately the component for design and application purposes.

7.4.4 Soldering

The detail specification shall specify the test methods, severities and requirements applicable for the solderability and the resistance to soldering heat tests.

7.5 Marking

The detail specification shall specify the content of the marking on the capacitor and on the packaging. Deviations from Clause 6 shall be specifically stated in the detail specification.

8 Quality assessment procedures

8.1 Primary stage of manufacture

The primary stage of manufacture is the first common firing of the dielectric-electrode assembly.

8.2 Structurally similar components

Capacitors considered as being structurally similar are capacitors produced with similar processes and materials, though they can be of different case sizes and values.

8.3 Certified records of released lots

The information required in IEC 60384-1:2021, Q.1.5, shall be made available when specified in the detail specification and when requested by a purchaser. After the endurance test, the parameters for which variables information is required are the capacitance change, $\tan \delta$ and the insulation resistance.

8.4 Qualification approval

8.4.1 General

The procedures for qualification approval testing are given in IEC 60384-1:2021, Clause Q.2.

The schedule to be used for qualification approval testing on the basis of lot-by-lot and periodic tests is given in Annex C. The procedure using a fixed sample size schedule is given in 8.4.2 and 8.4.3.

8.4.2 Qualification approval on the basis of the fixed sample size procedures

The fixed sample size procedure is described in IEC 60384-1:2021, Q.2.4. The sample shall be representative of the range of capacitors for which approval is sought. This range may be different from the complete range covered by the detail specification.

For each temperature coefficient, the sample shall consist of specimens of capacitors of maximum and minimum size and for each of these sizes, the maximum capacitance value for the highest rated voltage and minimum rated voltage of the voltage ranges for which approval is sought. When there are more than four rated voltages, an intermediate voltage shall also be tested. Thus, for the approval of a range, testing is required of either four or six values (capacitance/voltage combinations) for each temperature coefficient. Where the total range consists of fewer than four values, the number of specimens to be tested shall be that required for four values. When approval is sought for more than one temperature coefficient, see 8.4.3.

In case assessment level EZ is used, spare specimens are permitted as follows:

Two (for six values) or three (for four values) per value may be used as replacements for specimens that are non-conforming because of incidents not attributable to the manufacturer.

The numbers given in Group 0 assume that all groups are applicable. If this is not so, the numbers may be reduced accordingly.

When additional groups are introduced into the qualification approval test schedule, the number of specimens required for Group 0 shall be increased by the same number as that required for the additional groups.

Table 4 gives the number of samples to be tested in each group or subgroup together with the number of permissible non-conformances for the qualification approval test.

8.4.3 Tests

The complete series of tests specified in Table 19 and Table 20 are required for the approval of capacitors covered by one detail specification. The tests of each group shall be carried out in the order given.

The whole sample shall be subjected to the tests of Group 0 and then divided for the other groups.

Non-conforming specimens found during the tests of Group 0 shall not be used for the other groups.

"One non-conforming item" is counted when a capacitor has not satisfied the whole or a part of the tests of a group.

When approval is sought for more than one temperature coefficient at the same time, the test schedule and sample size required for the smallest temperature coefficient are those of Groups 1, 2 and 3. For each additional temperature coefficient, the testing is limited to the tests and sample sizes as specified for Subgroup 3.3 and Group 4.

The approval is decided on an individual temperature coefficient basis in accordance with the permissible number of non-conforming items indicated in Table 4. In order to calculate the total actual non-conforming items for temperature coefficients other than the smallest, the non-conforming items in Groups 1, 2 and 3 for the smallest temperature coefficient are added to the non-conforming items in Subgroup 3.3 and Group 4 for that particular temperature coefficient.

The approval is granted when the number of non-conforming items is zero.

Table 19 and Table 20 together form the fixed sample size test schedule. Table 4 includes the details for the sampling and permissible non-conforming items for the different tests or groups of tests. Table 5 together with the details of the test contained in Clause 8 gives a complete summary of test conditions and performance requirements and indicates where, for example for the test method or conditions of test, a choice shall be made in the detail specification.

The conditions of test and performance requirements for the fixed sample size test schedule shall be identical to those specified in the detail specification for quality conformance inspection.

**Table 19 – Fixed sample size test plan for qualification approval
Assessment level EZ**

Group No.	Test	Subclause of this publication	Number of specimens n^e	Permissible number of nonconforming items c
0	Visual examination Dimensions Capacitance Tangent of loss angle Insulation resistance Voltage proof Spare specimens	5.5 5.5 5.6.1 5.6.2 5.6.3 5.6.4 12	132 + 24 ^f 12	0
1A	Robustness of termination ^g Resistance to soldering heat Component solvent resistance ^b	5.16 5.10 5.17	12	0
1B	Solderability Solvent resistance of marking ^b	5.11 5.18	12	0
2	Substrate bending test ^d	5.9	12	0
3 ^a	Mounting Visual examination Capacitance Tangent of loss angle Insulation resistance Voltage proof	5.4 5.5 5.6.1 5.6.2 5.6.3 5.6.4	84 + 24 ^f	0 ^c
3.1	Shear test ^h Rapid change of temperature Climatic sequence	5.8 5.12 5.13	24	0
3.2	Damp heat, steady state	5.14	24	0
3.3	Endurance	5.15	36	0
3.4	Accelerated damp heat, steady state ^b	5.19	24 ^f	0
4	Temperature coefficient and temperature cyclic drift	5.7	12	0
^a The values of these measurements serve as initial measurements for the tests of Group 3. ^b If required in the detail specification. ^c The capacitors found non-conforming items after mounting shall not be taken into account when calculating the permissible non-conforming for the following tests. They shall be replaced by spare capacitors. ^d Not applicable to capacitors, which, in accordance with their detail specification, shall only be mounted on alumina substrates. ^e Capacitance/voltage combinations, see 8.4.2. ^f Additional capacitors, if Group 3.4 is tested. ^g Applicable to capacitors with strip terminations. ^h Not applicable to capacitors with strip terminations.				

Table 20 – Tests schedule for qualification approval

Test (see NOTE 1)	Conditions of test (see NOTE 1)	D or ND (see NOTE 2)	n c (see Table 19)	Performance requirements (see NOTE 1)
GROUP 0		ND	See Table 19	
5.5 Visual examination				As in 5.5.3
5.5 Dimension (detail)				Legible marking and as specified in the detail specification
5.6.1 Capacitance	Frequency: ... Hz Measuring voltage: V RMS			See the detail specification
5.6.2 Tangent of loss angle ($\tan \delta$)	Frequency and Measuring voltage same as in 5.6.1			Within specified tolerance
5.6.3 Insulation resistance	See detail specification for the method			As in 5.6.2.3
5.6.4 Voltage proof	See detail specification for the method			As in 5.6.3.4
				No breakdown or flashover
GROUP 1A		D	See Table 19	
5.16 Robustness of termination (if applicable)	Test U_{a1} , Force: 2,5 N Test U_b , Method 1, Force: 2,5 N Number of bends: 1			
	Visual examination			No visible damage
5.10.2 Initial measurement	Capacitance			
5.10 Resistance to soldering heat	See detail specification for the method Recovery: 6 h to 24 h			
5.10.5 Final inspection, measurements and requirements	Visual examination Capacitance			As in 5.10.5
5.17 Component solvent resistance (if required)	Solvent: ... Solvent temperature: Method 2 Recovery: ...			As in 5.10.5
				See detail specification
GROUP 1B		D	See Table 19	
5.11 Solderability	See detail specification for the method			
5.11.4 Final inspection, measurements and requirements	Visual examination			As in 5.11.4
5.18 Solvent resistance of the marking ^a (if required)	Solvent: ... Solvent temperature: ... Method 1 Rubbing material: cotton wool Recovery: ...			Legible marking

Test (see NOTE 1)	Conditions of test (see NOTE 1)	D or ND (see NOTE 2)	n c (see Table 19)	Performance requirements (see NOTE 1)
GROUP 2		D	See Table 19	
5.9 Substrate bending test	Deflection: ...			See detail specification
5.9.2 Initial measurement	Number of bends: ...			
5.9.3 Final inspection	Capacitance			$ \Delta C/C \leq 5 \%$ No visible damage
	Capacitance (with printed board in bent position)			
	Visual examination			
GROUP 3		D	See Table 19	
5.4 Mounting	Substrate material: ... ^b			As in 5.5.3
	Visual examination			Within specified tolerance
	Capacitance			As in 5.6.2.3
	Tangent of loss angle			As in 5.6.3.4
	Insulation resistance			No breakdown or flashover
	Voltage proof			
GROUP 3.1		D	See Table 19	
5.8 Shear test	Visual examination			No visible damage
5.12.2 Initial measurement	Capacitance			
5.12 Rapid change of temperature	T_A = Lower category temperature			
	T_B = Upper category temperature			
	Five cycles			
	Duration t_1 = 30 min			
	Recovery: 6 h to 24 h			
5.12.5 Final inspection, measurements and requirements	Visual examination			No visible damage
	Capacitance			$\Delta C/C$: as in 5.12.5
5.13 Climatic sequence				
5.13.2 Initial Measurement	Capacitance			
5.13.3 Dry heat	Temperature: upper category temperature			
	Duration: 16 h			
5.13.4 Damp heat, cyclic, test Db, first cycle				
5.13.5 Cold	Temperature: lower category temperature			
	Duration: 2 h			
	Visual examination			No visible damage
5.13.6 Damp heat, cyclic, test Db, remaining cycles	Recovery: 6 h to 24 h			
5.13.7 Final inspection, measurements and requirements	Visual examination			No visible damage
	Capacitance			Legible marking
	Tangent of loss angle			$\Delta C/C$: as in 5.13.7
	Insulation resistance			As in 5.13.7

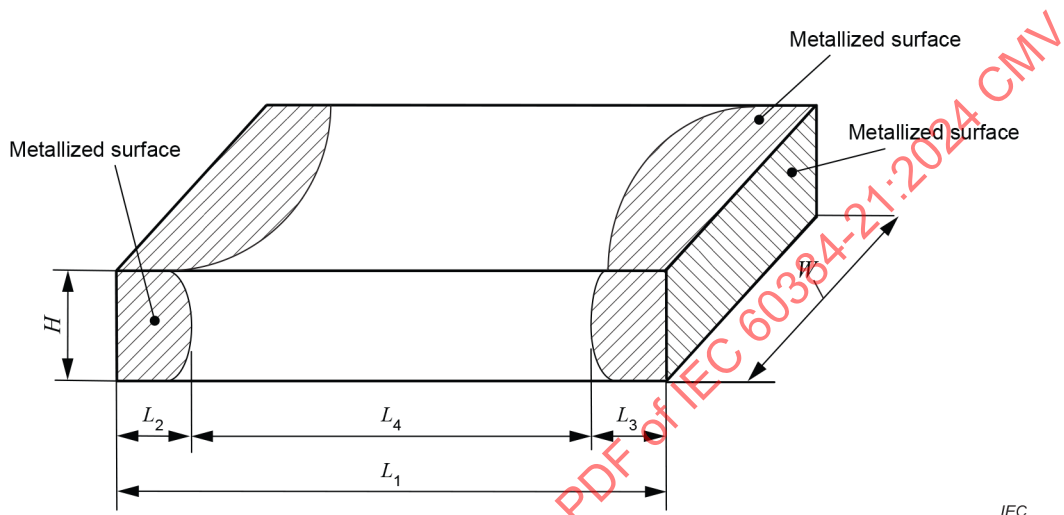
Test (see NOTE 1)	Conditions of test (see NOTE 1)	D or ND (see NOTE 2)	<i>n</i> <i>c</i> (see Table 19)	Performance requirements (see NOTE 1)
GROUP 3.2 5.14 Damp heat, steady state 5.14.2 Initial measurement 5.14.5 Final inspection, measurements and requirements	Capacitance Recovery: 6 h to 24 h Visual examination Capacitance Tangent of loss angle Insulation resistance	D	See Table 19	No visible damage Legible marking $\Delta C/C$: as in 5.14.5 As in 5.14.5 As in 5.14.5
GROUP 3.3 5.15 Endurance 5.15.2 Initial measurement 5.15.5 Final inspection, measurements and requirements	Duration: ... h Temperature: ... °C Voltage: ... V Capacitance Recovery: 6 h to 24 h Visual examination Capacitance Tangent of loss angle Insulation resistance	D	See Table 19	No visible damage Legible marking $\Delta C/C$: as in 5.15.5 As in 5.15.5 As in 5.15.5
GROUP 3.4 5.19 Accelerated damp heat, steady state (if required) 5.19.2 Initial measurement 5.19.5 Final measurement	Duration: ... h Temperature: $(85 \pm 2) ^\circ\text{C}$ Humidity: $(85 \pm 3) \% \text{ RH}$ Insulation resistance Recovery: 6 h to 24 h Insulation resistance	D	See Table 19	As in 5.19.2 As in 5.19.5
GROUP 4 5.7 Temperature coefficient (<i>a</i>) and temperature cyclic drift	Primary drying: 16 h to 24 h	ND	See Table 19	$\Delta C/C$: as in 5.7.4
NOTE 1 Subclause numbers of test and performance requirements refer to Clause 5.				
NOTE 2 In this table: D = destructive, ND= non-destructive.				
^a This test may be carried out on capacitors mounted on a substrate.				
^b When different substrate materials are used for the individual subgroup, the detail specification shall indicate which substrate material is used in each subgroup.				

Annex A (normative)

Guidance for the specification and coding of dimensions of fixed surface mount multilayer capacitors of ceramic dielectric, Class 1

The principles given in Figure A.1 shall be considered in the dimensioning of the capacitors.

Dimensions are specified in Table A.1.



Dimension W should not exceed dimension L_1 .

Dimension H should not exceed dimension W .

If necessary, the thickness of tinning should be specified.

Figure A.1 – Dimensions

Table A.1 – Dimensions

Code	Length L_1	Width W	$L_2; L_3$ Minimum	L_4 Minimum
0201M	$0,25 \pm 0,013$	$0,125 \pm 0,013$	0,04	0,06
0402M	$0,4 \pm 0,02$	$0,2 \pm 0,02$	0,05	0,1
0603M	$0,6 \pm 0,03$	$0,3 \pm 0,03$	0,1	0,2
1005M	$1,0 \pm 0,05$	$0,5 \pm 0,05$	0,1	0,3
1608M	$1,6 \pm 0,1$	$0,8 \pm 0,1$	0,2	0,5
2012M	$2,0 \pm 0,1$	$1,25 \pm 0,1$	0,2	0,7
3216M	$3,2 \pm 0,2$	$1,6 \pm 0,15$	0,3	1,4
3225M	$3,2 \pm 0,2$	$2,5 \pm 0,2$	0,3	1,4
4532M	$4,5 \pm 0,3$	$3,2 \pm 0,2$	0,3	2,0
5750M	$5,7 \pm 0,4$	$5,0 \pm 0,4$	0,3	2,5
NOTE Dimension in millimetres.				

Other case sizes and dimensions may be specified in the detail specification.

Annex B

(normative)

Combination of temperature coefficients and tolerances for the reference temperature of 25 °C

Temperature coefficients of capacitance, tolerances and related codes are shown in Table B.1.

Table B.1 – Combination of temperature coefficients and tolerances for the reference temperature of 25 °C

Code of temperature coefficient and tolerance	Temperature coefficient and the tolerance		Permissible relative variation in capacitance in parts per 1 000 between 25 °C and given temperature							
			Lower category temperature				Upper category temperature			
	α 10 ⁻⁶ /K	Tolerance 10 ⁻⁶ /K	-55 °C	-40 °C	-25 °C	-10 °C	+70 °C	+85 °C	+100 °C	+125 °C
C0G	0	± 30	-2,40/ 5,81	-1,95/ 4,72	-1,50/ 3,63	-1,05/ 2,54	-1,35/ 1,35	-1,80/ 1,80	-2,25/ 2,25	-3,00/ 3,00
U2J	-750	±120	50,4/ 87,8	41,0/ 71,3	31,5 /54,9	22,1/ 38,4	-39,2/ -28,4	-52,2/ -37,8	-65,3/ -47,3	-87,0/ -63,0

α = nominal temperature coefficient

NOTE C0G and U2J (Code of temperature coefficient and tolerance), see EIA-198-1-F.

Annex C (normative)

Quality conformance inspection

C.1 Formation of inspection lots

C.1.1 Groups A and B inspection

These tests shall be carried out on a lot-by-lot basis.

A manufacturer may aggregate the current production into inspection lots subject to the following safeguards.

- a) The inspection lot shall consist of structurally similar capacitors (see 8.2).
- b) The sample tested shall be representative of the values and the dimensions contained in the inspection lot:
 - in relation to their number;
 - with a minimum of five of any one value.
- c) If there are fewer than five of any one value in the sample, the basis for the drawing of samples shall be agreed between the manufacturer and the certification body (CB).

C.1.2 Group C inspection

These tests shall be carried out on a periodic basis.

Samples shall be representative of the current production of the specified periods and shall be divided into small, medium and large sizes. In order to cover the range of approvals in any period, one voltage shall be tested from each group of sizes. In subsequent periods, other sizes and/or voltage ratings in production shall be tested with the aim of covering the whole range.

C.2 Test schedule

The schedule for the lot-by-lot and periodic tests for quality conformance inspection is given in Table C.3 and Table C.4.

C.3 Delayed delivery

When, in accordance with the procedures of IEC 60384-1:2021, Q.1.7, re-inspection shall be made, solderability and capacitance shall be checked as specified in Groups A and B inspection.

C.4 Assessment levels

The assessment level(s) given in Table C.3 and Table C.4 should be selected from Table C.1 and Table C.2.

Table C.1 – Lot by lot inspection

Inspection subgroup ^d	EZ		
	IL ^a	n^a	c^a
A0	100 % ^b		
A1	S-4	c	0
A2	S-3	c	0
B1	S-3	c	0
B2	S-2	c	0
^a IL = inspection level n = sample size c = permissible number of non-conforming items ^b The inspection shall be performed after removal of nonconforming items by 100 % testing during the manufacturing process. Whether the lot was accepted or not, all samples for sampling inspection shall be inspected in order to monitor outgoing quality level by nonconforming items per million ($\times 10^{-6}$). The sampling level shall be established by the manufacturer and should be in accordance with IEC 61193-2:2007, Annex A. In the case where one or more nonconforming items occur in a sample, this lot shall be rejected, but all non-conforming items shall be counted for the calculation of quality level values. Outgoing quality level by non-conforming items per million ($\times 10^{-6}$) values shall be calculated by accumulating inspection data in accordance with the method given in IEC 61193-2:2007, 6.2. ^c Number to be tested: Sample size shall be determined in accordance with IEC 61193-2:2007, 4.3.2. ^d The content of the inspection subgroup is described in Table C.3.			

Table C.2 – Periodic inspection

Inspection subgroup ^b	EZ		
	p^a	n^a	c^a
C1	3	12	0
C2	3	12	0
C3.1	6	27	0
C3.2	6	15	0
C3.3	3	15	0
C3.4 ^c	6	15	0
C4	6	9	0
^a p = periodicity in months n = sample size c = permissible number of non-conforming items ^b The content of the inspection subgroup is described in Table C.4. ^c If required.			

C.5 Test schedule for quality conformance inspection

For quality conformance inspection, the test schedules given in Table C.3 and Table C.4 include sampling, periodicity, severities and requirements. The formation of inspection lots is given in Clause C.1.

Table C.3 – Test schedule for quality conformance inspection (lot by lot)

Test ^a		Lot-by-lot tests Conditions of test ^b		D ^c or ND	IL ^c	c ^c	Performance requirements
Group A0 [100 % tests]				ND	100 % ^d		
5.6.1	Capacitance	Frequency: ... Hz Measuring voltage: ... V r.m.s	Within specified tolerance				
5.6.2	Tangent of loss angle (tan δ)	Frequency and measuring voltage same as in 5.6.1	As in 5.6.2				
5.6.3	Insulation resistance	See detail specification for the method	As in 5.6.3.4				
5.6.4	Voltage proof	See detail specification for the method	No breakdown or flashover				
Group A1 [Sampling tests]				ND	S-4 ^e		
5.5.2	Visual examination		As in 5.5.2 Legible marking and as specified in the detail specification				
Group A2 [Sampling tests]				ND	S-3 ^e		
4.2.6	Dimension ^f		See the detail specification				
Group B1 [Special tests]				D	S-3 ^e		
5.11	Solderability	See detail specification for the method					
5.11.4	Final inspection, measurements and requirements	Visual examination	As in 5.11.4				
5.18	Solvent resistance of the marking (if required) ^g	Solvent: ... Solvent temperature: ... Method 1 Rubbing material: cotton wool Recovery: ...	Legible marking				
Group B2 [Special tests]				ND	S-2 ^e		
5.7	Temperature coefficient (α) and cyclic drift ^h		ΔC/C: As in 5.7.3				

^a Applicable tests, test conditions, requirements and clause numbers as selected from this document.

^b The information given in Table C.3 shall provide a suitable overview of the most relevant parameters of each test, however shall not take precedence over any more detailed specification given in a respective clause of this specification or in a cited normative reference.

^c Refer to Table C.1 for lists of symbols and of abbreviated terms.

^d After 100 % measurement and removal of nonconforming items, a re-inspection shall be performed in order to monitor the outgoing quality level, in accordance with the detail specification. A lot shall be rejected if one or more non-conforming items occur in a sample during re-inspection.

^e Inspection levels are selected from IEC 611932-2:2007.

^f This test may be replaced by in-production testing if the manufacturer installs statistical process control (SPC) on dimensional measurements or other mechanisms to avoid parts exceeding the limits.

^g This test may be carried out on capacitors mounted on a substrate.

^h This subgroup may be omitted if a corresponding test is carried out on each manufacturing batch of dielectric material.

Table C.4 – Test schedule for quality conformance inspection (Periodic test)

Periodic tests							
Test ^a		Conditions of test ^b	D ^c or ND	p ^c	n ^c	c ^c	Performance requirements
Group C1 ^h			D	3	12	0 ^d	No visible damage
5.16	Robustness of Termination (only for capacitors with strip terminations)	Test Ua, Force: 2,5 N Test Ub, Method 1, Force: 2,5 N Number of bends: 1 Visual examination					
5.10.2	Initial measurement	Capacitance					
5.10	Resistance to soldering heat	See detail specification for the method Recovery: 6 h to 24 h					
5.10.5	Final inspection, measurements and requirements	Visual examination Capacitance					
5.17	Component solvent resistance (if required)	Solvent: ... Solvent temperature: ... Method 2 Recovery: ...					As in 5.10.5 As in 5.10.5 See detail specification
Group C2 ^h			D	3	12	0 ^d	See detail specification $\Delta C/C \leq 5\%$ No visible damage
5.9	Substrate bending test ^e	Deflection: ... Number of bends: ...					
5.9.2	Initial measurement	Capacitance					
5.9.3	Final inspection	Capacitance (with printed board in bent position) Visual examination					
Group C3 ^h			D				As in 5.5.3 Within specified tolerance As in 5.6.2.3 As in 5.6.3.4 No breakdown or flashover
5.4	Mounting ^f	Substrate material: ...					
		Visual examination					
		Capacitance					
		Tangent of loss angle					
		Insulation resistance					
		Voltage proof					

Periodic tests								
Test ^a		Conditions of test ^b	D ^c or ND	p ^c	n ^c	c ^c	Performance requirements	
Group C3.1 ^h			D	6	27	0 ^d		
5.8	Shear test ^g	Visual inspection					No visible damage	
5.12.2	Initial measurement	Capacitance						
5.12	Rapid change of temperature	T _A = Lower category temperature T _B = Upper category temperature: five cycles Duration t ₁ = 30 min Recovery: 6 h to 24 h						
5.12.5	Final inspections, measurements and requirements	Visual examination						No visible damage
		Capacitance					ΔC/C: As in 5.12.5	
5.13.2	Initial measurement	Capacitance						
5.13.3	Dry heat	Temperature: upper category temperature Duration: 16 h						
5.13.4	Damp heat, cyclic, test Db, first cycle							
5.13.5	Cold	Temperature: lower category temperature Duration: 2 h Visual inspection						No visible damage
5.13.6	Damp heat, cyclic, test Db, remaining cycles	Recovery: 6 h to 24 h						No visible damage, Legible marking
5.13.7	Final inspections, measurements and requirements	Visual examination						ΔC/C: As in 5.13.7
		Capacitance						As in 5.13.7
		Tangent of loss angle						As in 5.13.7
		Insulation resistance						
Group C3.2 ^h							D	6
5.14	Damp heat, steady state							
5.14.2	Initial measurement	Capacitance Recovery: 6 h to 24 h						
5.14.5	Final inspections, measurements and requirements	Visual examination	No visible damage, Legible marking					
		Capacitance Tangent of loss angle Insulation resistance	ΔC/C: As in 5.14.5 As in 5.14.5 As in 5.14.5					

Periodic tests							
Test ^a		Conditions of test ^b	D ^c or ND	p ^c	n ^c	c ^c	Performance requirements
Group C3.3 ^h			D				No visible damage. Legible marking ΔC/C: As in 5.15.5 As in 5.15.5 As in 5.15.5
5.15	Endurance	Duration: ...h Temperature: ...°C Voltage: ...V		3	15	0 ^d	
5.15.2	Initial measurement	Capacitance Recovery: 6 h to 24 h					
5.15.5	Final inspections, measurements and requirements	Visual examination Capacitance Tangent of loss angle Insulation resistance					
Group C3.4 ^h			D				As in 5.19.2 As in 5.19.5
5.19	Accelerated damp heat, steady state (if required)	Duration: ... h Temperature: (85 ± 2) °C Humidity: (85 ± 3) %		6	15	0 ^d	
5.19.2	Initial measurement	Insulation resistance Recovery: 6 h to 24 h					
5.19.5	Final measurements	Insulation resistance					As in 5.19.5
Group C4 ^h			ND				ΔC/C: As in 5.7.3
5.7	Temperature coefficient (α) and cyclic drift	Preliminary drying: 16 h to 24 h		6	9	0 ^d	

^a Applicable tests, test conditions, requirements and clause numbers as selected from this document.

^b The information given in Table C.4 shall provide a suitable overview of the most relevant parameters of each test, however shall not take precedence over any more detailed specification given in a respective clause of this specification or in a cited normative reference.

^c Refer to Table C.2 for lists of symbols and of abbreviated terms.

^d If one non-conforming item is obtained, all the tests of the subgroup shall be repeated on a new sample and then no further non-conforming items are permitted. Release of product may continue during repeat testing.

^e Not applicable to capacitors, which, in accordance with the detail specification, shall only be mounted on alumina substrates.

^f The capacitors found non-conformances after mounting shall not be taken into account when calculating the non- conformances for the following tests. They shall be replaced by spare capacitors.

^g Not applicable to capacitors with strip terminations

^h All tests of the sub-group shall be repeated if one or more nonconforming item is obtained. No non-conforming items are permitted in the repeat testing. Release of products may continue during repeat testing.

Annex X (informative)

Cross-reference for reference to IEC 60384-21:2019

The drafting of this document has resulted in a new structure. Table X.1 indicates the new clause and subclause numbers with respect to IEC 60384-21:2019.

Table X.1 – Reference to IEC 60384-21 for clause/annex

IEC 60384-21:2019 3 rd edition Clause/Annex	IEC 60384-21:2024 4 th edition Clause/Annex	Notes
1	1	No change
2	2	No change
3	3	No change
4	7	In accordance with the change of clause numbers
5	6	In accordance with the change of clause numbers
6	4	In accordance with the change of clause numbers
7.1 to 7.4	8.1 to 8.4	In accordance with the change of clause numbers
7.5.1 to 7.5.4	C.1 to C.4	In accordance with the change of clause numbers
8	5	In accordance with the change of clause numbers
Annex A	Annex A	No change
Annex B	Annex B	Changed from informative to normative
—	C.5	Newly added. Modified from IEC 60384-21-1:2004, Clause 2
Annex X	Annex X	No change

Table X.2 indicates the new figure and table numbers with respect to IEC 60384-21:2019.

Table X.2 – Reference to IEC 60384-21 for figure/table

IEC 60384-21:2019 3 rd edition Figure/Table	IEC 60384-21:20xx 4 th edition Figure/Table	Notes
Table 1 to Table 3	Table 1 to Table 3	No change
Table 4 and table 5	Table 19 and Table 20	In accordance with the change of table numbers
Table 6 and Table 7	Table C.1 and Table C.2	In accordance with the change of table numbers
-	Table C.3 and Table C.4	Newly added. Modified from IEC 60384-21-1:2004, Table 4
Table 8 to Table 22	Table 4 to Table 18	In accordance with the change of table numbers
Table A.1	Table A.1	No change
Table B.1	Table B.1	Updated
Table X.1 and Table X.2	Table X.1 and Table X.2	No change
For the figure numbers, there was no change.		

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SOMMAIRE

AVANT-PROPOS	52
1 Domaine d'application	54
2 Références normatives	54
3 Termes et définitions	55
4 Valeurs assignées et caractéristiques préférentielles	56
4.1 Caractéristiques préférentielles	56
4.2 Valeurs assignées préférentielles	56
4.2.1 Température assignée (T_R)	56
4.2.2 Tension assignée (U_R)	56
4.2.3 Tension de catégorie (U_C)	57
4.2.4 Valeurs préférentielles de la capacité nominale et des valeurs de tolérance associées	57
4.2.5 Coefficient de température (α)	57
4.2.6 Dimensions	59
5 Procédures d'essai et de mesure	59
5.1 Généralités	59
5.2 Séchage préliminaire	60
5.3 Conditions de mesure	60
5.4 Montage	60
5.5 Examen visuel et contrôle des dimensions	60
5.5.1 Généralités	60
5.5.2 Examen visuel	60
5.5.3 Exigences	60
5.6 Essais électriques	62
5.6.1 Capacité	62
5.6.2 Tangente de l'angle de perte ($\tan \delta$)	62
5.6.3 Résistance d'isolement	63
5.6.4 Tenue en tension	64
5.7 Coefficient de température (α) et dérive après cycle thermique	64
5.7.1 Généralités	64
5.7.2 Séchage préliminaire	65
5.7.3 Conditions de mesure	65
5.7.4 Exigences	65
5.8 Essai de cisaillement	65
5.9 Essai de pliage du substrat	65
5.9.1 Généralités	65
5.9.2 Mesure initiale	66
5.9.3 Contrôle final	66
5.10 Résistance à la chaleur de brasage	66
5.10.1 Généralités	66
5.10.2 Mesure initiale	66
5.10.3 Conditions d'essai	66
5.10.4 Rétablissement	67
5.10.5 Inspection finale, mesures et exigences	67
5.11 Brasabilité	68
5.11.1 Généralités	68

5.11.2	Conditions d'essai	68
5.11.3	Rétablissement.....	69
5.11.4	Inspection finale, mesures et exigences.....	69
5.12	Variations rapides de température	69
5.12.1	Généralités	69
5.12.2	Mesure initiale	69
5.12.3	Nombre de cycles	69
5.12.4	Rétablissement.....	69
5.12.5	Inspection finale, mesures et exigences.....	69
5.13	Séquence climatique.....	70
5.13.1	Généralités	70
5.13.2	Mesure initiale	70
5.13.3	Chaleur sèche	70
5.13.4	Chaleur humide, cyclique, essai Db, premier cycle	70
5.13.5	Froid.....	70
5.13.6	Chaleur humide, cyclique, essai Db, cycles restants	70
5.13.7	Inspection finale, mesures et exigences.....	70
5.14	Chaleur humide, essai continu	71
5.14.1	Généralités	71
5.14.2	Mesure initiale	71
5.14.3	Conditions d'essai	71
5.14.4	Rétablissement.....	72
5.14.5	Inspection finale, mesures et exigences.....	72
5.15	Endurance	72
5.15.1	Généralités	72
5.15.2	Mesure initiale	72
5.15.3	Conditions d'essai	72
5.15.4	Rétablissement.....	73
5.15.5	Inspection finale, mesures et exigences.....	73
5.16	Robustesse des sorties (uniquement pour les condensateurs avec sorties à lamelle).....	74
5.16.1	Généralités	74
5.16.2	Conditions d'essai	74
5.16.3	Inspection finale et exigences.....	74
5.17	Résistance du composant aux solvants (si cela est exigé)	74
5.18	Résistance au solvant du marquage (si cela est exigé)	74
5.19	Chaleur humide, essai continu accéléré (si cela est exigé).....	74
5.19.1	Généralités	74
5.19.2	Mesure initiale	74
5.19.3	Conditionnement	75
5.19.4	Rétablissement.....	75
5.19.5	Mesures finales	75
6	Marquage	75
6.1	Généralités	75
6.2	Informations pour le marquage.....	76
6.3	Marquage sur le corps	76
6.4	Exigences relatives au marquage.....	76
6.5	Marquage de l'emballage	76
6.6	Marquage supplémentaire.....	76

7	Informations à spécifier dans une spécification particulière.....	76
7.1	Généralités	76
7.2	Dessin d'encombrement et dimensions	77
7.3	Montage.....	77
7.4	Valeurs assignées et caractéristiques	77
7.4.1	Généralités	77
7.4.2	Gamme de capacités nominales	77
7.4.3	Caractéristiques particulières	77
7.4.4	Brasure.....	77
7.5	Marquage	77
8	Procédures d'assurance de la qualité	78
8.1	Étape initiale de fabrication.....	78
8.2	Modèles associables.....	78
8.3	Enregistrements certifiés de lots livrés	78
8.4	Homologation.....	78
8.4.1	Généralités	78
8.4.2	Homologation fondée sur les procédures avec un effectif d'échantillons fixe	78
8.4.3	Essais	79
	Annexe A (normative) Recommandations pour la spécification et le codage des dimensions des condensateurs multicouches fixes à diélectriques en céramique pour montage en surface, Classe 1.....	84
	Annexe B (normative) Combinaison de coefficients de température et de tolérances pour la température de référence de 25 °C	85
	Annexe C (normative) Contrôle de conformité de la qualité	86
C.1	Constitution des lots de contrôle	86
C.1.1	Inspection des Groupes A et B	86
C.1.2	Inspection du groupe C	86
C.2	Programme d'essais	86
C.3	Livraison différée	86
C.4	Niveaux d'assurance.....	86
C.5	Programme d'essais pour les contrôles de conformité de la qualité.....	87
	Annexe X (informative) Références croisées pour référence à l'IEC 60384-21:2019	93
	Bibliographie.....	94
	Figure 1 – Défaut: craquelure ou fissure	60
	Figure 2 – Défaut: craquelure ou fissure	61
	Figure 3 – Séparation ou décollement interlaminaire.....	61
	Figure 4 – Électrodes exposées	61
	Figure 5 – Faces principales	62
	Figure 6 – Profil de température de refusion	67
	Figure A.1 – Dimensions	84
	Tableau 1 – Tolérances préférentielles sur la capacité nominale.....	57
	Tableau 2 – Coefficient de température nominal et tolérance (pour température de référence 20 °C)	58

Tableau 3 – Combinaisons de coefficient de température et de tolérance	58
Tableau 4 – Limites de la tangente de l'angle de perte	63
Tableau 5 – Tensions d'essai.....	64
Tableau 6 – Limites de dérive après cycle thermique	65
Tableau 7 – Profils de température de refusion pour alliage Sn-Ag-Cu.....	67
Tableau 8 – Variation maximale de capacité	68
Tableau 9 – Variation maximale de capacité	69
Tableau 10 – Nombre de cycles de chaleur humide	70
Tableau 11 – Exigences, mesures et contrôle final	71
Tableau 12 – Conditions d'essai continu de chaleur humide	71
Tableau 13 – Exigences, mesures et contrôle final	72
Tableau 14 – Conditions d'essai d'endurance ($U_C = U_R$).....	73
Tableau 15 – Conditions d'essai d'endurance ($U_C \neq U_R$).....	73
Tableau 16 – Exigences, mesures et contrôle final	73
Tableau 17 – Exigences initiales.....	75
Tableau 18 – Conditionnement	75
Tableau 19 – Plan d'essais avec un nombre d'échantillons fixe pour homologation Niveau d'assurance EZ	80
Tableau 20 – Programme d'essais pour l'homologation.....	81
Tableau A.1 – Dimensions	84
Tableau B.1 – Combinaison de coefficients de température et de tolérances pour la température de référence de 25 °C	85
Tableau C.1 – Contrôle lot par lot	87
Tableau C.2 – Contrôle périodique.....	87
Tableau C.3 – Programme d'essais pour le contrôle de conformité de la qualité (lot par lot).....	88
Tableau C.4 – Programme d'essais pour le contrôle de conformité de la qualité (essai périodique)	89
Tableau X.1 – Référence à l'article/annexe de l'IEC 60384-21	93
Tableau X.2 – Référence à la figure/au tableau de l'IEC 60384-21.....	93

COMMISSION ÉLECTROTECHNIQUE INTERNATIONALE

**CONDENSATEURS FIXES UTILISÉS
DANS LES ÉQUIPEMENTS ÉLECTRONIQUES –****Partie 21: Spécification intermédiaire – Condensateurs multicouches fixes
à diélectriques en céramique pour montage en surface, de Classe 1****AVANT-PROPOS**

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L'IEC 60384-21 a été établie par le comité d'études 40 de l'IEC: Condensateurs et résistances pour équipements électroniques. Il s'agit d'une Norme internationale.

Cette quatrième édition annule et remplace la troisième édition parue en 2019. Cette édition constitue une révision technique.

Cette édition inclut les modifications techniques majeures suivantes par rapport à l'édition précédente:

- a) le document a été entièrement restructuré pour se conformer aux directives ISO/IEC, Partie 2, et pour en faciliter l'utilisation; les tableaux, les figures et les références ont été révisés en conséquence; l'Annexe X comporte toutes les références croisées des changements de numérotation des articles/paragraphes;
- b) les termes ont été remplacés par des symboles littéraux dans le Tableau 3;
- c) le codage de coefficient de température et tolérance de C0G et U2J a été ajouté dans le Tableau 4, le Tableau 6, le Tableau 8, le Tableau 9, le Tableau 11, le Tableau 13, le Tableau 16 et à l'Annexe B;
- d) l'exigence de 5.5.2 (examen visuel) a été répétée en 5.9.3, en 5.10.5, en 5.11.4, en 5.11.4, en 5.13.7, en 5.14.5 et en 5.15.5;
- e) la flèche D dans les modèles très robustes a été ajoutée en 5.9.1;
- f) l'Annexe B est passée d'informatrice à normative;
- g) l'Article C.5 (Programme d'essais pour le contrôle de conformité de la qualité) a été ajouté pour retirer la spécification particulière-cadre: IEC 60384-21-1.

Le texte de cette Norme internationale est issu des documents suivants:

Projet	Rapport de vote
40/3119/FDIS	40/3138/RVD

Le rapport de vote indiqué dans le tableau ci-dessus donne toute information sur le vote ayant abouti à son approbation.

La langue employée pour l'élaboration de cette Norme internationale est l'anglais.

Ce document a été rédigé selon les Directives ISO/IEC, Partie 2, il a été développé selon les Directives ISO/IEC, Partie 1 et les Directives ISO/IEC, Supplément IEC, disponibles sous www.iec.ch/members_experts/refdocs. Les principaux types de documents développés par l'IEC sont décrits plus en détail sous www.iec.ch/publications.

Une liste de toutes les parties de la série IEC 60384, publiées sous le titre général *Condensateurs fixes utilisés dans les équipements électroniques*, se trouve sur le site Web de l'IEC.

Le comité a décidé que le contenu de ce document ne sera pas modifié avant la date de stabilité indiquée sur le site Web de l'IEC sous webstore.iec.ch dans les données relatives au document recherché. A cette date, le document sera:

- reconduit,
- supprimé, ou
- révisé.

CONDENSATEURS FIXES UTILISÉS DANS LES ÉQUIPEMENTS ÉLECTRONIQUES –

Partie 21: Spécification intermédiaire – Condensateurs multicouches fixes à diélectriques en céramique pour montage en surface, de Classe 1

1 Domaine d'application

La présente partie de l'IEC 60384 s'applique aux condensateurs multicouches fixes à diélectriques en céramique pour montage en surface non encapsulés, avec un coefficient de température défini (diélectrique de Classe 1), destinés à être utilisés dans les équipements électroniques. Ces condensateurs possèdent des pastilles de connexion métallisées ou des bandes de brasure et sont destinés à être montés sur des cartes imprimées ou directement sur des substrats de circuits hybrides.

Les condensateurs d'antiparasitage ne sont pas inclus, mais sont couverts par l'IEC 60384-14.

Le présent document a pour objet de spécifier les valeurs assignées et caractéristiques préférentielles, de sélectionner, en se référant à l'IEC 60384-1:2021, les procédures d'assurance qualité appropriées, les essais et les méthodes de mesure et de donner les exigences de performances générales pour ce type de condensateur. Les sévérités et les exigences des essais spécifiées dans les spécifications particulières se référant au présent document fournissent des sévérités et des exigences d'essai d'un niveau de performance supérieur ou égal. Pour plus d'informations sur la conception des spécifications génériques, intermédiaires et particulières, voir l'Introduction de l'IEC 60384-1:2021.

2 Références normatives

Les documents suivants sont cités dans le texte de sorte qu'ils constituent, pour tout ou partie de leur contenu, des exigences du présent document. Pour les références datées, seule l'édition citée s'applique. Pour les références non datées, la dernière édition du document de référence s'applique (y compris les éventuels amendements).

IEC 60068-2-58, *Essais d'environnement – Partie 2-58: Essais – Essai Td: Méthodes d'essai de la soudabilité, résistance de la métallisation à la dissolution et résistance à la chaleur de brasage des composants pour montage en surface (CMS)*

IEC 60384-1:2021, *Condensateurs fixes utilisés dans les équipements électroniques – Partie 1: Spécification générique*

IEC 61193-2:2007, *Quality assessment systems – Part 2: Selection and use of sampling plans for inspection of electronic components and packages* (disponible en anglais seulement)

3 Termes et définitions

Pour les besoins du présent document, les termes et les définitions de l'IEC 60384-1:2021 ainsi que les suivants s'appliquent.

L'ISO et l'IEC tiennent à jour des bases de données terminologiques destinées à être utilisées en normalisation, consultables aux adresses suivantes:

- IEC Electropedia: disponible à l'adresse <https://www.electropedia.org/>
- ISO Online browsing platform: disponible à l'adresse <https://www.iso.org/obp>

3.1

condensateur multicouche pour montage en surface

condensateur multicouche dont les petites dimensions et la nature ou la forme des connexions de sortie en font un condensateur pouvant être monté en surface dans des circuits hybrides et sur des cartes imprimées

3.2

condensateur à diélectrique en céramique, Classe 1

condensateur spécialement conçu et adapté à une application de circuit résonant où de faibles pertes et une grande stabilité de capacité sont essentielles ou lorsqu'un coefficient de température défini avec précision est exigé, par exemple pour compenser les effets de la température dans le circuit

Note 1 à l'article: Le diélectrique en céramique est défini par son coefficient de température nominale (α).

3.3

sous-classe

<Classe 1> tolérance sur le coefficient de température pour un coefficient de température nominale donné

Note 1 à l'article: Voir Tableau 2.

Note 2 à l'article: La valeur du coefficient de température nominale et sa tolérance font référence à l'intervalle de températures comprises entre +20 °C ou +25 °C et +85 °C, mais en raison du fait qu'en pratique, les courbes de TC (coefficient de température) ne sont pas strictement linéaires, il est nécessaire de définir l'écart de capacité limite ($\Delta C/C$) pour d'autres températures (voir Tableau 3 et Annexe B).

3.4

plage de températures

plage des températures ambiantes pour laquelle le condensateur a été conçu pour fonctionner de manière continue

Note 1 à l'article: Cette plage est donnée par la température minimale de catégorie et la température maximale de catégorie. (voir Tableau 3 et Annexe B)

3.5

température assignée

T_R

température ambiante maximale à laquelle la tension assignée peut être appliquée de manière continue

3.6

tension assignée

U_R

tension en courant continu maximale qui peut être appliquée de manière continue à un condensateur à n'importe quelle température entre la température minimale de catégorie et la température assignée

Note 1 à l'article: La tension en courant continu maximale est la somme de la tension en courant continu et de la valeur de crête de la tension alternative ou de la valeur de crête de la tension d'impulsion appliquées au condensateur.

3.7

tension de catégorie

U_C

tension maximale pouvant être appliquée de manière continue à un condensateur à sa température maximale de catégorie

4 Valeurs assignées et caractéristiques préférentielles

4.1 Caractéristiques préférentielles

Les catégories climatiques préférentielles doivent être données uniquement dans les caractéristiques préférentielles.

Les condensateurs couverts par le présent document sont classés en catégories climatiques conformément aux règles générales données dans l'IEC 60068-1:2013, Annexe A.

Pour une température de référence de 20 °C ou 25 °C, les températures minimale et maximale de catégorie et la durée de l'essai continu de chaleur humide doivent être sélectionnées dans la liste ci-dessous:

- température minimale de catégorie: –55 °C, –40 °C, –25 °C, –10 °C et +10 °C;
- température maximale de catégorie: +70 °C, +85 °C, +100 °C, +125 °C;
- durée de l'essai continu de chaleur humide (température = 40 °C, humidité relative = 93 %): 4, 10, 21 et 56 jours.

Les sévérités pour les essais de froid et de chaleur sèche sont les températures minimale et maximale de catégorie respectivement.

NOTE La résistance à l'humidité résultant de la catégorie climatique ci-dessus concerne les condensateurs dans l'état non monté. La performance climatique des condensateurs après montage dépend considérablement du substrat de montage, de la méthode de montage (voir 5.4) et du revêtement final.

4.2 Valeurs assignées préférentielles

4.2.1 Température assignée (T_R)

Pour les condensateurs couverts par le présent document, la température assignée est égale à la température maximale de catégorie, à moins que la température maximale de catégorie ne dépasse 125 °C.

4.2.2 Tension assignée (U_R)

Les valeurs préférentielles de la tension assignée sont les valeurs de la série R5 de l'ISO 3. Si d'autres valeurs sont nécessaires, elles doivent être choisies dans la série R10.

La somme de la tension en courant continu et de la plus grande parmi la valeur de crête de la tension alternative et la valeur crête à crête de la tension alternative, appliquée au condensateur ne doit pas dépasser la tension assignée.

4.2.3 Tension de catégorie (U_C)

Lorsque la température assignée est définie comme la température maximale de catégorie, la tension de la catégorie est égale à la tension assignée, telle qu'elle est définie dans l'IEC 60384-1:2021, 3.5. Si la température maximale de catégorie dépasse 125 °C, ou les tensions assignées dépassent 500 V, la tension de catégorie doit être fournie dans la spécification particulière.

4.2.4 Valeurs préférentielles de la capacité nominale et des valeurs de tolérance associées

4.2.4.1 Valeurs préférentielles de la capacité nominale

Il convient que les valeurs de capacité nominale proviennent des séries E6, E12 et E24 données dans l'IEC 60063.

4.2.4.2 Tolérances préférentielles sur la capacité nominale

Voir Tableau 1.

Tableau 1 – Tolérances préférentielles sur la capacité nominale

Série préférentielle	Tolérance			
	$C_N \geq 10 \text{ pF}$	Lettre de codage	$C_N < 10 \text{ pF}$	Lettre de codage
E6	$\pm 20 \%$	M	$\pm 2 \text{ pF}$	G
E12	$\pm 10 \%$	K	$\pm 1 \text{ pF}$	F
E24	$\pm 5 \%$	J	$\pm 0,5 \text{ pF}$	D
	$\pm 2 \%$	G	$\pm 0,25 \text{ pF}$	C
	$\pm 1 \%$	F	$\pm 0,1 \text{ pF}$	B

4.2.5 Coefficient de température (α)

4.2.5.1 Coefficient de température nominale et tolérance (pour la température de référence 20 °C)

Le Tableau 2 représente les coefficients de température nominale pour la température de référence de 20 °C et les tolérances associées, exprimées en millionnièmes par Kelvin ($10^{-6}/K$), ainsi que les sous-classes et lettres de codage correspondantes. Les coefficients de température, tolérances et lettres de codage pour la température de référence 25 °C sont donnés à l'Annexe B.

La spécification particulière doit indiquer pour chaque coefficient de température, la valeur minimale de la capacité pour laquelle la tolérance donnée du coefficient de température peut être vérifiée, en tenant compte de la précision des méthodes de mesure de capacité spécifiées.

Pour des valeurs de capacité inférieures à cette valeur minimale:

- la spécification particulière doit spécifier un facteur de multiplication de la tolérance sur α , ainsi que les variations admissibles de capacité à la température maximale et minimale de catégorie;
- des méthodes spéciales de mesure peuvent être nécessaires et, si cela est exigé, doivent être indiquées dans la spécification particulière.

**Tableau 2 – Coefficient de température nominal et tolérance
(pour température de référence 20 °C)**

Coefficient de température nominale ($10^{-6}/K$)	Tolérance sur le coefficient de température ($10^{-6}/K$)	Sous-classe	Lettre de codage pour	
			α	Tolérance
+100	± 30	1B	A	G
0	± 30	1B	C	G
-33	± 30	1B	H	G
-75	± 30	1B	L	G
-150	± 30	1B	P	G
-220	± 30	1B	R	G
-330	± 60	1B	S	H
-470	± 60	1B	T	H
-750	± 120	1B	U	J
-1 000	± 250	1F	Q	K
-1 500	± 250	1F	V	K
$+140 \geq \alpha \geq -1\,000$	a	1C	SL	–

Les coefficients de température nominale et leurs tolérances sont définis à l'aide de la variation de capacité entre les températures 20 °C et 85 °C.

Un condensateur avec un coefficient de température de $0 \times 10^{-6}/K$ et une tolérance sur le coefficient de température de $\pm 30 \times 10^{-6}/K$ est conçu comme un condensateur CG (sous-classe 1B).

^a Cette valeur de coefficient de température n'est pas soumise à un contrôle puisqu'aucune limite sur la variation relative de capacité n'est spécifiée dans le Tableau 3.

4.2.5.2 Variation relative admissible de la capacité

Le Tableau 3 indique pour chaque combinaison de coefficient de température et de tolérance la variation relative admissible de la capacité exprimée en parties par millier aux températures de catégorie supérieure et inférieure. Ces coefficients de température et tolérances sont exprimés en millionnièmes par Kelvin ($10^{-6}/K$). Dans le cas de la température de référence de 25 °C, voir Tableau B.1 pour une explication de la variation relative admissible de la capacité.

Tableau 3 – Combinaisons de coefficient de température et de tolérance

		Variation relative admissible de capacité en parties par millier entre 20 °C et une température donnée							
		Température minimale de catégorie				Température maximale de catégorie			
α $10^{-6}/K$	Tolérance $10^{-6}/K$	-55 °C	-40 °C	-25 °C	-10 °C	+70 °C	+85 °C	+100 °C	+125 °C
+100	± 30 (G)	-9,75/ -3,71	-7,80/ -2,96	-5,85/ -2,22	-3,90/ -1,48	3,50/ 6,50	4,55/ 8,45	5,60/ 10,4	7,35/ 13,7
0	± 30 (G)	-2,25/ 5,45	-1,80/ 4,36	-1,35/ 3,27	-0,90/ 2,18	-1,50/ 1,50	-1,95/ 1,95	-2,40/ 2,40	-3,15/ 3,15
-33	± 30 (G)	0,225/ 8,47	0,180/ 6,77	0,135/ 5,08	0,090/ 3,39	-3,15/ -0,15	-4,10/ -0,195	-5,04/ -0,240	-6,62/ -0,32
-75	± 30 (G)	3,38/ 12,3	2,70/ 9,85	2,03/ 7,39	1,35/ 4,92	-5,25/ -2,25	-6,83/ -2,93	-8,40/ -3,60	-11,0/ -4,73
-150	± 30 (G)	9,00/ 19,2	7,20/ 15,3	5,40/ 11,5	3,60/ 7,67	-9,00/ -6,0	-11,7/ -7,80	-14,4/ -9,60	-18,9/ -12,6
-220	± 30 (G)	14,3/ 25,6	11,4/ 20,46	8,55/ 15,3	5,70/ 10,2	-12,5/ -9,50	-16,2/ -12,4	-20,0/ -15,2	-26,3/ -20,0

		Variation relative admissible de capacité en parties par millier entre 20 °C et une température donnée							
		Température minimale de catégorie				Température maximale de catégorie			
α 10 ⁻⁶ /K	Tolérance 10 ⁻⁶ /K	-55 °C	-40 °C	-25 °C	-10 °C	+70 °C	+85 °C	+100 °C	+125 °C
-330	±60 (H)	20,3/ 38,4	16,2/ 30,7	12,2/ 23,0	8,10/ 15,4	-19,5/ -13,5	-25,4/ -17,6	-31,2/ -21,6	-41,0/ -28,4
-470	±60 (H)	30,8/ 51,2	24,6/ 41,0	18,5/ 30,7	12,3/ 20,5	-26,5/ -20,5	-34,5/ -26,7	-42,4/ -32,8	-55,7/ -43,1
-750	±120 (J)	47,3/ 82,3	37,8/ 65,8	28,4/ 49,4	18,9/ 32,9	-43,5/ -31,5	-56,6/ -41,0	-69,6/ -50,4	-91,4/ -66,2
-1 000	±250 (K)	56,3/ 117	45,0/ 93,7	33,8/ 70,2	22,5/ 46,8	-62,5/ -37,5	-81,3/ -48,8	-100/ -60,0	-131/ -78,8
-1 500	±250 (K)	93,8/ 163	75,0/ 130	56,3/ 97,7	37,5/ 65,1	-87,5/ -62,5	-114/ -81,3	-140/ -100	-184/ -131

Lorsque la température maximale de catégorie dépasse 125 °C, les limites doivent être indiquées dans la spécification particulière.

Formules de calcul de la variation relative admissible de capacité:

Variation relative admissible de la plage de températures de 20 °C à la température maximale de catégorie:

$$\Delta C/C \left(10^{-3}\right) = (\alpha \pm |\delta|) \times (UCT - 20) / 1000 \quad (1)$$

Variation relative admissible de la plage de températures de 20 °C à la température minimale de catégorie:

a) Variation relative admissible inférieure de capacité de 20 °C à la température minimale de catégorie:

$$\Delta C/C \left(10^{-3}\right) = (\alpha \pm |\delta|) \times (LCT - 20) / 1000 \quad (2)$$

b) Variation relative admissible supérieure de capacité de 20 °C à la température minimale de catégorie:

$$\Delta C/C \left(10^{-3}\right) = [(-36) - (1,22 \times |\delta|) + (0,22 \times \alpha) + \alpha] \times (LCT - 20) / 1000 \quad (3)$$

α Coefficient de température

δ Tolérance de α

LCT Lower Category Temperature (température minimale de catégorie)

UCT Upper Category Temperature (température maximale de catégorie)

4.2.6 Dimensions

Les règles proposées pour la spécification et le codage des dimensions sont présentées à l'Annexe A.

Les dimensions spécifiques doivent être données dans la spécification particulière.

5 Procédures d'essai et de mesure

5.1 Généralités

Le présent Article 5 complète les informations de l'IEC 60384-1:2021, de l'Article 5 à l'Article 10.

5.2 Séchage préliminaire

Voir IEC 60384-1:2021, 5.3.

5.3 Conditions de mesure

Voir IEC 60384-1:2021, 5.2.1.

5.4 Montage

Voir IEC 60384-1:2021, 5.5.

5.5 Examen visuel et contrôle des dimensions

5.5.1 Généralités

Voir IEC 60384-1:2021, 7.1, avec les détails de 5.5.2 et 5.5.3.

5.5.2 Examen visuel

L'examen visuel doit être réalisé avec un équipement adapté offrant un grossissement d'environ 10×, un éclairage approprié du spécimen d'essai et le niveau de qualité exigé. Si le spécimen est composé de très petits composants, l'examen visuel peut être effectué avec un grossissement plus élevé.

Il convient que l'opérateur dispose d'équipements pour l'éclairage incident ou transmis, ainsi que d'équipements de mesure appropriés.

5.5.3 Exigences

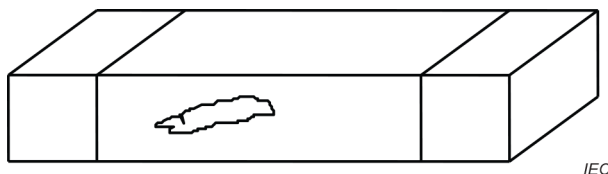
5.5.3.1 Généralités

Les valeurs quantitatives pour les exigences ci-dessous peuvent être données dans la spécification particulière ou dans la spécification du fabricant.

5.5.3.2 Exigences relatives à la céramique

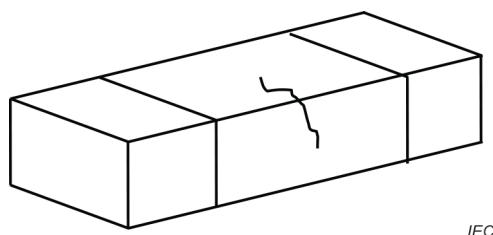
Les exigences relatives à la céramique sont les suivantes:

- a) être exempt de craquelures ou de fissures, à l'exception de dommages minimes en surface qui ne dégradent pas les performances du condensateur (exemples: voir Figure 1 et Figure 2);



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Figure 1 – Défaut: craquelure ou fissure

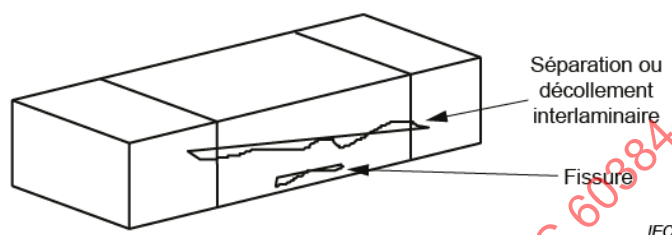


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NOTE Craquelure ou fissure sur un côté ou s'étendant d'une face à une autre en passant par une arête.

Figure 2 – Défaut: craquelure ou fissure

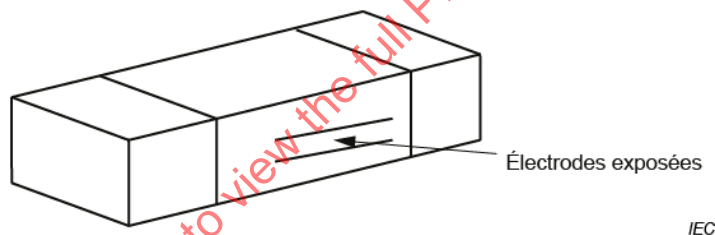
- b) ne pas présenter de séparation ou décollement interlaminaire visible entre les couches du condensateur (voir Figure 3);



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Figure 3 – Séparation ou décollement interlaminaire

- c) ne pas présenter d'électrodes exposées entre les deux sorties (voir Figure 4);



IEC

Figure 4 – Électrodes exposées

- d) le corps céramique doit être exempt de toute trace conductrice (métallisation, étamage, etc.) sur une zone centrale entre deux sorties adjacentes qui est égale à la distance minimale entre celles-ci (Annexe A, dimension L_4).

5.5.3.3 Exigences relatives à la métallisation

Les exigences relatives à la métallisation sont les suivantes:

- ne pas présenter de décollement visible des sorties métallisées ni d'électrodes exposées (voir Figure 4);
- les faces principales (voir Figure 5) sont celles notées A, B et C.

Dans le cas de condensateurs de section carrée, les faces D et E sont également considérées comme principales.

La surface maximale des espaces dans la métallisation sur chaque face principale ne doit pas dépasser 15 % de la surface de cette face et ces espaces ne doivent pas être concentrés dans la même région. Les espaces dans la métallisation ne doivent pas affecter les deux arêtes principales de chaque extrémité du bloc (ou les quatre arêtes dans le cas de condensateurs carrés). La dissolution du revêtement d'extrémité (lixiviation) ne doit pas dépasser 25 % de la longueur de l'arête concernée.

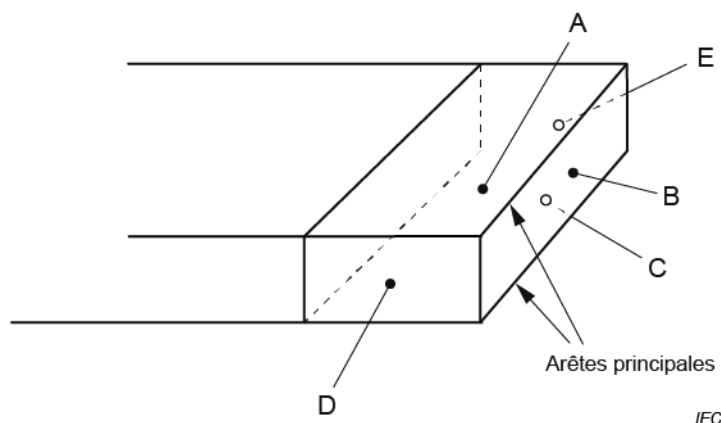


Figure 5 – Faces principales

5.6 Essais électriques

5.6.1 Capacité

5.6.1.1 Généralités

Voir IEC 60384-1:2021, 6.3, avec les détails de 5.6.1.2 et 5.6.1.3.

5.6.1.2 Conditions de mesure

Sauf indication contraire dans la spécification particulière,

- tension de mesure: ≤ 5 V eff.
- fréquence: $C_N \leq 1\,000$ pF 1 MHz ou 100 kHz (fréquence d'arbitrage 1 MHz);
 $C_N > 1\,000$ pF 1 kHz ou 100 kHz (fréquence d'arbitrage 1 kHz).

5.6.1.3 Exigences

La valeur de la capacité, telle que mesurée dans l'état non monté, doit correspondre à la valeur assignée en tenant compte de la tolérance spécifiée.

La capacité telle que mesurée dans l'état monté conformément au Groupe 3 est donnée uniquement à des fins de référence lors des essais ultérieurs.

5.6.2 Tangente de l'angle de perte ($\tan \delta$)

5.6.2.1 Généralités

Voir IEC 60384-1:2021, 6.4, avec les détails de 5.6.2.2 et 5.6.2.3.

5.6.2.2 Conditions de mesure

Les conditions de mesure sont les mêmes que celles de 5.6.1. L'imprécision de l'appareil de mesure ne doit pas dépasser 3×10^{-4} .

5.6.2.3 Exigences

La tangente de l'angle de perte, telle que mesurée dans l'état non monté, ne doit pas dépasser la limite donnée au Tableau 4.

Tableau 4 – Limites de la tangente de l'angle de perte

Capacité nominale pF	Tangente de l'angle de perte ($\tan \delta$) $\times 10^{-4}$		
	$+100 \geq \alpha > -750$ et SL (1C) C0G	$-750 \geq \alpha > -1\ 500$ U2J	$\alpha = -1\ 500$
$C_N \geq 50$	15	20	30
$5 \leq C_N < 50$	$1,5 \left(\frac{150}{C_N} + 7 \right)$	$2 \left(\frac{150}{C_N} + 7 \right)$	$3 \left(\frac{150}{C_N} + 7 \right)$
$C_N < 5$	Lorsque la mesure est exigée, la spécification particulière doit indiquer la limite.		

La tangente de l'angle de perte telle que mesurée dans l'état monté conformément au Groupe 3 est donnée uniquement à des fins de référence lors des essais ultérieurs.

5.6.3 Résistance d'isolement

5.6.3.1 Généralités

Voir IEC 60384-1:2021, 6.1, en l'associant aux informations données de 5.6.3.2 à 5.6.3.4.

5.6.3.2 Préparation de l'essai

Avant l'essai, les condensateurs doivent être nettoyés avec soin pour éliminer toute contamination.

Les chambres d'essai, comme les lieux dans lesquels s'effectuent les mesures après les essais, doivent être propres. Avant le mesurage, les condensateurs doivent être complètement déchargés. La résistance d'isolement doit être mesurée entre les sorties.

5.6.3.3 Conditions de mesure

Voir IEC 60384-1:2021, 6.1.2, avec les détails suivants:

La tension de mesure peut être d'une valeur quelconque inférieure ou égale à U_R , la tension d'arbitrage étant U_R , pour un condensateur dont la tension assignée est inférieure ou égale à 1 kV. Pour $U_R > 1$ kV, la tension d'arbitrage doit être de 1 kV.

La résistance d'isolement (R_i) doit être mesurée après avoir appliqué la tension pendant (60 ± 5) s.

Pour les essais lot par lot (Groupe A), l'essai peut durer moins longtemps, si la valeur de la résistance d'isolement exigée est atteinte.

Le produit de la résistance interne de la source de tension et de la capacité nominale du condensateur ne doit pas dépasser 1 s, sauf indication contraire dans la spécification particulière.

Le courant de charge ne doit pas dépasser 0,05 A. Pour les condensateurs dont les tensions assignées sont supérieures ou égales à 1 kV, une (valeur) limite inférieure peut être donnée dans la spécification particulière.

5.6.3.4 Exigences

La résistance d'isolement doit satisfaire aux exigences suivantes.

$C_N \leq 10 \text{ nF}$	$R_i \geq 10\,000 \text{ M}\Omega$
$C_N > 10 \text{ nF}$	$R_i \times C_N \geq 100 \text{ s}$

5.6.4 Tenue en tension

5.6.4.1 Généralités

Voir IEC 60384-1:2021, 6.2, en l'associant aux informations données de 5.6.4.2 à 5.6.4.4.

5.6.4.2 Conditions d'essai

Le produit de R_1 et de la capacité nominale C_X doit être inférieur ou égal à 1 s.

NOTE R_1 est une résistance de charge qui comprend la résistance interne de la source de tension. Ces informations peuvent être consultées dans l'IEC 60384-1:2021, 6.2.2.

Le courant de charge ne doit pas dépasser 0,05 A.

Pour les condensateurs dont les tensions assignées sont supérieures ou égales à 1 kV, une limite de courant de charge inférieure peut être donnée dans la spécification particulière. Pour protéger les condensateurs contre l'amorçage, l'essai peut être réalisé dans un milieu isolant adapté.

5.6.4.3 Tensions d'essai

Des tensions d'essai conformes au Tableau 5 doivent être appliquées entre les points de mesures de 5.6.3 et du Tableau 3 de l'IEC 60384-1:2021, pendant une durée de 1 min pour les essais d'homologation et pendant une durée de 1 s pour les essais de conformité de la qualité lot par lot.

Tableau 5 – Tensions d'essai

Tension assignée V	Tension d'essai V
$U_R \leq 100$	$2,5 U_R$
$100 < U_R \leq 200$	$1,5 U_R + 100$
$200 < U_R \leq 500$	$1,3 U_R + 100$
$500 < U_R < 1\,000$	$1,3 U_R$
$U_R \geq 1\,000$	$1,2 U_R$

5.6.4.4 Exigence

Aucun claquage ni contournement électrique ne doit être constaté pendant l'essai.

5.7 Coefficient de température (α) et dérive après cycle thermique

5.7.1 Généralités

Voir IEC 60384-1:2021, 6.8.3.3, avec les détails de 5.7.2 et 5.7.4.

5.7.2 Séchage préliminaire

Les condensateurs doivent être séchés conformément à 5.2 pendant une durée de 16 h à 24 h.

5.7.3 Conditions de mesure

Voir l'IEC 60384-1:2021, 6.8.1.2 et 6.8.1.3, avec les détails suivants.

Les condensateurs doivent être mesurés dans l'état non monté.

5.7.4 Exigences

L'écart de capacité aux températures maximale et minimale de catégorie (ainsi qu'aux autres températures qui peuvent être indiquées dans la spécification particulière) ne doit pas dépasser les limites données au Tableau 3.

La dérive après cycle thermique ne doit pas dépasser les limites données dans le Tableau 6.

Tableau 6 – Limites de dérive après cycle thermique

α assignées en $10^{-6}/K$	Exigences ^a
+100 $\geq \alpha > -150$ C0G	0,3 % ou 0,05 pF
-150 $\geq \alpha > -1\ 500$ et SL (1C) U2J	1 % ou 0,05 pF
$\alpha = -1\ 500$	2 % ou 0,05 pF
^a La plus grande des valeurs.	

5.8 Essai de cisaillement

Voir IEC 60384-1:2021, 7.7.

Une force doit être choisie parmi 1 N, 2 N, 5 N et 10 N et indiquée dans la spécification particulière.

5.9 Essai de pliage du substrat

5.9.1 Généralités

Voir IEC 60384-1:2021, 7.8.

Sauf indication contraire dans la spécification particulière,

- la flèche D doit être choisie entre 1 mm, 2 mm ou 3 mm, des valeurs de flèche plus élevées peuvent être données dans la spécification particulière dans le cas de conceptions très robustes;
- le nombre de courbures doit être égal à 1;
- le rayon de l'outil de courbure doit être égal à 5 mm.
Lorsque la flèche D est inférieure ou égale à 2 mm, le rayon peut être égal à 230 mm;
- la durée dans l'état courbé doit être de 5 s.

Pour la dimension 1005M ou une dimension inférieure, il convient que l'épaisseur du substrat soit égale à 0,8 mm.

5.9.2 Mesure initiale

La capacité doit être mesurée comme cela est spécifié en 5.6.1 et dans la spécification particulière.

5.9.3 Contrôle final

Les condensateurs doivent être examinés visuellement et il ne doit pas y avoir de dommage visible.

Voir 5.5.2.

La variation de capacité avec la carte en position courbée ne doit pas dépasser 5 %.

5.10 Résistance à la chaleur de brasage

5.10.1 Généralités

Voir IEC 60068-2-58, en l'associant aux informations données de 5.10.2 à 5.10.5.

5.10.2 Mesure initiale

La capacité doit être mesurée conformément à 5.6.1.

5.10.3 Conditions d'essai

5.10.3.1 Méthode du bain de brasure (s'applique à 1608M, 2012M et 3216M)

Les codes de taille sont expliqués dans le Tableau A.1.

Voir l'IEC 60068-2-58, Essai Td₂, Méthode 1, avec les détails suivants, sauf indication contraire dans la spécification particulière.

Le spécimen doit être préchauffé à une température comprise entre 110 °C et 140 °C et maintenue pendant 30 s à 60 s.

Alliage de brasure: Sn-Pb ou Sn-Ag-Cu

Température: 260 °C ± 5 °C

Durée d'immersion: 10 s ± 1 s

Profondeur d'immersion: 10 mm

Nombre d'immersions: 1

5.10.3.2 Système de brasage par convection gazeuse ou infrarouge

Voir l'IEC 60068-2-58, Essai Td₂, Méthode 2, avec les détails suivants:

- a) la pâte à braser doit être appliquée sur le substrat d'essai;
- b) l'épaisseur du dépôt de brasure doit être indiquée dans la spécification particulière;
- c) les sorties du spécimen doivent être placées sur la pâte à braser;
- d) alliage de brasure: Sn-Pb;

sauf indication contraire dans la spécification particulière, le spécimen et le substrat d'essai doivent être préchauffés à une température de (150 ± 10) °C et maintenue pendant 60 s à 120 s dans un système de brasage par convection gazeuse ou infrarouge;

la température du système de refusion doit être augmentée rapidement jusqu'à ce que le spécimen ait atteint une température de (235 ± 5) °C et maintenue pendant (10 ± 1) s;